

INCH-POUND

MIL-M-38510/653B  
17 January 2006

SUPERSEDING  
MIL-M-38510/653A  
15 January 1988

MILITARY SPECIFICATION

MICROCIRCUITS, DIGITAL, HIGH-SPEED CMOS,  
FLIP-FLOPS, MONOLITHIC SILICON, POSITIVE LOGIC

Reactivated after 17 Jan. 2006 and may be used for new and existing designs and acquisitions.

This specification is approved for use by all Departments  
and Agencies of the Department of Defense.

The requirements for acquiring the product herein shall consist of this specification sheet and MIL-PRF 38535.

1. SCOPE

1.1 Scope. This specification covers the detail requirements for monolithic silicon, high speed CMOS, logic microcircuits. Two product assurance classes and a choice of case outlines and lead finishes are provided and are reflected in the complete part or identifying number (PIN). For this product, the requirements of MIL-M-38510 have been superseded by MIL-PRF-38535 (see 6.3).

1.2 Part or identifying number (PIN). The PIN is in accordance with MIL-PRF-38535 and as specified herein.

1.2.1 Device types. The device types are as follows:

<u>Device type</u>	<u>Circuit</u>
01	Dual JK flip-flop with clear
02	Dual D positive-edge triggered flip-flop with clear and preset
03	Dual JK negative-edge triggered flip-flop with clear
04	Dual JK positive-edge triggered flip-flop with clear and preset
05	Dual JK negative-edge triggered flip-flop with clear and preset
06	Quad D-type flip-flop with 3-state outputs and clear
07	Hex D-type flip-flop with clear
08	Quad D-type flip-flop with clear
52	Dual D-type positive-edge triggered flip-flop with clear and preset, TTL compatible inputs

1.2.2 Device class. The device class is the product assurance level as defined in MIL-PRF-38535.

1.2.3 Case outlines. The case outlines are as designated in MIL-STD-1835 and as follows:

<u>Outline letter</u>	<u>Descriptive designator</u>	<u>Terminals</u>	<u>Package style</u>
C	GDIP1-T14 or CDIP2-T14	14	Dual-in-line
D	GDFP1-F14 or CDFP2-F14	14	Flat pack
E	GDIP1-T16 or CDIP2-T16	16	Dual-in-line
F	GDFP2-F16 or CDFP3-F16	16	Flat pack
2	CQCC1-N20	20	Square leadless chip carrier

Comments, suggestions, or questions on this document should be addressed to: Commander, Defense Supply Center Columbus, ATTN: DSCC-VAC, P.O. Box 3990, Columbus, OH 43218-3990, or email [CMOS@dsc.dla.mil](mailto:CMOS@dsc.dla.mil). Since contact information can change, you may want to verify the currency of this address information using the ASSIST Online database at <http://assist.daps.dla.mil/>.

1.3 Absolute maximum ratings.

Supply voltage range ( $V_{CC}$ ) .....	-0.5 V dc to +7.0 V dc
DC input voltage range ( $V_{IN}$ ).....	-0.5 V dc to $V_{CC} + 0.5$ V dc
DC output voltage range ( $V_{OUT}$ ).....	-0.5 V dc to $V_{CC} + 0.5$ V dc
Clamp diode current ( $I_{IK}, I_{OK}$ ).....	$\pm 20$ mA
DC output current per pin ( $I_{OUT}$ ).....	$\pm 25$ mA ( $\pm 35$ mA for device type 06)
DC $V_{CC}$ or GND current per pin ( $I_{CC}, I_{GND}$ ) .....	$\pm 50$ mA ( $\pm 70$ mA for device type 06)
Storage temperature range ( $T_{STG}$ ).....	-65°C to +150°C
Maximum power dissipation ( $P_D$ ):	
Device types 01-05, 07, 08, 52.....	300 mW
Device type 06.....	420 mW
Lead temperature (soldering, 10 seconds) .....	300°C
Thermal resistance, junction to case ( $\theta_{JC}$ ).....	See MIL-STD-1835
Junction temperature ( $T_J$ ) .....	175°C

1.4 Recommended operating conditions.Device types 01 to 08:

Maximum input low voltage ( $V_{IL}$ ) .....	0.3 V at $V_{CC} = 2.0$ V 0.9 V at $V_{CC} = 4.5$ V 1.2 V at $V_{CC} = 6.0$ V
Minimum input high voltage ( $V_{IH}$ ).....	1.5 V at $V_{CC} = 2.0$ V 3.15 V at $V_{CC} = 4.5$ V 4.2 V at $V_{CC} = 6.0$ V
Supply voltage range ( $V_{CC}$ ) .....	2.0 V dc to 6.0 V dc
Output voltage range ( $V_{OUT}$ ).....	0.0 V to $V_{CC}$
Operating temperature range ( $T_C$ ).....	-55°C to +125°C
Maximum input rise and fall times ( $t_r, t_f$ ):	
$V_{CC} = 2.0$ V .....	1000 ns
$V_{CC} = 4.5$ V.....	500 ns
$V_{CC} = 6.0$ V.....	400 ns
Width of clock pulse ( $t_p$ clock) $V_{CC} = 4.5$ V:	
Device types 01, 03, 04, 06, 07 .....	27 ns minimum
Device types 02, 05.....	30 ns minimum
Device type 08.....	24 ns minimum
Width of clear pulse ( $t_p$ clear):	
Device types 01, 02, 03, 04, 05, 06 .....	30 ns minimum
Device types 07, 08.....	24 ns minimum
Width of preset pulse ( $t_p$ preset):	
Device types 02, 04, 05.....	30 ns minimum
Data setup time before clock ( $t_{setup}$ ):	
Device types 01-08.....	30 ns minimum
Clear or preset setup time before clock ( $t_{rem}$ ):	
Device types 01, 03, 04, 05, 07, 08 .....	30 ns minimum
Device type 02.....	38 ns minimum
Device type 06.....	27 ns minimum
Hold time ( $t_{hold}$ ):	
Device types 01-08.....	8 ns minimum

1.4 Recommended operating conditions – Continued.Device type 52:

Maximum input low voltage ( $V_{IL}$ ) .....	0.8 V at $V_{CC} = 4.5$ V to 5.5 V
Minimum input high voltage ( $V_{IH}$ ) .....	2.0 V at $V_{CC} = 4.5$ V to 5.5 V
Supply voltage range ( $V_{CC}$ ) .....	4.5 V dc to 5.5 V dc
Output voltage range ( $V_{OUT}$ ) .....	0.0 V dc to $V_{CC}$
Operating ambient temperature range ( $T_A$ ) .....	-55°C to +125°C
Width of clock pulse ( $t_p$ clock) .....	30 ns minimum
Width of clear pulse ( $t_p$ clear) .....	30 ns minimum
Width of preset pulse ( $t_p$ preset) .....	30 ns minimum
Data setup time before clock ( $t_{setup}$ ) .....	30 ns minimum
$t_{rem}$ setup time before clock ( $t_{su}$ clear or $t_{su}$ preset) .....	38 ns minimum
Hold time ( $t_{hold}$ ) .....	3 ns minimum
Input rise and fall times ( $t_r$ , $t_f$ ): $V_{CC} = 4.5$ V .....	500 ns maximum

## 2. APPLICABLE DOCUMENTS

2.1 General. The documents listed in this section are specified in sections 3, 4, or 5 of this specification. This section does not include documents cited in other sections of this specification or recommended for additional information or as examples. While every effort has been made to ensure the completeness of this list, document users are cautioned that they must meet all specified requirements of documents cited in sections 3, 4, or 5 of this specification, whether or not they are listed.

2.2 Government documents.

2.2.1 Specifications and Standards. The following specifications and standards form a part of this specification to the extent specified herein. Unless otherwise specified, the issues of these documents are those cited in the solicitation or contract.

## DEPARTMENT OF DEFENSE SPECIFICATION

MIL-PRF-38535 - Integrated Circuits (Microcircuits) Manufacturing, General Specification for.

## DEPARTMENT OF DEFENSE STANDARDS

MIL-STD-883 - Test Method Standard Microcircuits.

MIL-STD-1835 - Interface Standard Electronic Component Case Outlines.

(Copies of these documents are available online at <http://assist.daps.dla.mil/quicksearch> or <http://assist.daps.dla.mil> or from the Standardization Document Order Desk, 700 Robbins Avenue, Building 4D, Philadelphia, PA 19111-5094.)

2.3 Order of precedence. In the event of a conflict between the text of this document and the references cited herein, the text of this document takes precedence. Nothing in this document, however, supersedes applicable laws and regulations unless a specific exemption has been obtained.

### 3. REQUIREMENTS

3.1 Qualification. Microcircuits furnished under this specification shall be products that are manufactured by a manufacturer authorized by the qualifying activity for listing on the applicable qualified manufacturers list before contract award (see 4.3 and 6.4).

3.2 Item requirements. The individual item requirements shall be in accordance with MIL-PRF-38535 and as specified herein or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

3.3 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-PRF-38535 and herein.

3.3.1 Logic diagrams and terminal connections. The logic diagrams and terminal connections shall be as specified on figure 1.

3.3.2 Truth tables. The truth tables shall be as specified on figure 2.

3.3.3 Switching test circuit and waveforms. The switching test circuit and waveforms shall be as specified on figure 3.

3.3.4 Schematic circuits. The schematic circuits shall be maintained by the manufacturer and made available to the qualifying activity or preparing activity upon request.

3.3.5 Case outlines. The case outlines shall be as specified in 1.2.3 and MIL-STD-1835.

3.4 Lead material and finish. The lead material and finish shall be in accordance with MIL-PRF-38535 (see 6.6).

3.5 Electrical performance characteristics. Unless otherwise specified, the electrical performance characteristics are as specified in table I, and apply over the full recommended ambient operating temperature range.

3.6 Electrical test requirements. The electrical test requirements for each device class shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table III.

3.7 Marking. Marking shall be in accordance with MIL-PRF-38535.

3.8 Microcircuit group assignment. The devices covered by this specification shall be in microcircuit group number 38 (see MIL-PRF-38535, appendix A).

### 4. VERIFICATION

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with MIL-PRF-38535 or as modified in the device manufacturer's Quality Management (QM) plan. The modification in the QM plan shall not affect the form, fit, or function as described herein.

4.2 Screening. Screening shall be in accordance with MIL-PRF-38535 and shall be conducted on all devices prior to qualification and conformance inspection. The following additional criteria shall apply:

- a. The burn-in test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1015 of MIL-STD-883.
- b. Delete the sequence specified as interim (pre-burn-in) electrical parameters through interim (post-burn-in) electrical parameters of table IA of MIL-PRF-38535 and substitute lines 1 through 7 of table II herein.
- c. Burn-in (method 1015 of MIL-STD-883).

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- (1) Unless otherwise specified in the manufacturers QM plan for static tests (test condition A), ambient temperature ( $T_A$ ) shall be +125°C minimum. Test duration for each static test shall be 24 hours minimum for class S devices and in accordance with table I of method 1015 for class B devices.
  - i. For static burn-in I, all inputs shall be connected to GND. Outputs shall be open or connected to  $V_{CC}/2$ . Resistors are optional on outputs if open. Resistors are required on inputs and on outputs connected to  $V_{CC}/2$ .  $R = 470\Omega$  to  $47\text{ k}\Omega$ .
  - ii. For static burn-in II, all inputs shall be connected through a resistor to  $V_{CC}$ . Outputs shall be open or connected to  $V_{CC}/2$ . Resistors are optional on outputs if open. Resistors are required on inputs and on outputs connected to  $V_{CC}/2$ .  $R = 470\Omega$  to  $47\text{ k}\Omega$ .
- (2) Unless otherwise specified in the manufacturers QM plan for dynamic test (test condition D), ambient temperature shall be +125°C minimum. Test duration shall be in accordance with table I of method 1015.
  - i. For dynamic burn-in, the generator shall be connected to the clock and J – K or D (depending on device type) inputs and reset shall be connected to clock/2. Outputs shall be connected to  $V_{CC}/2 + 0.5\text{ V}$  through the resistors.  $R = 680\Omega$  to  $1\text{ k}\Omega$  for outputs,  $470\Omega$  to  $47\text{ k}\Omega$  for inputs.
  - ii. CP = 25 kHz to 1 MHz square wave; duty cycle = 50%  $\pm$ 15%;  $V_{IH} = 4.5\text{ V}$  to  $V_{CC}$ ;  $V_{IL} = 0.0\text{ V} \pm 0.5\text{ V}$ ; transition time  $\leq 0.5\text{ }\mu\text{s}$ .
  - iii.  $V_{CC} = 6.0\text{ V} + 0.0\text{ V}, -0.5\text{ V}$ .  $V_{CC} = 5.5\text{ V} + 0.0\text{ V}, -0.5\text{ V}$  for device type 52.
- d. Interim and final electrical test parameters shall be as specified in table II.
- e. For class S devices, post dynamic burn-in, or class B devices, post static burn-in, electrical parameter measurements may, at the manufacturer's option, be performed separately or included in the final electrical parameter requirements.

4.2.1 Percent defective allowable (PDA).

- a. The PDA for class S devices shall be 5 percent for static burn-in and 5 percent for dynamic burn-in, based on the exact number of devices submitted to each separate burn-in.
- b. Static burn-in I and II failure shall be cumulative for determining the PDA.
- c. The PDA for class B devices shall be in accordance with MIL-PRF-38535 for static burn-in. Dynamic burn-in is not required.
- d. Those devices whose measured characteristics, after burn-in, exceed the specified delta ( $\Delta$ ) limits or electrical parameter limits specified in table III, subgroup 1, are defective and shall be removed from the lot. The verified failures divided by the total number of devices in the lot initially submitted to burn-in shall be used to determine the percent defective for the lot and the lot shall be accepted or rejected based on the specified PDA.

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ $T_C = +125^\circ\text{C}$ unless otherwise specified	Device type	$V_{CC}$	Limits		Unit	
					Min	Max		
High-level output voltage	$V_{OH1}$ <u>2/</u>	$V_{IH} = 1.5\text{ V}; V_{IL} = 0.3\text{ V}$ $I_{OH} = -20\ \mu\text{A}$	All	2.0 V	1.95		V	
	$V_{OH2}$ <u>2/</u>	$V_{IH} = 3.15\text{ V}; V_{IL} = 0.9\text{ V}$ $I_{OH} = -20\ \mu\text{A}$	All	4.5 V	4.45		V	
	$V_{OH3}$	$V_{IH} = 4.2\text{ V}; V_{IL} = 1.2\text{ V}$ $I_{OH} = -20\ \mu\text{A}$	All	6.0 V	5.95		V	
	$V_{OH4}$ <u>2/</u>	$V_{IH} = 3.15\text{ V}; V_{IL} = 0.9\text{ V}$ $I_{OH} = -4.0\text{ mA}$	All	4.5 V	3.7		V	
	$V_{OH5}$	$V_{IH} = 4.2\text{ V}$ $V_{IL} = 1.2\text{ V}$	$I_{OH} = -5.2\text{ mA}$	01,02 03,04 05,07,08	6.0 V	5.2		V
			$I_{OH} = -7.8\text{ mA}$	06				
	$V_{OH6}$	$V_{IH} = 2.0\text{ V}; V_{IL} = 0.8\text{ V}$ $I_{OH} = -20\ \mu\text{A}$	52	4.5 V	4.40		V	
$V_{OH7}$	$V_{IH} = 2.0\text{ V}; V_{IL} = 0.8\text{ V}$ $I_{OH} = -4.0\text{ mA}$	52	5.5 V	3.70		V		
Low-level output Voltage	$V_{OL1}$ <u>2/</u>	$V_{IL} = 0.3\text{ V}; V_{IH} = 1.5\text{ V}$ $I_{OL} = 20.0\ \mu\text{A}$	All	2.0 V		0.05	V	
	$V_{OL2}$ <u>2/</u>	$V_{IL} = 0.9\text{ V}; V_{IH} = 3.15\text{ V}$ $I_{OL} = 20.0\ \mu\text{A}$	All	4.5 V		0.05	V	
	$V_{OL3}$	$V_{IL} = 1.2\text{ V}; V_{IH} = 4.2\text{ V}$ $I_{OL} = 20.0\ \mu\text{A}$	All	6.0 V		0.05	V	
	$V_{OL4}$ <u>2/</u>	$V_{IL} = 0.9\text{ V}; V_{IH} = 3.15\text{ V}$ $I_{OL} = 4.0\text{ mA}$	All	4.5 V		0.4	V	
	$V_{OL5}$	$V_{IL} = 1.2\text{ V}$ $V_{IH} = 4.2\text{ V}$	$I_{OL} = 5.2\text{ mA}$	01,02 03,04 05,07,08	6.0 V		0.4	V
			$I_{OL} = 7.8\text{ mA}$	06				
	$V_{OL6}$	$V_{IL} = 0.8\text{ V}; V_{IH} = 2.0\text{ V}$ $I_{OL} = 20\ \mu\text{A}$	52	4.5 V		0.05	V	
$V_{OL7}$	$V_{IL} = 0.8\text{ V}; V_{IH} = 2.0\text{ V}$ $I_{OL} = 4.0\text{ mA}$	52	5.5 V		0.4	V		
Positive input clamp voltage	$V_{IC+}$	$I_{IN} = 1\text{ mA}$ $T_C = +25^\circ\text{C}$	All	GND		1.5	V	
Negative input clamp voltage	$V_{IC-}$	$I_{IN} = -1\text{ mA}$ $T_C = +25^\circ\text{C}$	All	OPEN		-1.5	V	
Input current low	$I_{IL}$	$V_{IN} = \text{GND}$	01-08	6.0 V		-0.1	$\mu\text{A}$	
			52	5.5 V				
Input current high	$I_{IH}$	$V_{IN} = V_{CC}$	01-08	6.0 V		0.1	$\mu\text{A}$	
			52	5.5 V				

See footnotes at end of table.

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions 1/ $T_C = +125^\circ\text{C}$ unless otherwise specified	Device type	$V_{CC}$	Limits		Unit
					Min	Max	
Short circuit output current	$I_{OS1}$ 2/	$V_O = \text{GND}$ $V_I = \text{GND}$	01-05 07,08	2.0 V	-2	-50	mA
			06			-60	
	$I_{OS2}$ 2/		01-05 07,08,52	4.5 V	-15	-150	
			06			-165	
	$I_{OS3}$ 2/		01-05 07,08	6.0 V	-25	-180	
			06			-210	
	$I_{OS4}$		01-05 07,08,52	4.0 V	-10	-120	
06		-135					
$I_{OS5}$ 2/	52	5.5 V	-25	-180			
Additional supply current quiescent per input pin (one unit load)	$I_{CCA}$ 3/	For all inputs, $V_{IL} = 0.4 \text{ V}$ and $V_{IH} = 2.4 \text{ V}$ Test pin at $V_{IN} = 2.4 \text{ V}$ When not being tested, control pins at $V_{IH} = V_{CC}$ and $V_{IL} = \text{GND}$ $I_O = 0 \mu\text{A}$	52	5.5 V		3.0	mA
Quiescent supply current	$I_{CC}$	$V_{IN} = 6.0 \text{ V}$	01-05 52	6.0 V		15	$\mu\text{A}$
			06-08			20	
	$I_{CCZ}$	$V_{IN} = 6.0 \text{ V}$	06	6.0 V		10	$\mu\text{A}$
Three-state output leakage current low	$I_{OZL}$	$V_{OUT} = \text{GND}$ $OC = V_{IH}$ 4/	06	6.0 V		-2.0	$\mu\text{A}$
Three-state output leakage current high	$I_{OZH}$	$V_{OUT} = V_{CC}$ $OC = V_{IH}$ 4/	06	6.0 V		+2.0	$\mu\text{A}$
Control input capacitance	$C_C$	$T_C = +25^\circ\text{C}$	All			15	pF
Input capacitance	$C_I$		All			10	
Three-state output capacitance	$C_O$		06	6.0 V		20	
Power dissipation capacitance	$C_{PD}$ 2/ 5/		01			30	pF
			02-05			35	
			06			29	
			07			38	
			08			65	
			52			30	
Maximum clock frequency	$f_{MAX}$ 6/ 7/	$C_L = 50 \text{ pF} \pm 10\%$	01,03 04,06 07	4.5 V	23		MHz
			02,05 52			21	
			08			26	

See footnotes at end of table.

TABLE I. Electrical performance characteristics – Continued.

Test	Symbol	Conditions <sup>1/</sup> T <sub>C</sub> = +125°C unless otherwise specified	Device type	V <sub>CC</sub>	Limits		Unit	
					Min	Max		
Propagation delay time, low to high level, CLK to Q	t <sub>PLH1</sub>	C <sub>L</sub> = 50 pF ± 10% <sup>7/</sup> <sup>8/</sup>	02,04	4.5 V	5	41	ns	
			05,52					
			01-03		5	40		
			06		6	47		
			07		5	42		
08	4		41					
Propagation delay time, high to low level, CLK to Q	t <sub>PHL1</sub>		02,04			5		41
			05,52					
			01-03		5	40		
			06		6	47		
			07		5	42		
Propagation delay time, low to high level, CLK or PRE to Q or $\bar{Q}$	t <sub>PLH2</sub>		08			4		41
			01,05		6	43		
			02		5	54		
			03		6	51		
		04	6	54				
		08	4	43				
Propagation delay time, high to low level, CLK or PRE to Q or $\bar{Q}$	t <sub>PHL2</sub>	52		5	47			
		01,05	6	43				
		02	5	54				
		03	6	51				
		04	6	54				
		06	5	41				
Enable time to high or low level	t <sub>PZH</sub> OR t <sub>PZL</sub>	07		5	42			
		08	4	43				
Disable time to high or low level	t <sub>PHZ</sub> OR t <sub>PLZ</sub>	52		5	47			
		06	5	35				
Transition time, low to high level or high to low level	t <sub>TLH</sub> OR t <sub>THL</sub>	06		5	35			
		01-05	3	20				
		07,08,52						
		06		2	16			

<sup>1/</sup> Complete terminal conditions shall be as specified in table III.

<sup>2/</sup> Guaranteed but not tested.

<sup>3/</sup> Total supply current = I<sub>CC</sub> + I<sub>CCA</sub>.

<sup>4/</sup> I<sub>OZL</sub> sets internal D flip-flops to high state.

I<sub>OZH</sub> sets internal D flip-flops to low state.

<sup>5/</sup> Power dissipation capacitance (C<sub>PD</sub>) per flip-flop.

<sup>6/</sup> See the formula for determining maximum frequencies shown in table IA.

<sup>7/</sup> Tested at V<sub>CC</sub> = 4.5 V at +125°C for sample testing and V<sub>CC</sub> = 4.5 V and +25°C for screening. Guaranteed at other V<sub>CC</sub> voltages and temperatures. See tables IA and IB (as appropriate) and the exception in 4.4.1d.

<sup>8/</sup> For propagation and transition delay times at V<sub>CC</sub> = 2.0 V, increase limit by a factor of 5. For propagation and transition delay times at V<sub>CC</sub> = 6.0 V, decrease limit by a factor of 0.85.

TABLE IA. Calculated  $f_{MAX}$  at  $-55^{\circ}\text{C} / +25^{\circ}\text{C}$  case temperature.

$V_{CC}$	$T_C$	
	$+125^{\circ}\text{C}$	$-55^{\circ}\text{C} / +25^{\circ}\text{C}$
2.0 V	0.2X	0.2Y
4.5 V	X = 1	1.33X = Y
6.0 V	1.18X	1.18Y

NOTE: Normalized numbers ( $+125^{\circ}\text{C} = 1$ ).  
The 2.0 V and 6.0 V numbers are derived from their 4.5 V integer value (rounding off according 5/4).

TABLE IB. Calculated dynamic values at  $-55^{\circ}\text{C} / +25^{\circ}\text{C}$ , case temperature.

$V_{CC}$	$T_C$	
	$+125^{\circ}\text{C}$	$-55^{\circ}\text{C}$ or $+25^{\circ}\text{C}$
2.0 V	5	5 x 0.75
4.5 V	1	0.75
6.0 V	0.85	0.85 x 0.75

NOTE: Normalized numbers ( $+125^{\circ}\text{C} = 1$ ).  
The 2.0 V and 6.0 V numbers are derived from their 4.5 V integer value (rounding off according 5/4).

## MIL-M-38510/653B

Line no.	MIL-PRF-38535 test requirements	Class S device <sup>1/</sup>			Class B device <sup>1/</sup>		
		Ref. par.	Table III subgroups <sup>2/</sup>	Table IV delta limits <sup>3/</sup>	Ref. par.	Table III subgroups <sup>2/</sup>	Table IV delta <sup>3/</sup>
1	Interim electrical parameters		1			1	
2	Static burn-in I (method 1015)	4.2c 4.5.2	Req'd			Not req'd	
3	Same as line 1		1*	Δ			
4	Static burn-in II (method 1015)	4.2c 4.5.2	Req'd		4.2c 4.5.2	<sup>4/</sup> req'd	
5	Same as line 1	4.2e	1*	Δ	4.2e	1*	Δ
6	Dynamic burn-in (method 1015)	4.2c 4.5.2	Req'd			Not req'd	
7	Same as line 1	4.2e	1	Δ			
8	Final electrical parameters		* 1, 2, 3, 7, 8, 9			1*, 2, 7, 9 <sup>4/</sup>	
9	Group A test requirements	4.4.1	1, 2, 3, 4, 7, 8, 9, 10, 11		4.4.1	1, 2, 3, 4, 7, 8, 9, 10, 11	
10	Group B test when using method 5005 QCI option	4.4.2	1, 2, 3, 7, 8, 9, 10, 11	Δ			
11	Group C endpoint electrical parameters	4.4.2	1, 2, 3, 7, 8, 9, 10, 11	Δ	4.4.3	1, 2	Δ
12	Group D endpoint electrical parameters	4.4.4	1, 2, 3		4.4.4	1, 2	

<sup>1/</sup> Blank spaces indicate tests are not applicable.

<sup>2/</sup> \* indicates PDA applies to subgroup 1 (see 4.2.1).

<sup>3/</sup> Δ indicates delta limits shall be required only on table III subgroup 1, where specified, and the delta values shall be computed with reference to the previous interim electrical parameters.

<sup>4/</sup> The device manufacturer may, at his option, either complete subgroup 1 electrical parameter measurements, including delta measurements, within 96 hours after burn-in completion (removal of bias); or may complete subgroup 1 electrical measurements without delta measurements within 24 hours after burn-in completion (removal of bias).

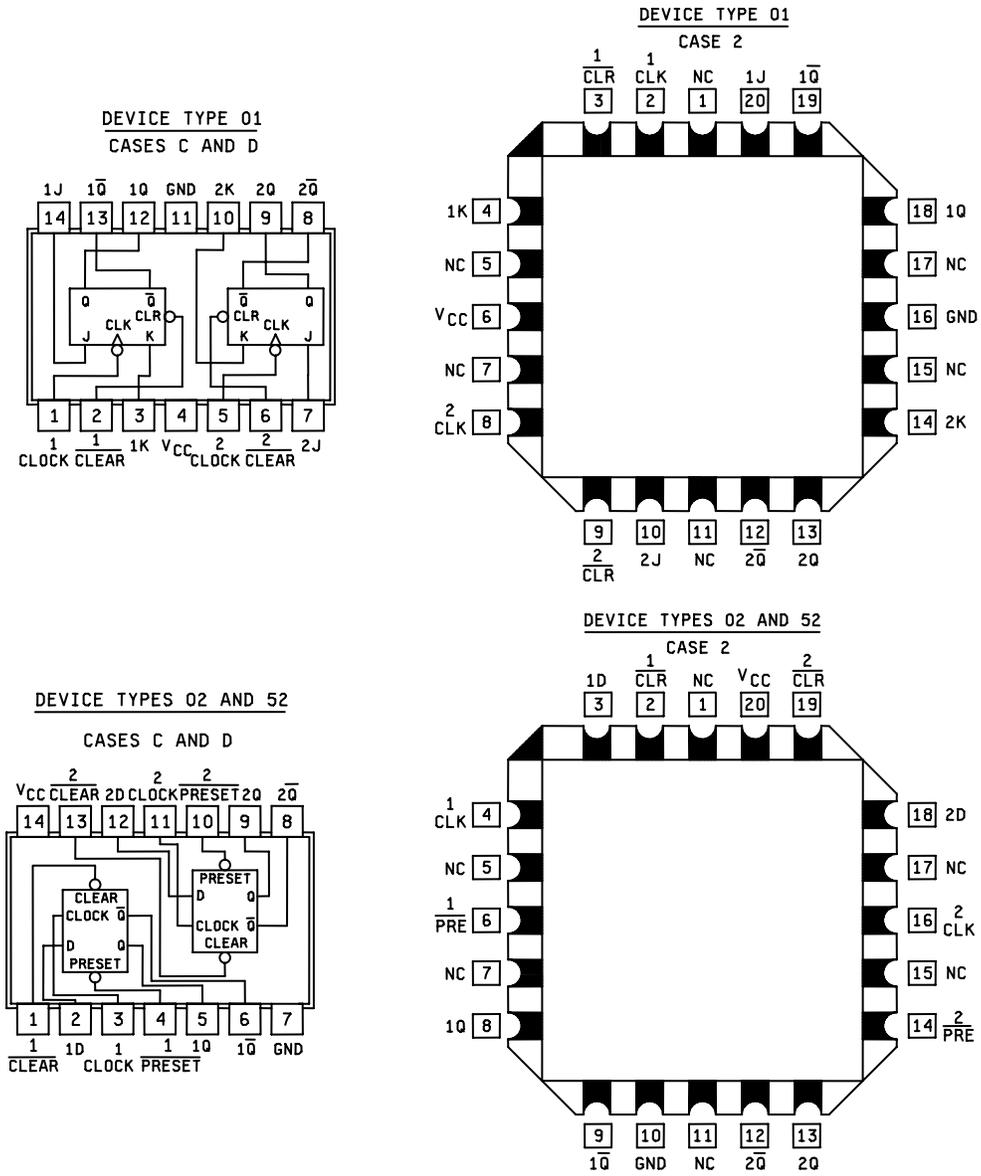


FIGURE 1. Logic diagrams and terminal connections (top views).

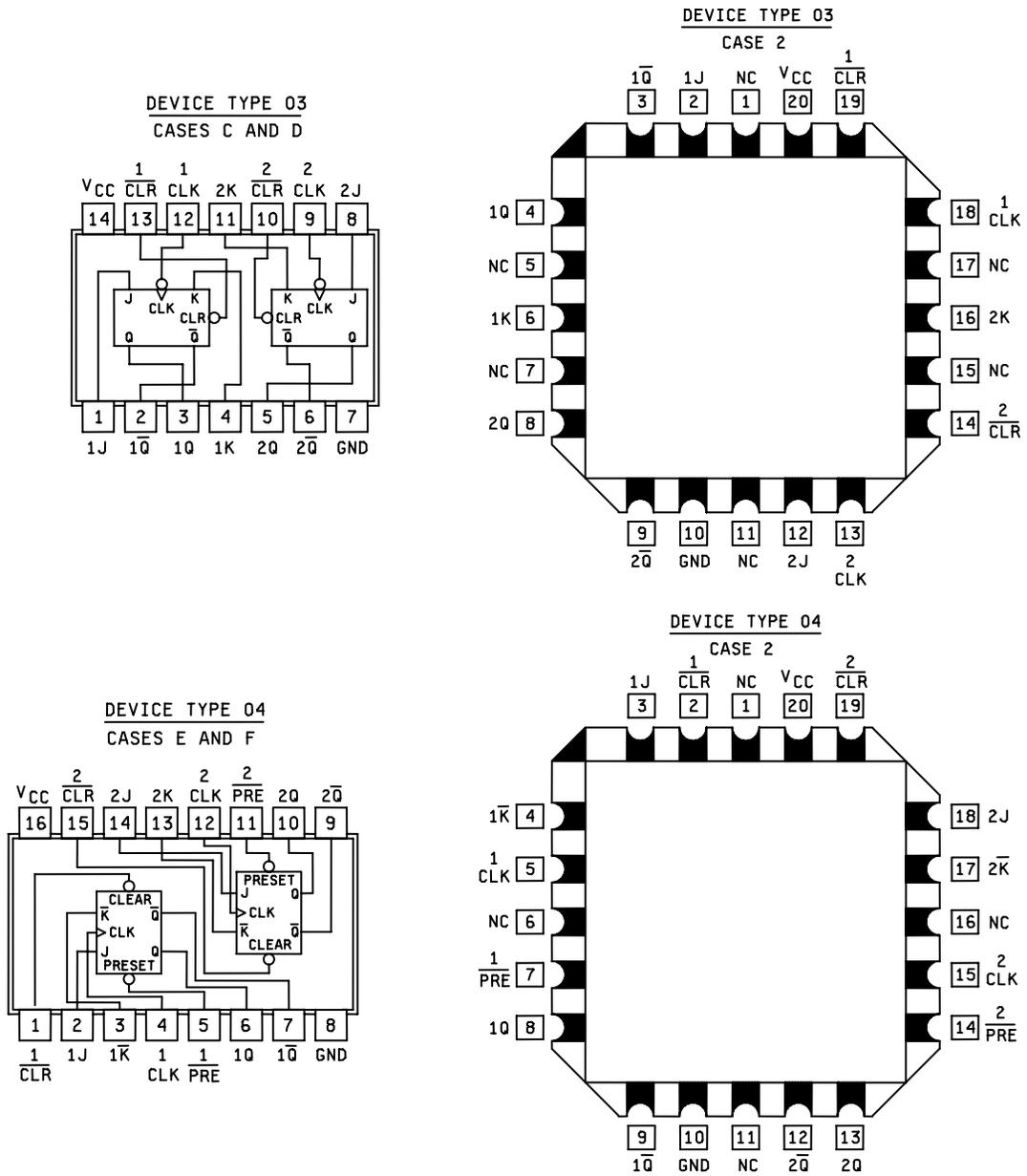


FIGURE 1. Logic diagrams and terminal connections (top views) – Continued.

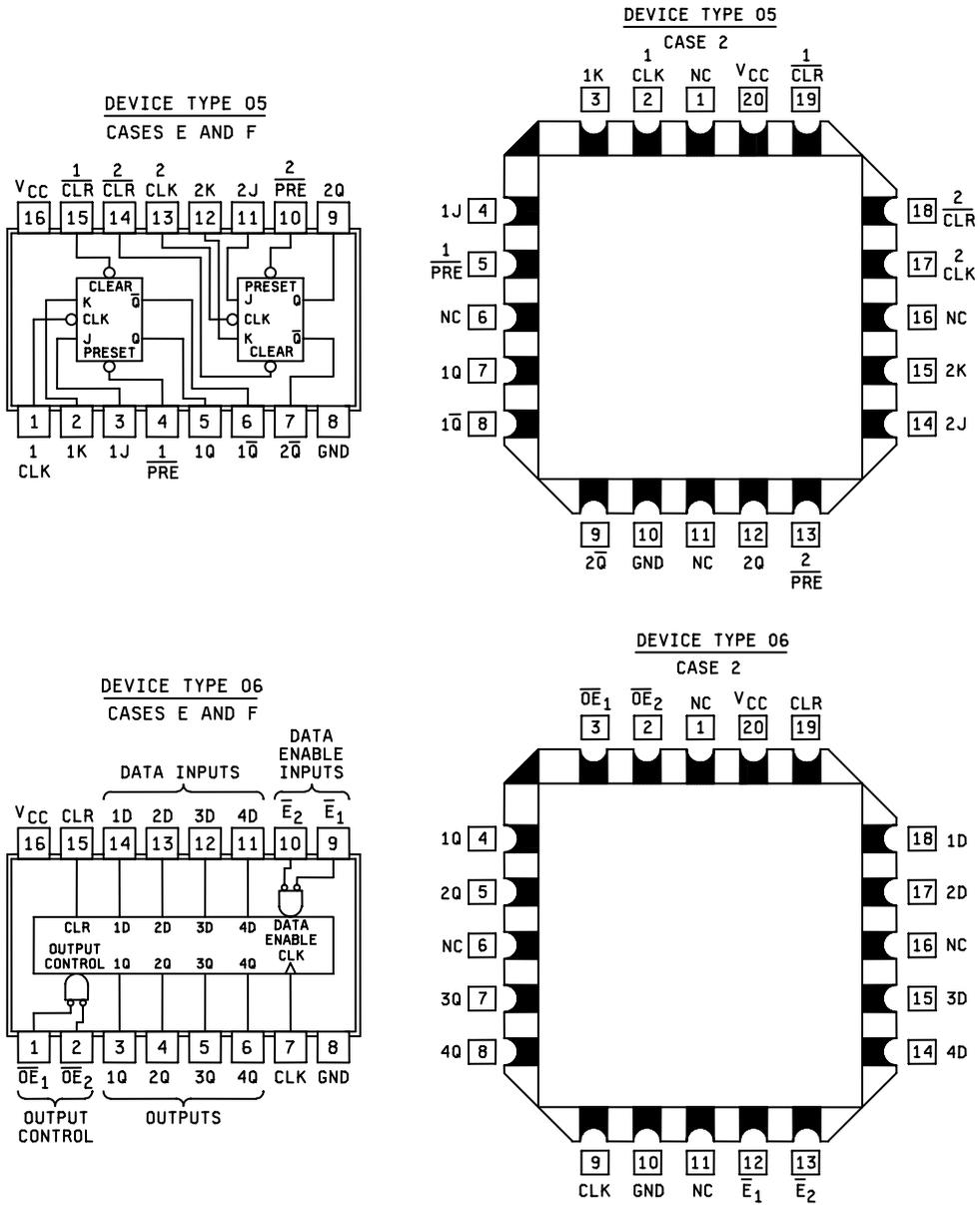


FIGURE 1. Logic diagrams and terminal connections (top views) – Continued.

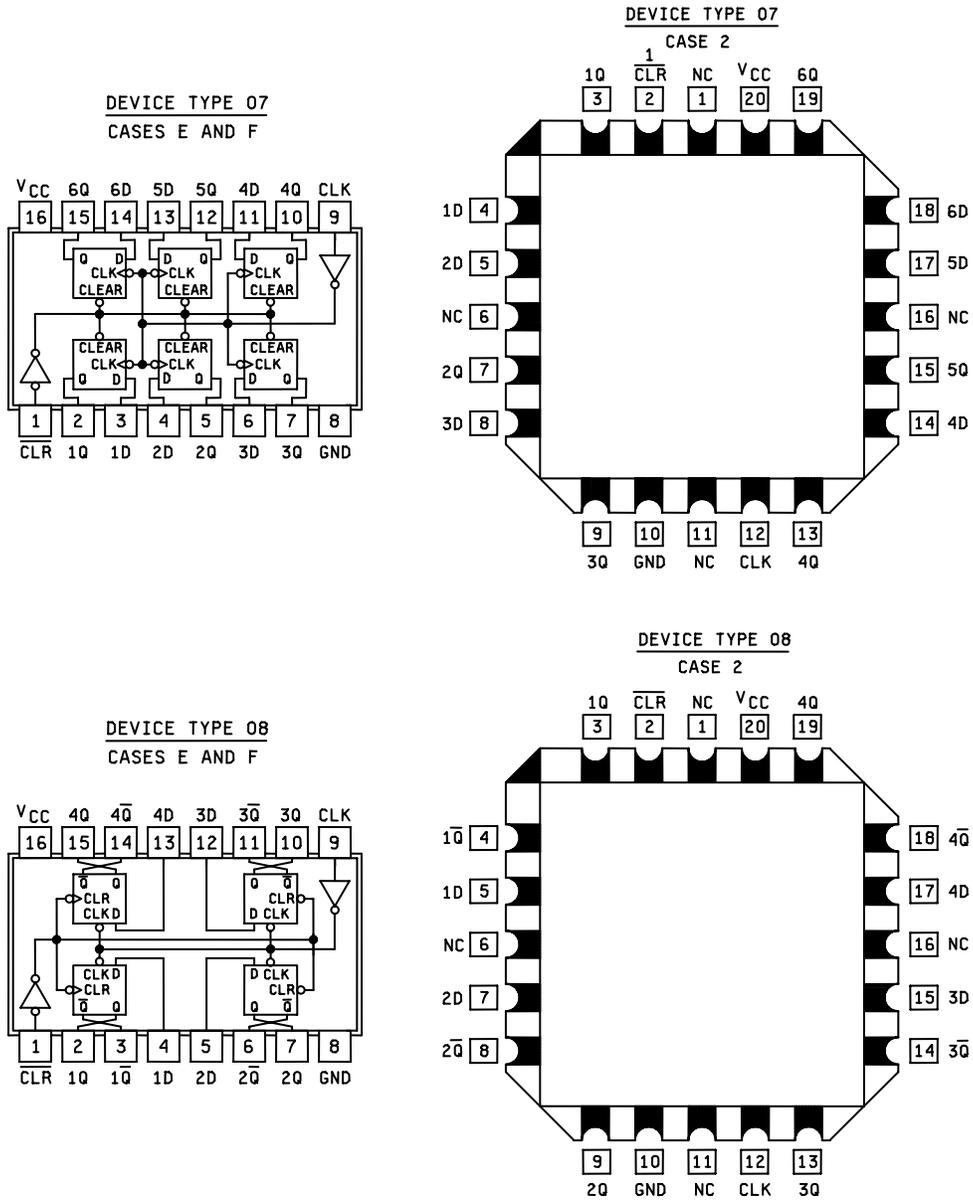


FIGURE 1. Logic diagrams and terminal connections (top views) – Continued.

MIL-M-38510/653B

Device type 01

Inputs				Outputs	
$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{\text{Q}}$
L	X	X	X	L	H
H	↓	L	L	Q0	$\overline{\text{Q0}}$
H	↓	H	L	H	L
H	↓	L	H	L	H
H	↓	H	H	Toggle	
H	H	X	X	Q0	$\overline{\text{Q0}}$

Device types 02 and 52

Inputs				Outputs	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	D	Q	$\overline{\text{Q}}$
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H*	H*
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	X	X	Q0	$\overline{\text{Q0}}$

Device type 03

Inputs				Outputs	
$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{\text{Q}}$
L	X	X	X	L	H
H	↓	L	L	Q0	$\overline{\text{Q0}}$
H	↓	H	L	H	L
H	↓	L	H	L	H
H	↓	H	H	Toggle	
H	H	X	X	Q0	$\overline{\text{Q0}}$

Device type 04

Inputs					Outputs	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	J	$\overline{\text{K}}$	Q	$\overline{\text{Q}}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H*	H*
H	H	↑	L	L	L	H
H	H	↑	H	L	Toggle	
H	H	↑	L	H	Q0	$\overline{\text{Q0}}$
H	H	↑	H	H	H	L
H	H	L	X	X	Q0	$\overline{\text{Q0}}$

- \* = This configuration is nonstable
- X = Pins have no effect on output
- H = High level voltage
- L = Low level voltage
- ↑ = Low-to-high transition of the clock
- ↓ = High-to-low transition of the clock
- Q0 ( $\overline{\text{Q0}}$ ) = The level of Q ( $\overline{\text{Q}}$ ) before the indicated steady-state input conditions were established

FIGURE 2. Truth tables.

## Device type 05

Inputs					Outputs	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	J	K	Q	$\overline{\text{Q}}$
L	H	X	X	X	H	L
H	L	X	X	X	L	H
L	L	X	X	X	H*	H*
H	H	↓	L	L	Q0	$\overline{\text{Q0}}$
H	H	↓	H	L	H	L
H	H	↓	L	H	L	H
H	H	↓	H	H	Toggle	
H	H	H	X	X	Q0	$\overline{\text{Q0}}$

## Device type 06

Inputs		Data enable		Data	Output
CLR	CLK	$\overline{\text{E1}}$	$\overline{\text{E2}}$	D	Q
H	X	X	X	X	L
L	L	X	X	X	Q0
L	↑	H	X	X	Q0
L	↑	X	H	X	Q0
L	↑	L	L	L	L
L	↑	L	L	H	H

For device type 06: When either  $\overline{\text{OE1}}$  or  $\overline{\text{OE2}}$  (or both) is (are) high, the output is disabled to the high-Z state; however, sequential operation of the flip-flops is not affected.

## Device type 07

Inputs			Output
$\overline{\text{CLR}}$	CLK	D	Q
L	X	X	L
H	↑	H	H
H	↑	L	L
H	L	X	Q0

## Device type 08

Inputs			Outputs	
$\overline{\text{CLR}}$	CLK	D	Q	$\overline{\text{Q}}$
L	X	X	L	H
H	↑	H	H	L
H	↑	L	L	H
H	L	X	Q0	$\overline{\text{Q0}}$

\* = This configuration is nonstable

X = Pins have no effect on output

H = High level voltage

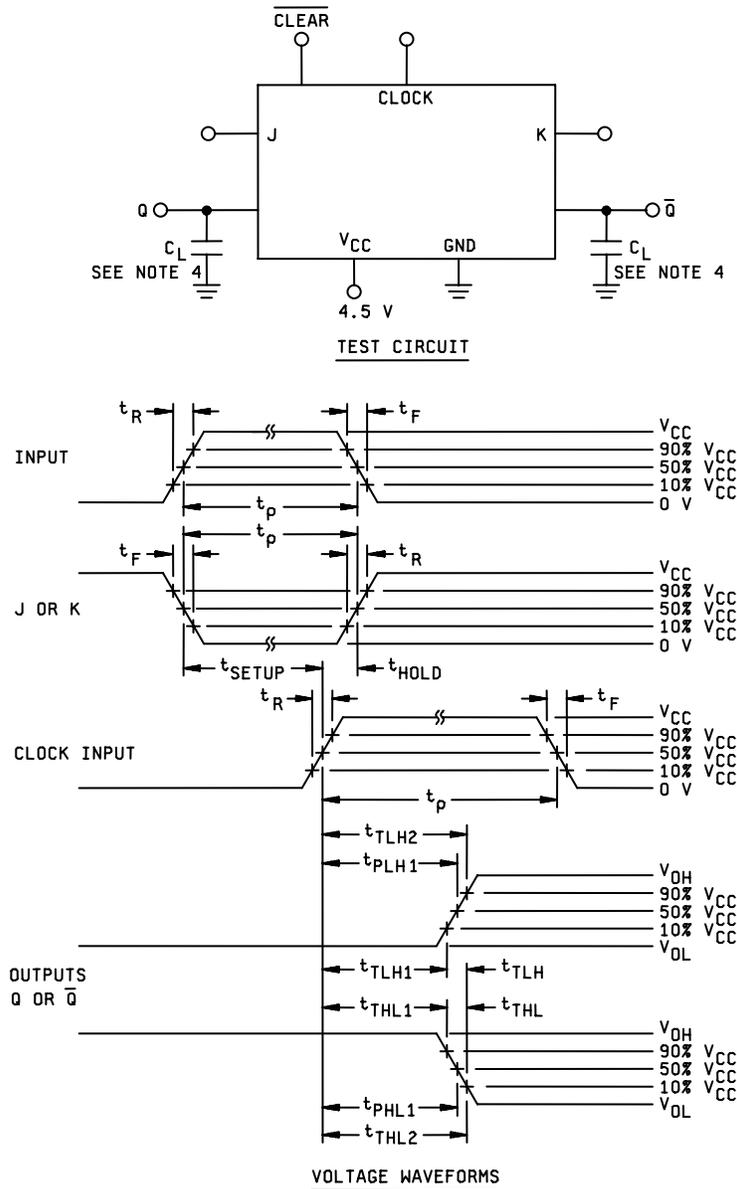
L = Low level voltage

↑ = Low-to-high transition of the clock

↓ = High-to-low transition of the clock

Q0 ( $\overline{\text{Q0}}$ ) = The level of Q ( $\overline{\text{Q}}$ ) before the indicated steady-state input conditions were established

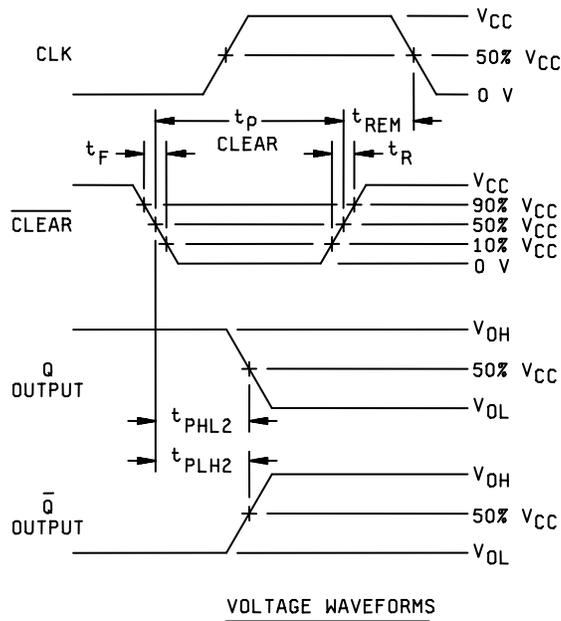
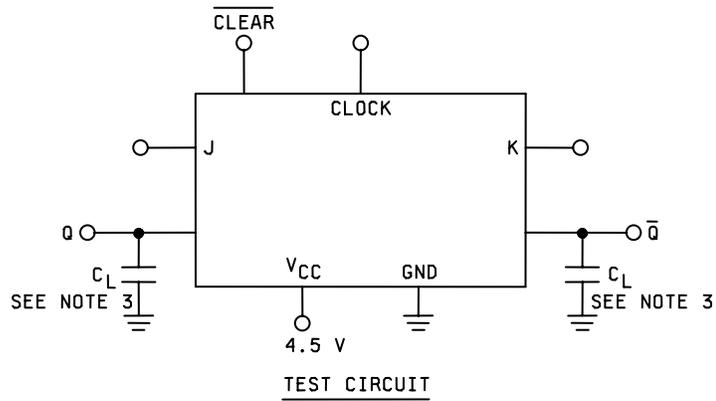
FIGURE 2. Truth tables – Continued.



NOTES:

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 27$  ns.
2. J or K input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_{setup} \leq 30$ ns;  $t_{hold} \leq 8$  ns;  $t_p$  (data)  $\leq 38$  ns.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 22$  ns;  $PRR \geq 23$  MHz.
4.  $C_L = 50$  pF  $\pm 10$  % (includes test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{TLH} = t_{TLH2} - t_{TLH1}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .

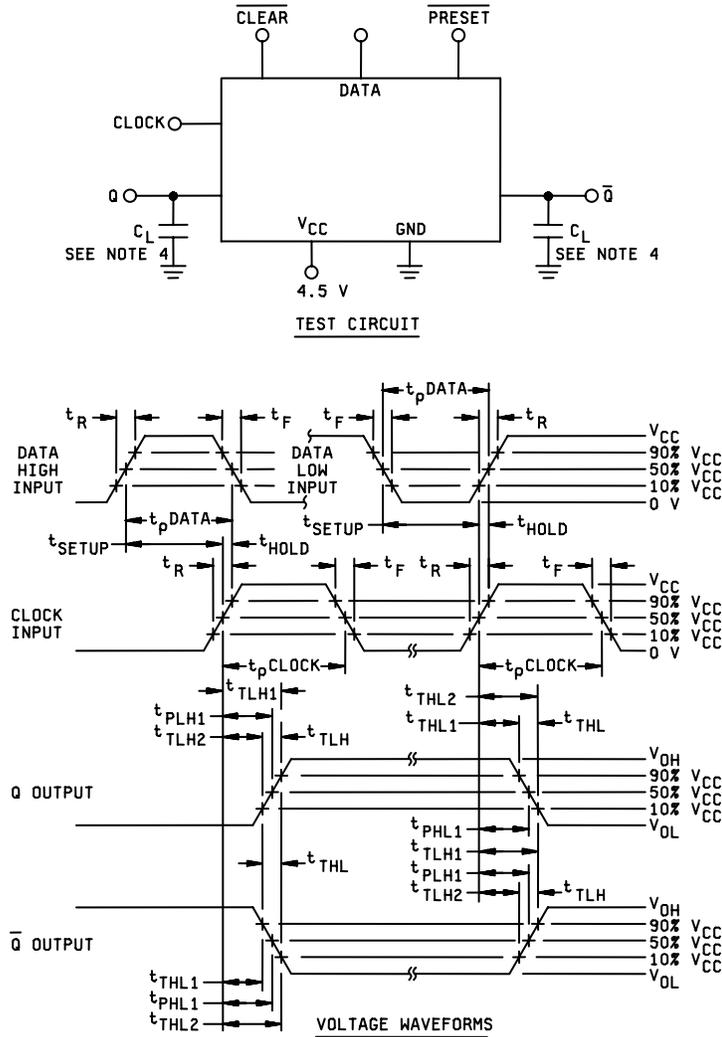
FIGURE 3. Synchronous switching test circuit and waveforms (device type 01).



NOTES:

1. CLEAR pulses dominate regardless of the state of the other inputs.
2. CLEAR input pulse characteristics are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clear)  $\leq 30$  ns;  $t_{REM} \leq 30$  ns.
3.  $C_L = 50$  pF  $\pm 10$  % (includes test jig and probe capacitance).
4. Clock pulse prior to test with inputs biased to place output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

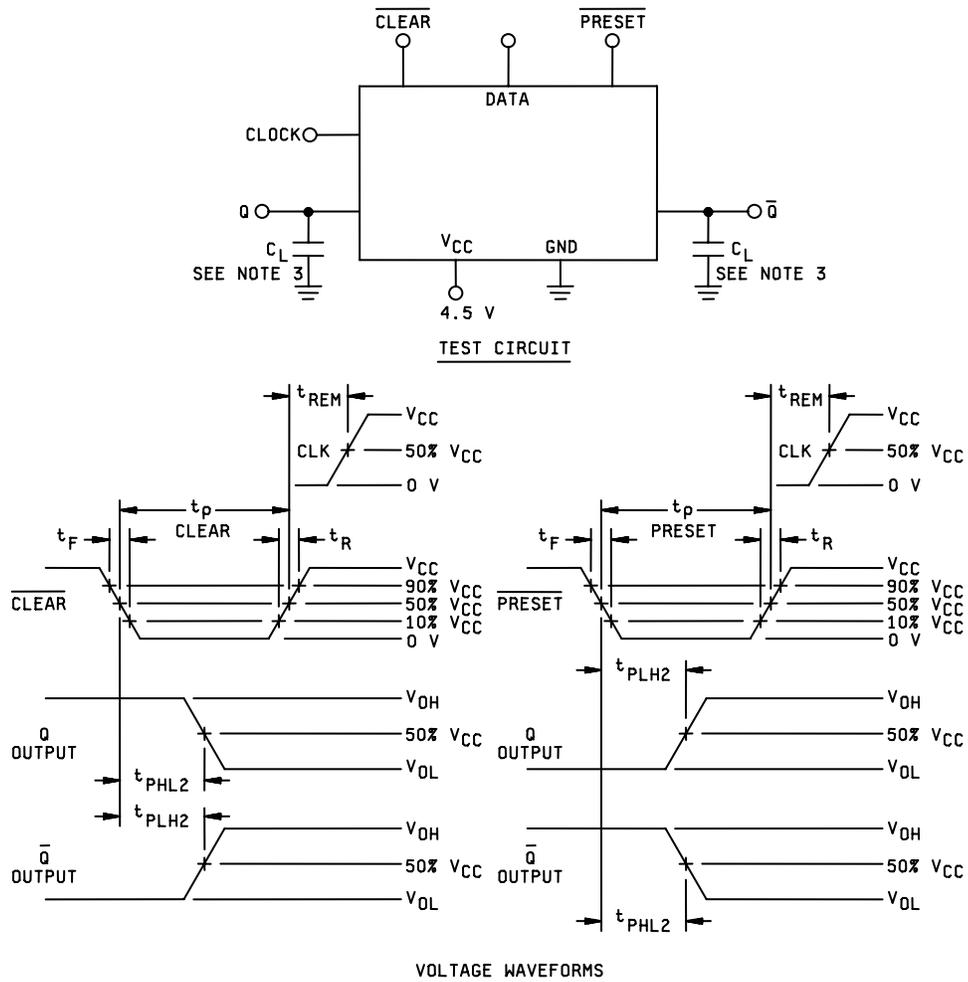
FIGURE 3. CLEAR switching test circuit and waveforms (device type 01) – Continued.



NOTES:

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 30$  ns.
2. Data input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (data)  $\leq 38$  ns;  
 (for device type 52),  $t_p$  (data)  $\leq 33$  ns;  $t_{setup} \leq 30$  ns;  $t_{hold} \leq 8$  ns.  
 (for device type 52),  $t_{hold} \leq 3$  ns;  $PRR \geq 1$  MHz.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 24$  ns;  $PRR \geq 21$  MHz.
4.  $C_L = 50$  pF  $\pm 10\%$  (including test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal. The input signal(s) for HCT device type 52 will be 0 V to 3 V; however, the 50 %  $V_{CC}$  measuring point is 1.3 V for input and output.
6.  $t_{TLH} = t_{TLH1} - t_{TLH2}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .

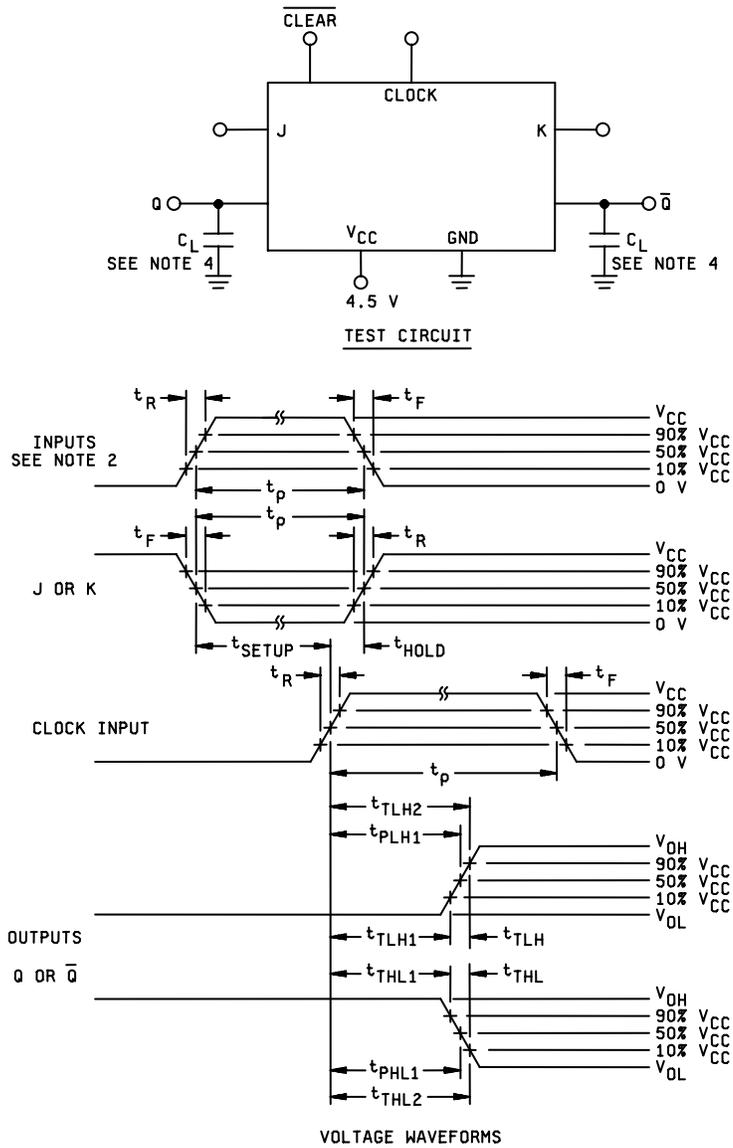
FIGURE 3. Synchronous switching test circuit and waveforms (device types 02 and 52) - Continued.



NOTES:

1. CLEAR and PRESET pulses are active low and dominate regardless of the state of the clock and data inputs.
2. CLEAR or PRESET input pulse characteristics are as follows:  
 $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p(\text{CLEAR}) = t_p(\text{PRESET}) \leq 30 \text{ ns}$ ;  $t_{\text{REM}} \leq 38 \text{ ns}$ .
3.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
4. While testing the CLEAR input at a logic "0" level, PRESET will have a logic "1" level applied. While testing the PRESET input at a logic level "0", CLEAR will have a logic "1" applied.
5. Voltage measurements are to be made with respect to the network ground terminal. The input signal(s) for HCT device type 52 will be 0 V to 3 V; however, the 50 % measurements point is 1.3 V for inputs and outputs.

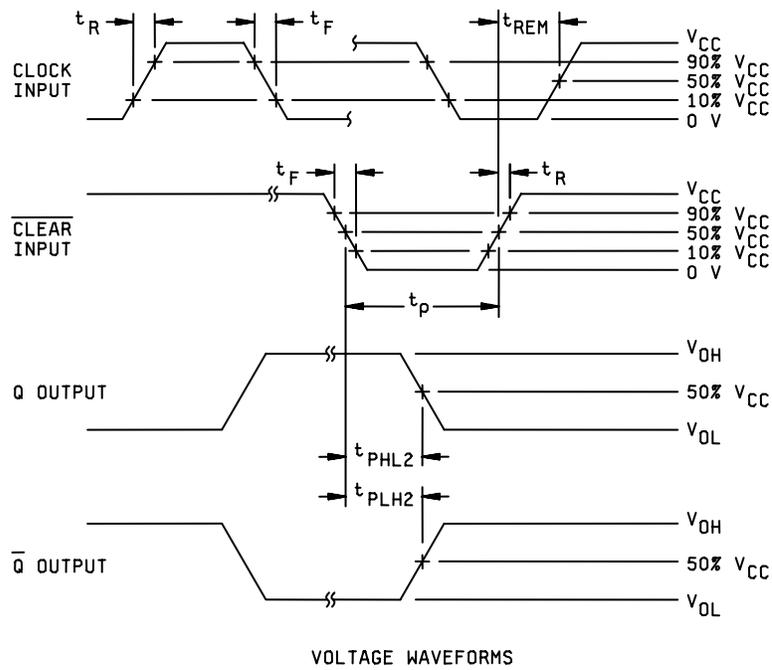
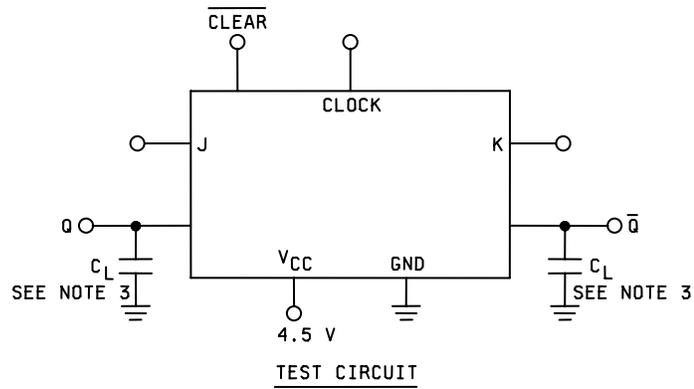
FIGURE 3. CLEAR switching test circuit and waveforms (device types 02 and 52) - Continued.



NOTES:

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 27$  ns.
2. J or K input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (J or K)  $\leq 38$  ns;  $t_{hold} \leq 8$  ns;  $t_{setup} \leq 30$  ns; PRR  $\geq 1$  MHz.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 22$  ns; PRR  $\geq 23$  MHz.
4.  $C_L = 50$  pF  $\pm 10\%$  (including test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{TLH} = t_{TLH2} - t_{TLH1}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .

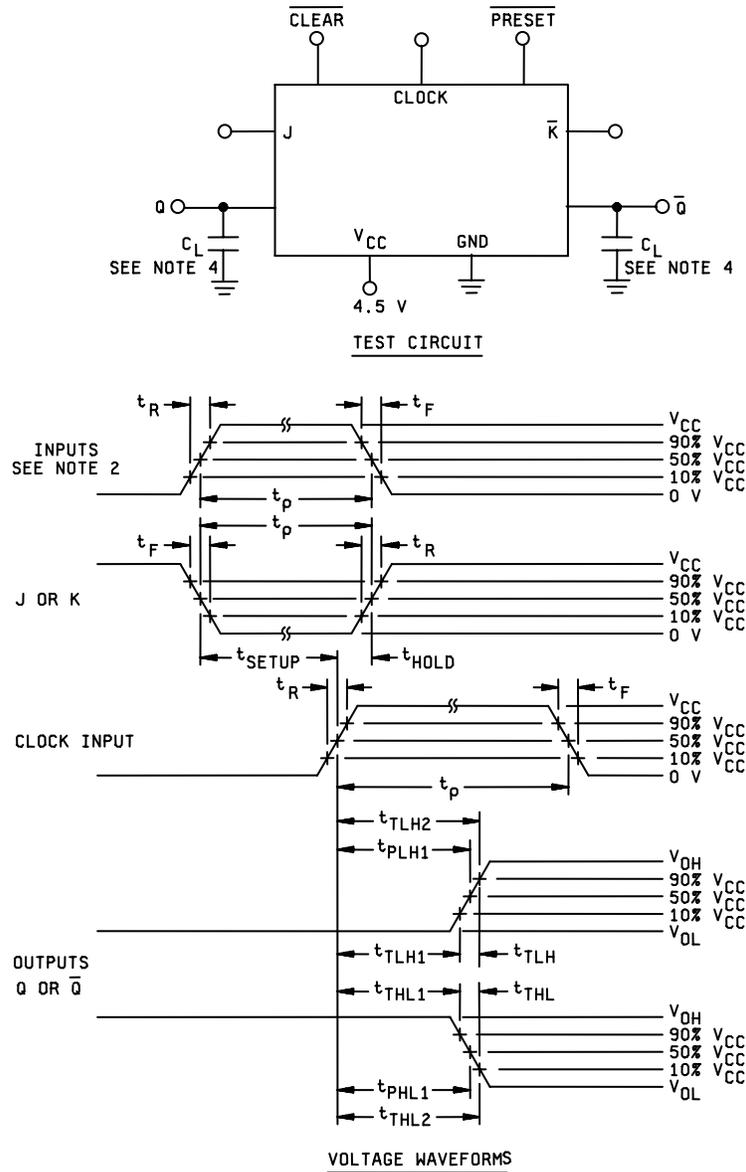
FIGURE 3. Synchronous switching test circuit and waveforms (device type 03) - Continued.



**NOTES:**

1. CLEAR pulses dominate regardless of the state of the other inputs.
2. CLEAR input pulse characteristics are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p(\text{CLEAR}) \leq 30 \text{ ns}$ ;  $t_{\text{REM}} \leq 30 \text{ ns}$ .
3.  $C_L = 50 \text{ pF} \pm 10\%$  (including test jig and probe capacitance).
4. Clock pulse prior to test with inputs biased to place the output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

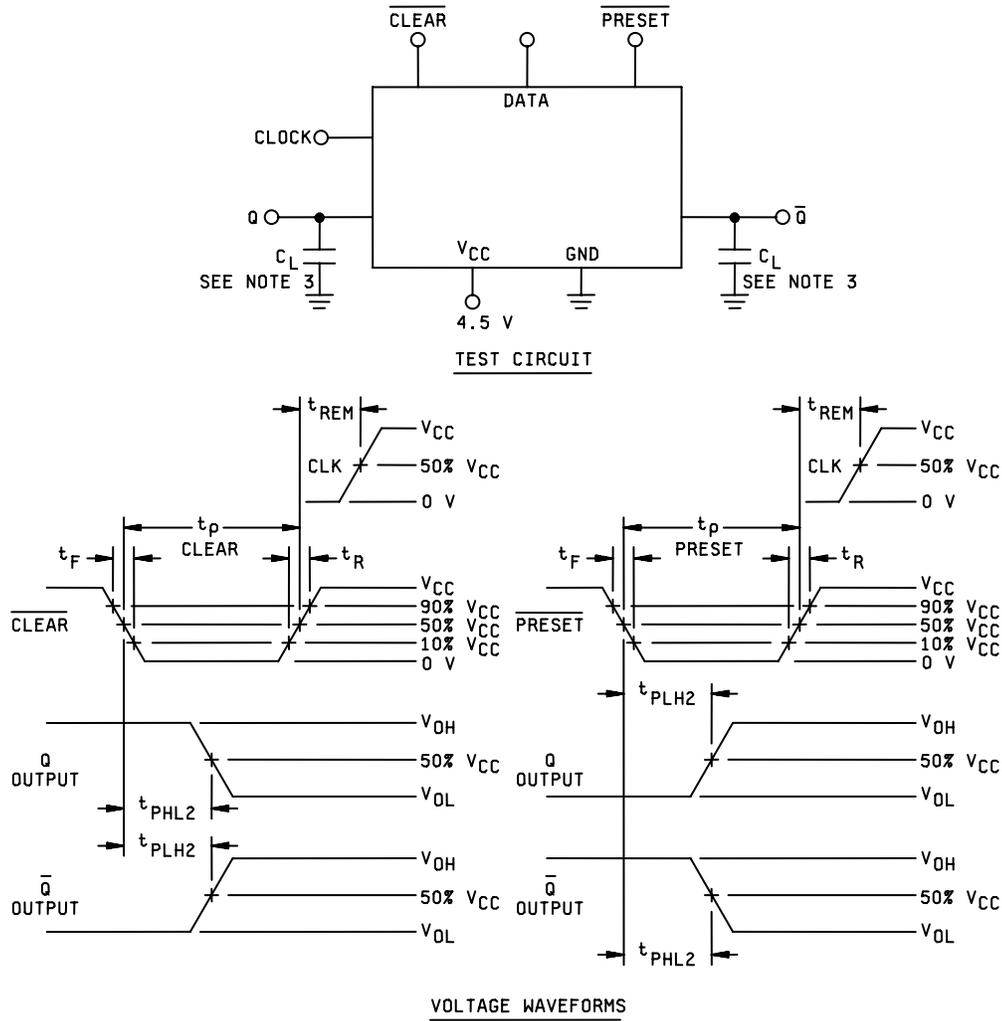
FIGURE 3. CLEAR switching test circuit and waveforms (device type 03) - Continued.



**NOTES:**

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 27$  ns.
2. J or K input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (J or K)  $\leq 38$  ns;  $t_{hold} \leq 8$  ns;  $t_{setup} \leq 30$  ns.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 22$  ns;  $PRR \geq 23$  MHz.
4.  $C_L = 50$  pF  $\pm 10\%$  (including jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{TLH} = t_{TLH2} - t_{TLH1}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .

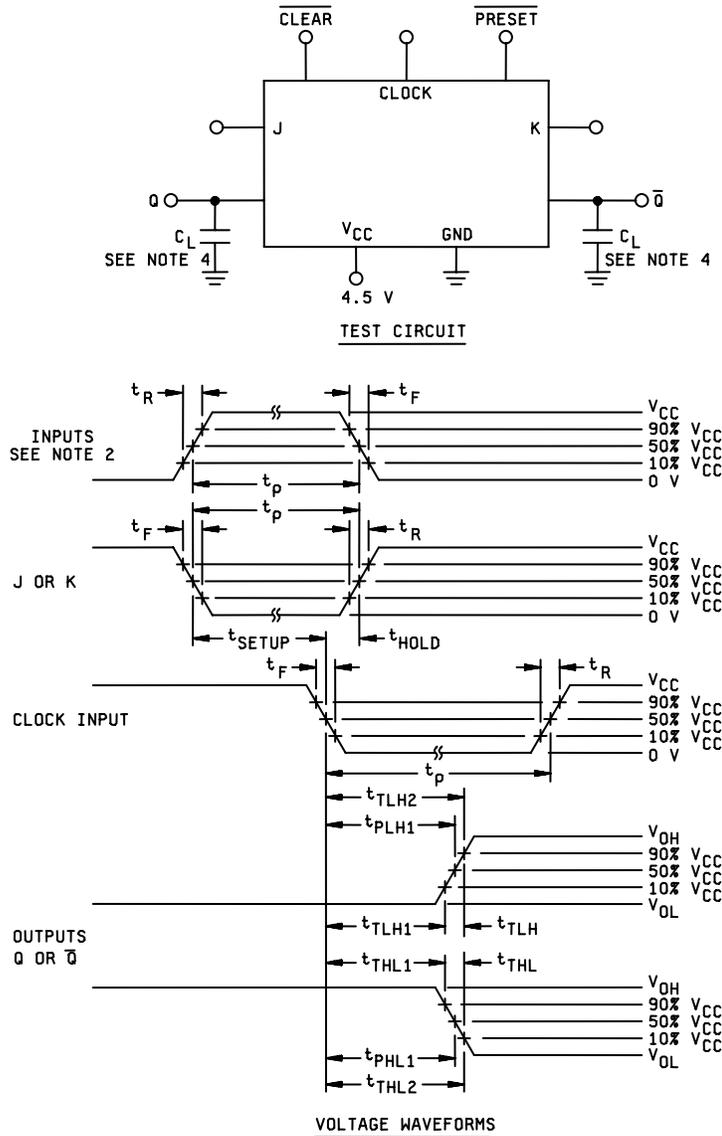
FIGURE 3. Synchronous switching test circuit and waveforms (device type 04) - Continued.



NOTES:

1.  $\overline{\text{CLEAR}}$  and  $\overline{\text{PRESET}}$  pulses are active low and dominate regardless of the state of the other inputs.
2.  $\overline{\text{CLEAR}}$  and  $\overline{\text{PRESET}}$  input pulse characteristics are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  
 $t_p(\overline{\text{CLEAR}}) = t_p(\overline{\text{PRESET}}) \leq 30 \text{ ns}$ ;  $t_{\text{REM}} \leq 30 \text{ ns}$ .
3.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
4. May be pulsed prior to test with inputs biased to place output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

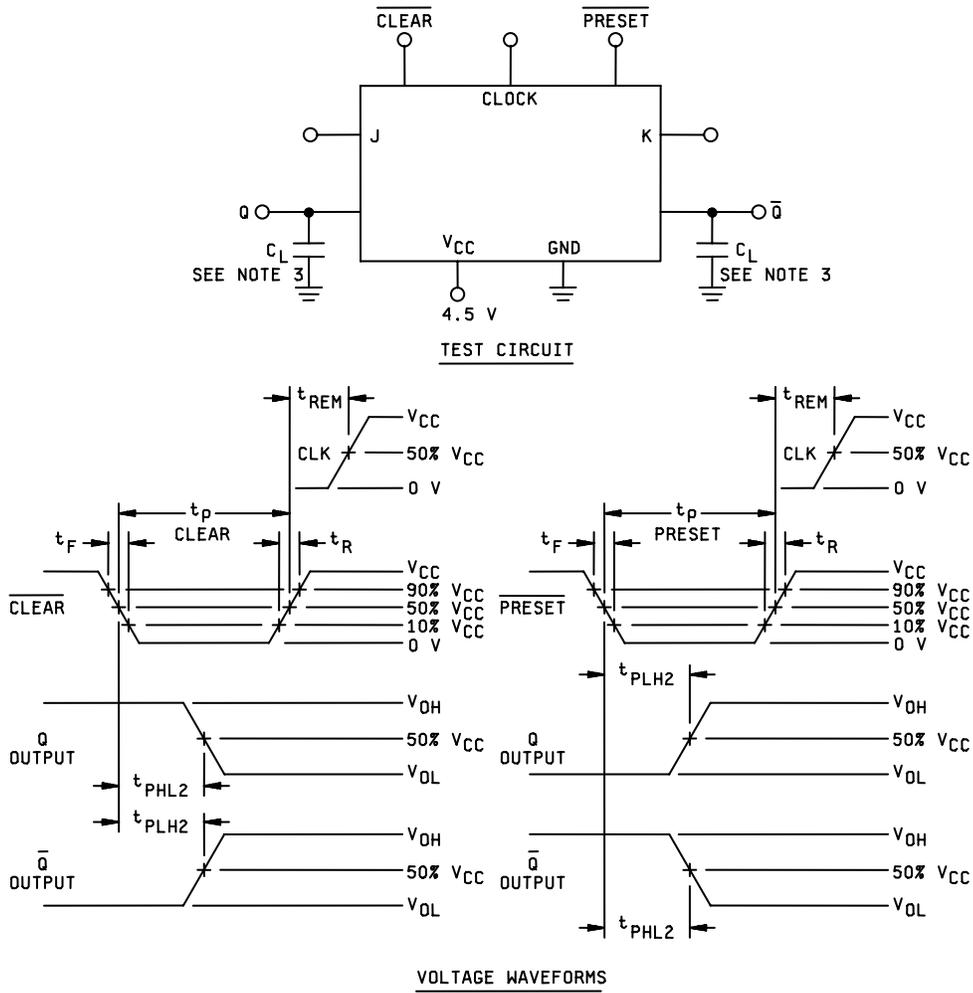
FIGURE 3.  $\overline{\text{CLEAR}}$  and  $\overline{\text{PRESET}}$  switching test circuit and waveforms (device type 04) - Continued.



NOTES:

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 30$  ns.
2. J or K input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (J or K)  $\leq 38$  ns;  $t_{hold} \leq 8$  ns;  $t_{setup} \leq 30$  ns.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 24$  ns;  $PRR \geq 21$  MHz.
4.  $C_L = 50$  pF  $\pm 10$  % (including test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{TLH} = t_{TLH2} - t_{TLH1}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .

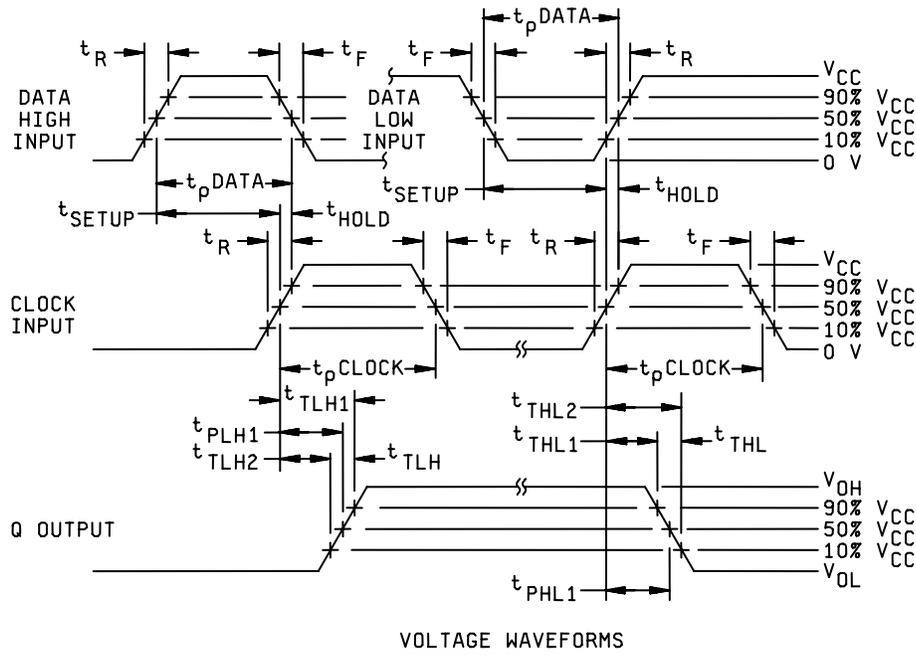
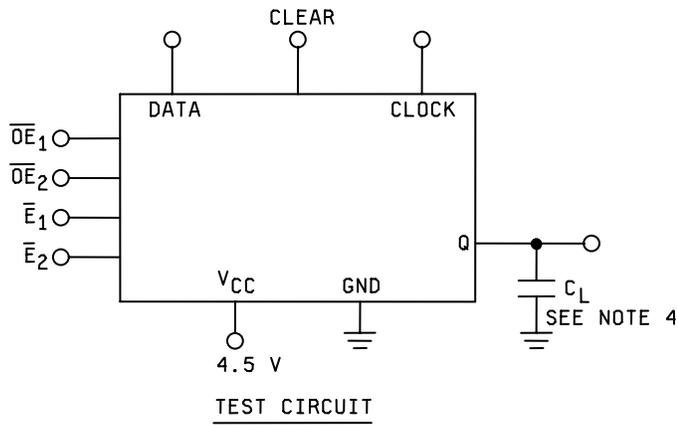
FIGURE 3. Synchronous switching test circuit and waveforms (device type 05) - Continued.



NOTES:

1. CLEAR and PRESET pulses are active low and dominate regardless of the state of the other inputs.
2. CLEAR and PRESET input pulse characteristics are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p$  (CLEAR) =  $t_p$  (PRESET)  $\leq 30 \text{ ns}$ ;  $t_{REM} \leq 30 \text{ ns}$ .
3.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
4. May be pulsed prior to test with inputs biased to place output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

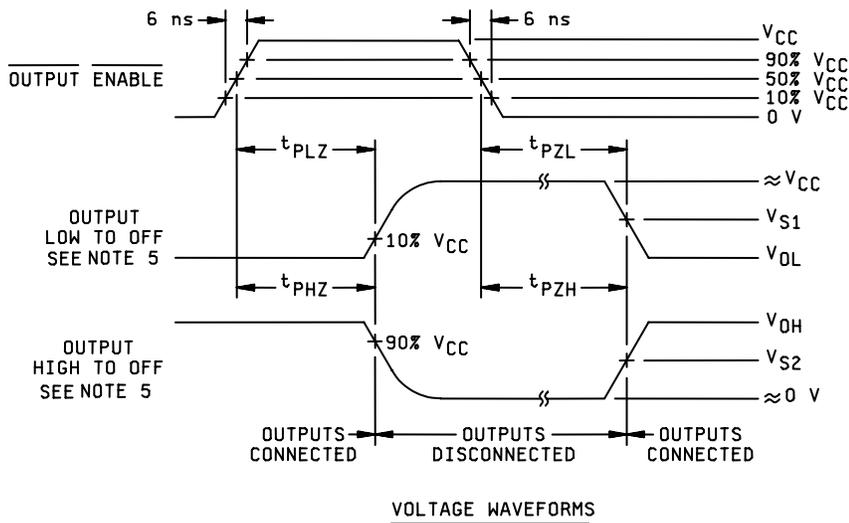
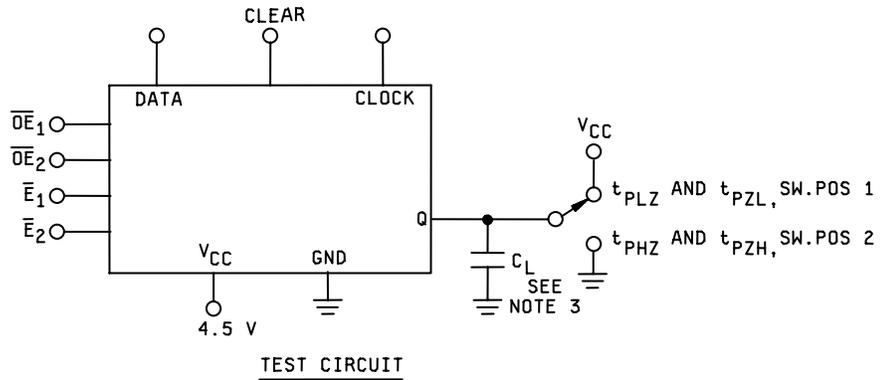
FIGURE 3. CLEAR and PRESET switching test circuit and waveforms (device type 05) - Continued.



**NOTES:**

1. Clock input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 27$  ns.
2. Data input pulse characteristics:  $t_r = t_f \leq 6$  ns;  $t_p$  (data)  $\leq 38$  ns;  $t_{setup} \leq 30$  ns;  $t_{hold} \leq 8$  ns;  $PRR \geq 1$  MHz.
3. The clock input characteristics for  $f_{MAX}$  are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (clock)  $\leq 22$  ns;  $PRR \geq 23$  MHz.
4.  $C_L = 50$  pF  $\pm 10$  % (including test jig and probe capacitance).
5.  $t_{TLH} = t_{TLH1} - t_{TLH2}$ ;  $t_{THL} = t_{THL2} - t_{THL1}$ .
6. Voltage measurements are to be made with respect to network ground terminal.

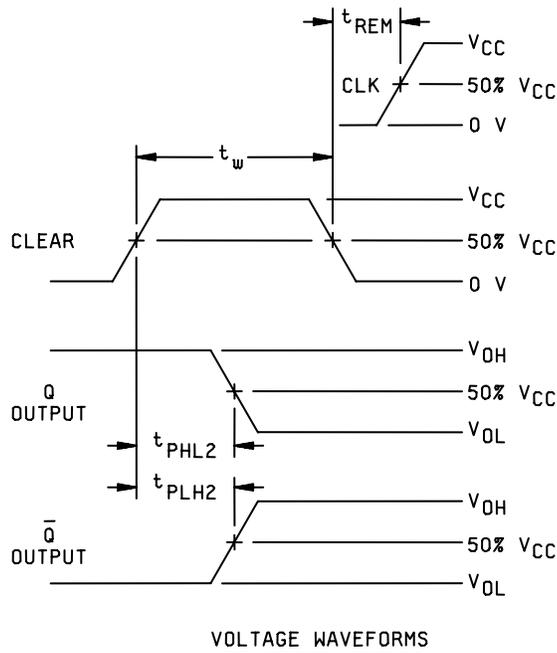
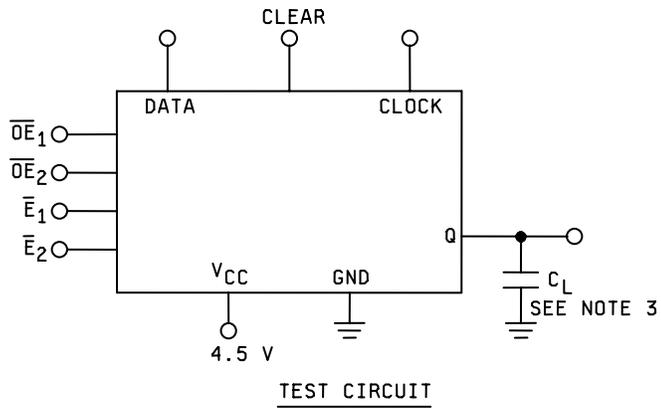
FIGURE 3. Synchronous switching test circuit and waveforms (device type 06) - Continued.



**NOTES:**

1.  $\overline{OE1}$  and  $\overline{OE2}$  pulses are active low and one or both must be active to enable the outputs.
2.  $\overline{OE1}$  and  $\overline{OE2}$  input pulse characteristics are as follows:  $t_r = t_f \leq 6$  ns;  $t_{pOE1} = t_{pOE2} \geq 200$  ns.
3.  $C_L = 50$  pF  $\pm 10$  % (including test jig and probe capacitance).
4.  $\overline{OE1}$  or  $\overline{OE2}$  does not affect the sequential operation of the flip-flop.
5. For  $t_{PHZ}$  and  $t_{PZH}$ , a 1 k $\Omega$  resistor is connected between the output and the GND terminal. For  $t_{PZL}$  and  $t_{PLZ}$ , a 1 k $\Omega$  resistor is connected between the output and the  $V_{CC}$  terminal.  $V_{S1} = V_{OL} + 0.1$  V ( $V_{OH} - V_{OL}$ ).  $V_{S2} = V_{OH} - 0.1$  V ( $V_{OH} - V_{OL}$ ).

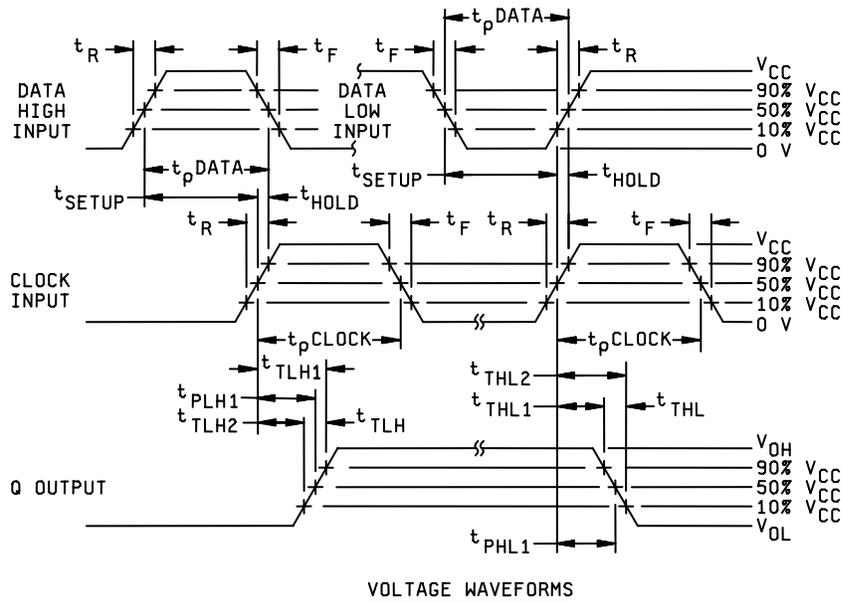
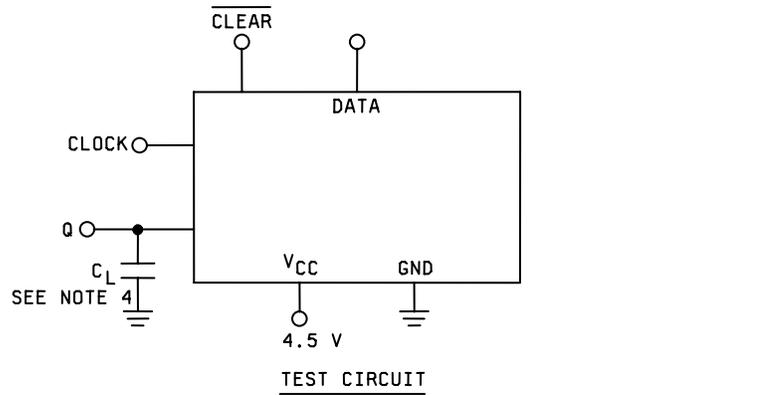
FIGURE 3. Three-state switching test circuit and waveforms (device type 06) - Continued.



NOTES:

1. CLEAR pulses are active high and dominate regardless of the state of the clock and data inputs.
2. CLEAR input pulse characteristics are as follows:  $t_r = t_f \leq 6$  ns;  $t_p$  (CLEAR)  $\leq 30$  ns;  $t_{REM} \leq 27$  ns.
3.  $C_L = 50$  pF  $\pm 10$  % (including test jig and probe capacitance).
4. Clock pulse prior to test with inputs biased to place output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

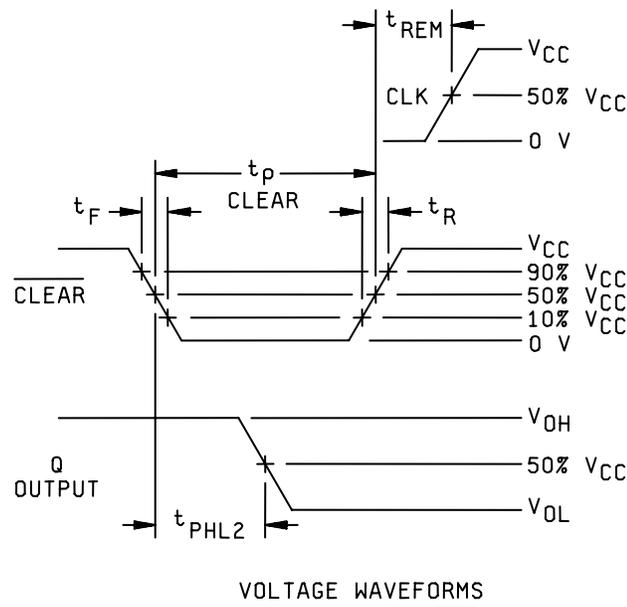
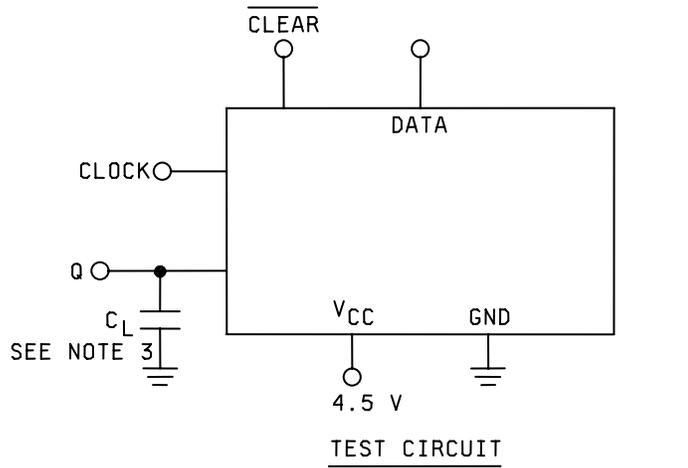
FIGURE 3. CLEAR switching test circuit and waveforms (device type 06) - Continued.



**NOTES:**

1. Clock input pulse characteristics:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p (\text{clock}) \leq 27 \text{ ns}$ .
2. Data input pulse characteristics:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p (\text{data}) \leq 38 \text{ ns}$ ;  $t_{\text{setup}} \leq 30 \text{ ns}$ ;  $t_{\text{hold}} \leq 8 \text{ ns}$ .
3. The clock input characteristics for  $f_{\text{MAX}}$  are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p (\text{clock}) \leq 22 \text{ ns}$ ;  $\text{PRR} \geq 23 \text{ MHz}$ .
4.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{\text{TLH}} = t_{\text{TLH1}} - t_{\text{TLH2}}$ ;  $t_{\text{THL}} = t_{\text{THL2}} - t_{\text{THL1}}$ .

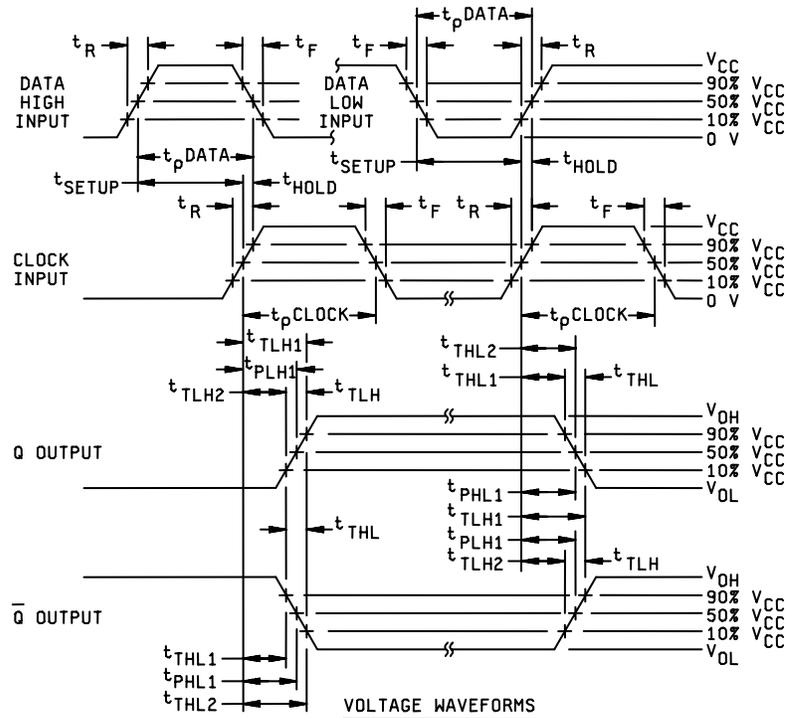
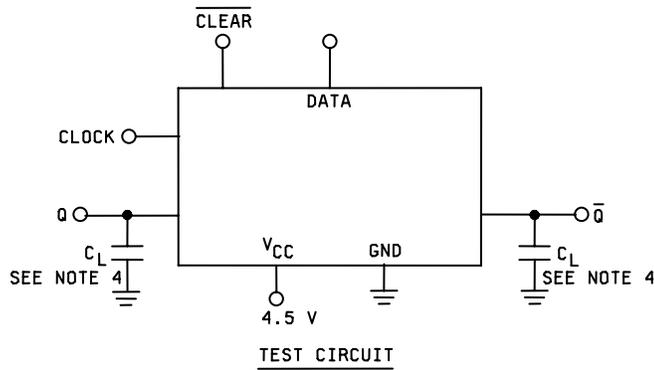
FIGURE 3. Synchronous switching test circuit and waveforms (device type 07) - Continued.



NOTES:

1. CLEAR pulses are active low and dominate regardless of the state of the clock and data inputs.
2. CLEAR input pulse characteristics are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p (\text{CLEAR}) \leq 24 \text{ ns}$ ;  $t_{REM} \leq 30 \text{ ns}$ .
3.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
4. Clock pulse prior to test with inputs biased to place the output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

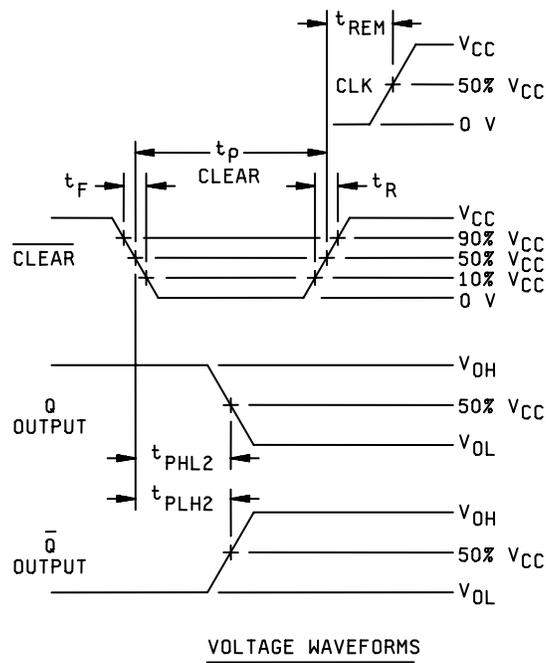
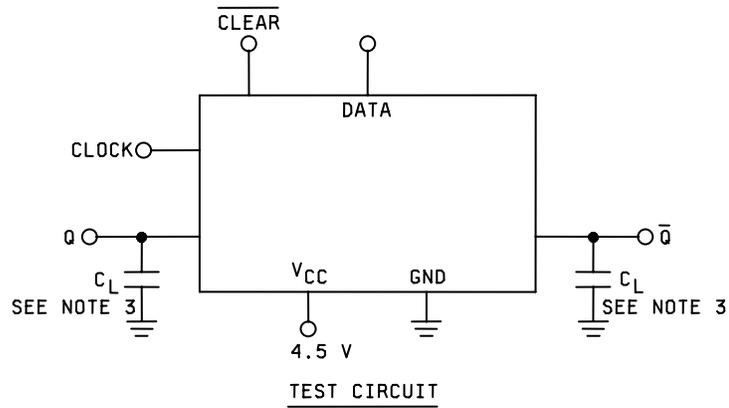
FIGURE 3. CLEAR switching test circuit and waveforms (device type 07) - Continued.



**NOTES:**

1. Clock input pulse characteristics:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p \text{ (clock)} \leq 24 \text{ ns}$ .
2. Data input pulse characteristics:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p \text{ (data)} \leq 38 \text{ ns}$ ;  $t_{\text{setup}} \leq 30 \text{ ns}$ ;  $t_{\text{hold}} \leq 8 \text{ ns}$ .
3. The clock input characteristics for  $f_{\text{MAX}}$  are as follows:  $t_r = t_f \leq 6 \text{ ns}$ ;  $t_p \text{ (clock)} \leq 19 \text{ ns}$ ;  $\text{PRR} \geq 26 \text{ MHz}$ .
4.  $C_L = 50 \text{ pF} \pm 10 \%$  (including test jig and probe capacitance).
5. Voltage measurements are to be made with respect to network ground terminal.
6.  $t_{\text{TLH}} = t_{\text{TLH1}} - t_{\text{TLH2}}$ ;  $t_{\text{THL}} = t_{\text{THL2}} - t_{\text{THL1}}$ .

FIGURE 3. Synchronous switching test circuit and waveforms (device type 08) - Continued.



NOTES:

1.  $\overline{\text{CLEAR}}$  pulses are active low and dominate regardless of the state of the clock and data inputs.
2.  $\overline{\text{CLEAR}}$  input pulse characteristics are as follows:  $t_r = t_f \leq 6\text{ ns}$ ;  $t_p(\overline{\text{CLEAR}}) \leq 24\text{ ns}$ ;  $t_{\text{REM}} \leq 30\text{ ns}$ .
3.  $C_L = 50\text{ pF} \pm 10\%$  (including test jig and probe capacitance).
4. Clock pulse prior to test with inputs biased to place the output at the appropriate level for test.
5. Voltage measurements are to be made with respect to the network ground terminal.

FIGURE 3.  $\overline{\text{CLEAR}}$  switching test circuit and waveforms (device type 08) - Continued.

TABLE III. Group A inspection for device type 01.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit										
			Cases C,D		1		3		4		6		8		9			10		12		13			14		16		18		19		20	
			Test no.	1CLK	1CLR	1K	V <sub>CC</sub>	2CLK	2CLR	2J	2Q	2K	GND	1Q	1Q	1J		Min	Max	Min	Max	Min	Max		Min	Max								
V <sub>IC</sub> (pos) 1/		1	1mA			GND										1/																V		
		2		1mA													1CLR															"		
		3				1mA											1K															"		
		4															2CLK															"		
		5							1mA								2CLR															"		
		6															2J															"		
		7															2K															"		
		8															1J															"		
V <sub>IC</sub> (neg) 1/		9	-1mA			1/										GND																"		
		10		-1mA													1CLR															"		
		11			-1mA												1K															"		
		12															2CLK															"		
		13															2CLR															"		
		14															2J															"		
		15															2K															"		
		16															1J															"		
I <sub>CC</sub>	3005	17	6.0V	GND	6.0V	6.0V	6.0V	GND	6.0V							6.0V	V <sub>CC</sub>															μA		
		18	2/	6.0V	GND	6.0V	2/	6.0V	6.0V	6.0V							6.0V	V <sub>CC</sub>														μA		
V <sub>OH3</sub>	3006	19	1.2V	1.2V	1.2V	6.0V										1Q																V		
		20															2Q															"		
		21	2/	4.2V	1.2V												1Q																"	
		22	2/	4.2V	4.2V												1Q																"	
		23															2Q																"	
		24															2Q																"	
V <sub>OH5</sub>	3006	25-30	Same terminal conditions as specified above for V <sub>OH3</sub> except I <sub>OH</sub> = -5.2 mA															5.48			5.2			5.48										
V <sub>OL3</sub>	3007	31	1.2V	1.2V	1.2V	6.0V										20μA																	"	
		32															20μA																"	
		33	2/	4.2V	1.2V													20μA															"	
		34	2/	4.2V	4.2V													20μA															"	
		35																20μA															"	
36																20μA															"			
V <sub>OL5</sub>	3007	37-42	Same terminal conditions as specified above for V <sub>OL3</sub> except I <sub>OL</sub> = 5.2 mA																		0.26			0.4			0.26							
I <sub>OS4</sub>	3011	43	3/	4.0V	GND	4.0V										GND																	mA	
		44	3/	4.0V	4.0V	4.0V																											"	
		45																															"	
		46																															"	

See footnotes at end of table.



TABLE III. Group A inspection for device type 01 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit											
			2		3		4		6		8		9		10			12		13		14			16		18		19		20				
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		15	16	17	18	19	20		21	22	23	24	25	26	27	28			
Cases C,D	1CLK	1CLR	1K	V <sub>CC</sub>	2CLK	2CLR	2J	2Q	2K	GND	1Q	1Q	1J	Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C																	
Test no.	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max															
Truth table tests 6/ 7/	3014	81	A	A	A	4.5V	A	A	A	B	L	H	A	GND	H	L	A	All outputs	5/	5/	5/	5/	5/	5/											
		82	A	A	A	"	A	A	B	L	H	A	A	GND	H	L	B	"	"	"	"	"	"	"	"	"	"	"	"	"	"				
		83	B	A	A	"	B	A	B	H	L	A	"	"	"	L	H	B	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
		84	A	A	A	"	A	A	B	H	L	A	"	"	"	L	H	B	"	"	"	"	"	"	"	"	"	"	"	"	"	"			
		85	A	A	A	"	A	A	A	H	L	A	"	"	"	L	H	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"		
		86	B	A	A	"	B	A	A	L	H	A	"	"	"	H	L	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
		87	A	A	A	"	A	A	A	L	H	A	"	"	"	H	L	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	
		88	B	A	A	"	B	A	A	H	L	A	"	"	"	L	H	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
		89	A	A	A	"	A	A	A	H	L	A	"	"	"	L	H	A	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"
																		Test limits 8/																	
																		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C													
																		Min	Max	Min	Max	Min	Max												
f <sub>MAX</sub> 7/ 9/	(Fig. 3)	90	IN	4.5V	4.5V	4.5V	"	IN	4.5V	4.5V	OUT	OUT	4.5V	GND	OUT	OUT	4.5V	1Q	31		23		31		MHz										
		91	IN	4.5V	4.5V	"	"	IN	4.5V	4.5V	OUT	OUT	4.5V	"	"	OUT	4.5V	1Q	"	"	"	"	"	"	"										
		92				"	"	IN	4.5V	4.5V	OUT	OUT	4.5V	"	"	OUT	4.5V	2Q	"	"	"	"	"	"	"										
		93				"	"	IN	4.5V	4.5V	OUT	OUT	4.5V	"	"	OUT	4.5V	2Q	"	"	"	"	"	"	"										
t <sub>PHL1</sub> 7/	3003 (Fig. 3)	94	IN	4.5V	GND	"	"	IN	4.5V	IN	OUT	OUT	GND	"	OUT	OUT	IN	1CLK to 1Q	5	30	5	40	5	30	ns										
		95	IN	4.5V	IN	"	"	IN	4.5V	IN	OUT	OUT	GND	"	OUT	OUT	GND	1CLK to 1Q	"	"	"	"	"	"	"										
		96				"	"	IN	4.5V	IN	OUT	OUT	GND	"	OUT	OUT	IN	2CLK to 2Q	"	"	"	"	"	"	"										
		97				"	"	IN	4.5V	GND	OUT	OUT	IN	"	OUT	OUT	GND	2CLK to 2Q	"	"	"	"	"	"	"										
t <sub>PLH1</sub> 7/	3003 (Fig. 3)	98	IN	4.5V	4.5V	"	"	IN	4.5V	IN	OUT	OUT	4.5V	"	OUT	OUT	IN	1CLK to 1Q	"	"	"	"	"	"	"										
		99	IN	4.5V	IN	"	"	IN	4.5V	IN	OUT	OUT	4.5V	"	OUT	OUT	4.5V	1CLK to 1Q	"	"	"	"	"	"	"										
		100				"	"	IN	4.5V	IN	OUT	OUT	4.5V	"	OUT	OUT	4.5V	2CLK to 2Q	"	"	"	"	"	"	"										
		101				"	"	IN	4.5V	4.5V	OUT	OUT	IN	"	OUT	OUT	4.5V	2CLK to 2Q	"	"	"	"	"	"	"										
t <sub>PHL2</sub> 7/	3003 (Fig. 3)	102	10/	IN	GND	"	"	10/	IN	4.5V		OUT	GND	"	OUT		4.5V	1CLR to 1Q	6	32	6	43	6	32	"										
		103				"	"	10/	IN	4.5V		OUT	GND	"	OUT		4.5V	2CLR to 2Q	"	"	"	"	"	"	"										
t <sub>PLH2</sub> 7/	3003 (Fig. 3)	104	10/	IN	GND	"	"	10/	IN	4.5V	OUT		GND	"		OUT	4.5V	1CLR to 1Q	"	"	"	"	"	"	"										
		105				"	"	10/	IN	4.5V	OUT		GND	"		OUT	4.5V	2CLR to 2Q	"	"	"	"	"	"	"										
t <sub>THL</sub> 7/	3004 (Fig. 3)	106	IN	4.5V	4.5V	"	"	IN	4.5V	4.5V	OUT	OUT	GND	"	OUT	OUT	GND	1Q	3	15	3	20	3	15	"										
		107	IN	4.5V	GND	"	"	IN	4.5V	4.5V	OUT	OUT	GND	"	OUT	OUT	4.5V	1Q	"	"	"	"	"	"	"										
		108				"	"	IN	4.5V	4.5V	OUT	OUT	GND	"	OUT	OUT	4.5V	2Q	"	"	"	"	"	"	"										
		109				"	"	IN	4.5V	GND	OUT	OUT	GND	"	OUT	OUT	4.5V	2Q	"	"	"	"	"	"	"										
t <sub>TLH</sub> 7/	3004 (Fig. 3)	110	IN	4.5V	4.5V	"	"	IN	4.5V	GND	OUT	OUT	GND	"	OUT	OUT	GND	1Q	"	"	"	"	"	"	"										
		111	IN	4.5V	GND	"	"	IN	4.5V	GND	OUT	OUT	GND	"	OUT	OUT	4.5V	1Q	"	"	"	"	"	"	"										
		112				"	"	IN	4.5V	GND	OUT	OUT	GND	"	OUT	OUT	4.5V	2Q	"	"	"	"	"	"	"										
		113				"	"	IN	4.5V	4.5V	OUT	OUT	GND	"	OUT	OUT	GND	2Q	"	"	"	"	"	"	"										

See footnotes at end of table.

TABLE III. Group A inspection for device type 02.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max	
V <sub>IC</sub> (pos) 1/		1	1mA													GND	1CLR	1/	1.5					V
		2		1mA														1D	"	"				"
		3			1mA													1CLK	"	"				"
		4				1mA												1PRE	"	"				"
		5					1mA											2PRE	"	"				"
		6											1mA					2CLK	"	"				"
		7												1mA				2D	"	"				"
		8														1mA		2CLR	"	"				"
V <sub>IC</sub> (neg) 1/		9	-1mA													1/	1CLR		-1.5				"	
		10		-1mA													1D	"	"				"	
		11			-1mA												1CLK	"	"				"	
		12				-1mA											1PRE	"	"				"	
		13					-1mA										2PRE	"	"				"	
		14											-1mA				2CLK	"	"				"	
		15												-1mA			2D	"	"				"	
		16													-1mA		2CLR	"	"				"	
I <sub>CC</sub>	3005	17	6.0V	GND	GND	GND										V <sub>CC</sub>		0.15		15			μA	
		18	GND	GND	GND	6.0V										6.0V	V <sub>CC</sub>		0.15		15			μA
V <sub>OH3</sub>	3006	19	4.2V	1.2V	1.2V	1.2V	-20μA										1Q	5.95		5.95		5.95		V
		20	1.2V	1.2V	1.2V	4.2V		-20μA									1Q	"	"	"	"	"	"	"
		21															2Q	"	"	"	"	"	"	"
		22															2Q	"	"	"	"	"	"	"
		23	4.2V	4.2V	2/	4.2V	-20μA										1Q	"	"	"	"	"	"	"
		24	4.2V	1.2V	2/	4.2V		-20μA									1Q	"	"	"	"	"	"	"
		25															2Q	"	"	"	"	"	"	"
		26															2Q	"	"	"	"	"	"	"
V <sub>OH5</sub>	3006	27-34	Same terminal conditions as specified above for V <sub>OH3</sub> except I <sub>OH</sub> = -5.2 mA.														5.48		5.2		5.48		"	
V <sub>OL3</sub>	3007	35	4.2V	1.2V	1.2V	1.2V	20μA	20μA	GND							6.0V	1Q		0.05		0.05		0.05	"
		36	1.2V	1.2V	1.2V	4.2V											1Q	"	"	"	"	"	"	"
		37															2Q	"	"	"	"	"	"	"
		38									20μA		20μA	4.2V	1.2V	1.2V	1.2V	2Q	"	"	"	"	"	"
		39	4.2V	4.2V	2/	4.2V											1Q	"	"	"	"	"	"	"
		40	4.2V	1.2V	2/	4.2V											1Q	"	"	"	"	"	"	"
		41						20μA									2Q	"	"	"	"	"	"	"
		42															2Q	"	"	"	"	"	"	"
V <sub>OL5</sub>	3007	43-50	Same terminal conditions as specified above for V <sub>OL3</sub> except I <sub>OL</sub> = 5.2 mA.															0.26		0.4		0.26	"	
I <sub>OS4</sub>	3011	51	4.0V	GND	GND	GND	GND									4.0V	1Q	-10	-120	-10	-120	-10	-120	mA
		52	GND	GND	GND	4.0V											1Q	"	"	"	"	"	"	"
		53															2Q	"	"	"	"	"	"	"
		54															2Q	"	"	"	"	"	"	"

See footnotes at end of table.

TABLE III. Group A inspection for device type 02 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit																
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C																		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max																	
I <sub>IH</sub>	3010	55	6.0V	6.0V	6.0V	6.0V			GND							6.0V	1CLR	.05		0.1																				
		56	1D														1CLK							1PRE	1Q	1Q	GND	2Q	2PRE	2CLK	2D	2CLR	V <sub>CC</sub>	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR
		57																																						
		58																																						
		59																																						
		60																																						
		61																																						
62																																								
I <sub>IL</sub>	3009	63	GND	GND	GND												1CLR	-.05		-0.1																				
		64	1D														1CLK							1PRE	2PRE	2CLK	2D	2CLR	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR					
		65																																						
		66																																						
		67																																						
		68																																						
		69																																						
		70																																						
																	Subgroup 4 T <sub>C</sub> = +25°C																							
C <sub>i</sub>	3012	71	4/	4/	4/				GND							GND	1CLR	10																						
		72	1D														1CLK							1PRE	2PRE	2CLK	2D	2CLR	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR					
		73																																						
		74																																						
		75																																						
		76																																						
		77																																						
78																																								
																	Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C																			
Truth table tests 6/ 7/	3014	79	B	A	B	A	L	H	GND	H	L	A	B	A	B	4.5V	All	5/	5/	5/	5/	5/	5/																	
		80	B	A	A	A	L	H	H	H	L	A	B	A	B	B		outputs																						
		81	B	A	B	A	L	H	H	H	L	A	B	B	A	B																								
		82	A	A	A	A	L	H	H	H	L	A	B	B	A	A																								
		83	A	A	B	B	H	L	L	L	H	B	B	A	A	A																								
		84	A	B	B	B	H	L	L	L	H	B	B	B	A	A																								
		85	A	B	A	B	H	L	L	L	H	B	A	B	B	A																								
		86	A	B	B	B	H	L	L	L	H	B	B	B	B	A																								
		87	A	B	B	A	H	L	L	L	H	A	B	B	B	A																								
		88	A	B	A	A	L	H	H	H	L	A	A	A	B	A																								

See footnotes at end of table.

TABLE III. Group A inspection for device type 02 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit					
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C							
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max						
Truth table tests 6/ 7/	3014	89 90 91	A A A	B A A	B B A	A A A	L L H	H H L	GND H “	H H L	L L H	A A A	B B A	B A A	A A A	4.5V “ “	All outputs “	5/ “ “	5/ “ “	5/ “ “	5/ “ “	5/ “ “	5/ “ “						
																		Test limits 8/											
																		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C							
																		Min	Max	Min	Max	Min	Max						
t <sub>MAX</sub> 7/ 9/	(Fig. 3)	92 93 94 95	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	OUT OUT	OUT OUT	GND “ “	OUT OUT	OUT OUT	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	4.5V “ “	1Q 1Q 2Q 2Q	28 “ “ “		21 “ “ “		28 “ “ “		MHz “ “ “					
t <sub>PHL1</sub> 7/	3003 (Fig. 3)	96 97 98 99	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	“ “ “	1CLK to 1Q 2CLK to 2Q 1CLK to 1Q 2CLK to 2Q	5 “ “ “	31 “ “ “	5 “ “ “	41 “ “ “	5 “ “ “	31 “ “ “	ns “ “ “					
t <sub>PLH1</sub> 7/	3003 (Fig. 3)	100 101 102 103	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	“ “ “	1CLK to 1Q 2CLK to 2Q 1CLK to 1Q 2CLK to 2Q	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “					
t <sub>PLH2</sub> 7/	3003 (Fig. 3)	104 105 106 107	IN 4.5V	GND GND	GND GND	4.5V IN	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V IN	GND GND	GND GND	IN 4.5V	“ “ “	1CLR to 1Q 1PRE to 1Q 2CLR to 2Q 2PRE to 2Q	“ “ “ “	41 “ “ “	“ “ “ “	54 “ “ “	“ “ “ “	41 “ “ “	“ “ “ “					
t <sub>PLH2</sub> 7/	3003 (Fig. 3)	108 109 110 111	IN 4.5V	GND GND	GND GND	4.5V IN	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V IN	GND GND	GND GND	IN 4.5V	“ “ “	1CLR to 1Q 1PRE to 1Q 2CLR to 2Q 2PRE to 2Q	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “					
t <sub>THL</sub> 7/	3004 (Fig. 3)	112 113 114 115	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	“ “ “	1Q 2Q 1Q 2Q	3 “ “ “	15 “ “ “	3 “ “ “	20 “ “ “	3 “ “ “	15 “ “ “	“ “ “ “					
t <sub>TLH</sub> 7/	3004 (Fig. 3)	116 117 118 119	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	OUT OUT	OUT OUT	“ “ “	OUT OUT	OUT OUT	4.5V 4.5V	IN IN	IN IN	4.5V 4.5V	“ “ “	1Q 2Q 1Q 2Q	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “	“ “ “ “					

See footnotes at end of table.

TABLE III. Group A inspection for device type 03.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit	
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C			
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max		
V <sub>IC</sub> (pos) 1/		1	1mA			1mA			1/						GND	1J	1/	1.5					V		
		2							"	1mA					"	1K	"	"					"		
		3							"		1mA				"	2J	"	"					"		
		4							"			1mA			"	2CLK	"	"					"		
		5							"				1mA		"	2CLR	"	"					"		
		6							"					1mA	"	2K	"	"					"		
		7							"						1mA	1CLK	"	"					"		
		8							"						1mA	1CLR	"	"					"		
V <sub>IC</sub> (neg) 1/		9	-1mA			-1mA			GND						1/	1J		-1.5					"		
		10							"	-1mA					"	1K		"					"		
		11							"		-1mA				"	2J		"					"		
		12							"			-1mA			"	2CLK		"					"		
		13							"				-1mA		"	2CLR		"					"		
		14							"					-1mA	"	2K		"					"		
		15							"						"	1CLK		"					"		
		16							"						"	1CLR		"					"		
I <sub>CC</sub>	3005	17	6.0V			6.0V			"	6.0V	6.0V	GND	6.0V	6.0V	GND	6.0V	V <sub>CC</sub>		0.15		15		μA		
		18	6.0V			GND			"	6.0V	2/	6.0V	GND	2/	6.0V	V <sub>CC</sub>		0.15		15			μA		
V <sub>OH3</sub>	3006	19	1.2V	-20μA		1.2V			-20μA	"	1.2V	1.2V	1.2V	1.2V	1.2V	1.2V	1Q	5.95		5.95		5.95	V		
		20							"							2Q	"	"					"		
		21	4.2V	-20μA	-20μA	1.2V			-20μA	"					2/	4.2V	1Q	"	"					"	
		22	1.2V	-20μA		4.2V				"					2/	4.2V	1Q	"	"					"	
		23					-20μA			"	4.2V	2/	4.2V	1.2V		4.2V	2Q	"	"					"	
		24					-20μA			"	1.2V	2/	4.2V	4.2V		4.2V	2Q	"	"					"	
V <sub>OH5</sub>	3006	25-30	Same terminal conditions as specified above for V <sub>OH3</sub> except I <sub>OH</sub> = -5.2 mA.														5.48		5.2		5.48				
V <sub>OL3</sub>	3007	31	1.2V		20μA	1.2V			GND						1.2V	1.2V	6.0V	1Q		0.05		0.05	0.05		
		32							"	1.2V	1.2V	1.2V	1.2V				2Q	"	"				"		
		33	4.2V	20μA		1.2V				"					2/	4.2V	1Q	"	"				"		
		34	1.2V		20μA	4.2V				"	4.2V	2/	4.2V	1.2V		4.2V	1Q	"	"				"		
		35								"	4.2V	2/	4.2V	1.2V		4.2V	2Q	"	"					"	
36								"	1.2V	2/	4.2V	4.2V		4.2V	2Q	"	"					"			
V <sub>OL5</sub>	3007	37-42	Same terminal conditions as specified above for V <sub>OL3</sub> except I <sub>OL</sub> = 5.2 mA.															0.26		0.4		0.26			
I <sub>OS4</sub>	3011	43	4.0V	GND	GND	GND			GND						3/	4.0V	4.0V	1Q	-10	-120	-10	-120	-10	-120	mA
		44	GND			4.0V			"						3/	4.0V		1Q	"	"	"	"	"	"	"
		45					GND			"	4.0V	3/	4.0V	GND		4.0V		2Q	"	"	"	"	"	"	"
		46					GND			"	GND	3/	4.0V	4.0V		4.0V		2Q	"	"	"	"	"	"	"

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit	
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C			
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max		
I <sub>IH</sub>	3010	47	6.0V							GND							6.0V	1J		.05		0.1			μA
		48					6.0V					6.0V							1K						
		49																	2J						
		50																	2CLK						
		51																	2CLR						
		52																	2K						
		53																	1CLK						
54																	1CLR								
I <sub>IL</sub>	3009	55	GND															1J		-.05		-0.1			
		56					GND											1K							
		57																2J							
		58																2CLK							
		59																2CLR							
		60																2K							
		61																1CLK							
62																1CLR									
																		Subgroup 4 T <sub>C</sub> = +25°C							
C <sub>i</sub>	3012	63	4/							GND							GND	1J		10					pF
		64					4/											1K							
		65										4/						2J							
		66											4/					2CLK							
		67												4/				2CLR							
		68													4/			2K							
		69														4/		1CLK							
70															4/	1CLR									
																		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C			
Truth table tests 6/ 7/	3014	71	A	H	L	B	L	H	GND	A	A	B	B	A	B	4.5V	All outputs	5/	5/	5/	5/	5/	5/		
		72	A	H	L	B	L	H		A	B	B	B	B	B										
		73	A	H	L	B	L	H		A	A	B	B	A	B										
		74	A	H	L	B	L	H		A	A	A	A	B	A										
		75	B	H	L	B	L	H		B	A	A	B	A	A										
		76	B	H	L	B	L	H		B	B	A	B	B	A										
		77	B	H	L	B	L	H		B	A	A	B	A	A										
		78	A	H	L	B	L	H		A	A	A	B	A	A										
		79	A	L	H	B	H	L		A	B	A	B	B	A										
		80	A	L	H	B	H	L		A	A	A	B	A	A										

See footnotes at end of table.

TABLE III. Group A inspection for device type 03 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max	
Truth table tests 6/ 7/	3014	81	A	L	H	A	H	L	GND	A	A	A	A	A	A	4.5V	All outputs	5/	5/	5/	5/	5/	5/	
		82	B	L	H	A	H	L	"	B	A	A	A	A	A	"		"	"	"	"	"	"	"
		83	B	H	L	A	L	H	"	B	B	A	A	B	A	"		"	"	"	"	"	"	"
		84	B	H	L	A	L	H	"	B	A	A	A	A	A	"		"	"	"	"	"	"	"
		85	A	H	L	A	L	H	"	A	A	A	A	A	A	"		"	"	"	"	"	"	"
		86	A	L	H	A	H	L	"	A	B	A	A	B	A	"		"	"	"	"	"	"	"
		87	A	L	H	A	H	L	"	A	A	A	A	A	A	"		"	"	"	"	"	"	"
		88	A	H	L	A	L	H	"	A	B	A	A	B	A	"		"	"	"	"	"	"	"
		89	A	H	L	A	L	H	"	A	A	A	A	A	"	"	"	"	"	"	"	"		
																	Test limits 8/							
																	Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C			
																	Min	Max	Min	Max	Min	Max		
f <sub>MAX</sub> 7/ 9/	(Fig. 3)	90 91 92 93	4.5V 4.5V	OUT OUT	OUT OUT	4.5V 4.5V	OUT OUT	OUT OUT	GND " " "	4.5V 4.5V	IN IN	4.5V 4.5V	4.5V 4.5V	IN IN	4.5V 4.5V	4.5V "	1Q 1Q 2Q 2Q	31 " " "	" " " "	23 " " "	" " " "	31 " " "	" " " "	MHz " " "
t <sub>PHL1</sub> 7/	3003 (Fig. 3)	94 95 96 97	IN GND	OUT OUT	OUT OUT	GND IN	OUT OUT	OUT OUT	" " " "	4.5V GND IN	IN IN	4.5V 4.5V	IN GND	IN IN	4.5V 4.5V	" "	1CLK to 1Q 1CLK to 1Q 2CLK to 2Q 2CLK to 2Q	5 " " "	30 " " "	5 " " "	40 " " "	5 " " "	30 " " "	ns " " "
t <sub>PLH1</sub> 7/	3003 (Fig. 3)	98 99 100 101	IN 4.5V	OUT OUT	OUT OUT	4.5V IN	OUT OUT	OUT OUT	" " " "	4.5V IN	IN IN	4.5V 4.5V	IN 4.5V	IN IN	4.5V 4.5V	" "	1CLK to 1Q 1CLK to 1Q 2CLK to 2Q 2CLK to 2Q	" " " "	" " " "	" " " "	" " " "	" " " "	" " " "	" " " "
t <sub>PHL2</sub> 7/	3003 (Fig. 3)	102 103	4.5V	OUT	OUT	GND	OUT	OUT	" "	4.5V	10/	IN	GND	10/ IN	IN "	" "	1CLR to 1Q 2CLR to 2Q	6 "	27 "	6 "	36 "	6 "	27 "	" "
t <sub>PLH2</sub> 7/	3003 (Fig. 3)	104 105	4.5V	OUT	OUT	GND	OUT	OUT	" "	4.5V	10/	IN	GND	10/ IN	IN "	" "	1CLR to 1Q 2CLR to 2Q	" "	" "	" "	" "	" "	" "	" "
t <sub>THL</sub> 7/	3004 (Fig. 3)	106 107 108 109	4.5V GND	OUT OUT	OUT OUT	GND 4.5V	OUT OUT	OUT OUT	" " " "	GND 4.5V	IN IN	4.5V 4.5V	4.5V GND	IN IN	4.5V 4.5V	" "	1Q 1Q 2Q 2Q	3 " " "	15 " " "	3 " " "	20 " " "	3 " " "	15 " " "	" " " "
t <sub>TLH</sub> 7/	3004 (Fig. 3)	110 111 112 113	GND 4.5V	OUT OUT	OUT OUT	4.5V GND	OUT OUT	OUT OUT	" " " "	4.5V GND	IN IN	4.5V 4.5V	GND 4.5V	IN IN	4.5V 4.5V	" "	1Q 1Q 2Q 2Q	" " " "	" " " "	" " " "	" " " "	" " " "	" " " "	" " " "

See footnotes at end of table.

TABLE III. Group A inspection for device type 04.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit																		
			2		3		4		5		7		8		9			10		12		13			14		15		17		18		19		20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		15	16	17	18	19	20		Min	Max	Min	Max	Min	Max												
V <sub>IC</sub> (pos) 1/		1	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		2	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		3	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		4	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		5	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		6	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		7	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		8	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		9	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
		10	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	1.5																	V				
V <sub>IC</sub> (neg) 1/		11	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		12	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		13	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		14	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		15	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		16	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		17	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		18	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		19	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
		20	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	1CLR	1/	-1.5																	V				
I <sub>CC</sub>	3005	21	GND	6.0V	6.0V	GND	6.0V						6.0V	GND	6.0V	6.0V	GND	6.0V	V <sub>CC</sub>	V <sub>CC</sub>		0.15		15											μA							
V <sub>OH3</sub>	3006	22	6.0V	6.0V	6.0V	GND	GND							GND	GND	6.0V	6.0V	6.0V	V <sub>CC</sub>	V <sub>CC</sub>		0.15		15											μA							
		23	4.2V	1.2V	1.2V	1.2V	1.2V	1.2V	-20μA											1Q	5.95			5.95			5.95								V							
		24	1.2V	4.2V	4.2V	4.2V	4.2V	4.2V	-20μA											1Q	5.95			5.95			5.95								V							
		25	1.2V	4.2V	4.2V	4.2V	4.2V	4.2V	-20μA											1Q	5.95			5.95			5.95								V							
		26	1.2V	4.2V	4.2V	4.2V	4.2V	4.2V	-20μA											1Q	5.95			5.95			5.95								V							
		27	4.2V	4.2V	4.2V	2/	4.2V	-20μA												1Q	5.95			5.95			5.95								V							
		28	4.2V	1.2V	1.2V	2/	4.2V	-20μA												1Q	5.95			5.95			5.95								V							
		29	4.2V	1.2V	1.2V	2/	4.2V	-20μA												1Q	5.95			5.95			5.95								V							
		30	4.2V	1.2V	1.2V	2/	4.2V	-20μA												1Q	5.95			5.95			5.95								V							
		V <sub>OH5</sub>	3006	31	4.2V	1.2V	1.2V	1.2V	1.2V	-5.2mA											1Q	5.48			5.2			5.48								V						
32	1.2V			4.2V	4.2V	4.2V	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
33	1.2V			4.2V	4.2V	4.2V	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
34	1.2V			4.2V	4.2V	4.2V	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
35	4.2V			4.2V	4.2V	2/	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
36	4.2V			1.2V	1.2V	2/	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
37	4.2V			1.2V	1.2V	2/	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
38	4.2V			1.2V	1.2V	2/	4.2V	-5.2mA											1Q	5.48			5.2			5.48								V								
V <sub>OL3</sub>	3007			39	1.2V	4.2V	4.2V	1.2V	4.2V	20μA											1Q			0.05		0.05			0.05							V						
				40	4.2V	1.2V	1.2V	1.2V	1.2V	20μA											1Q			0.05		0.05			0.05							V						
		41	4.2V	1.2V	1.2V	1.2V	1.2V	20μA											1Q			0.05		0.05			0.05							V								
		42	4.2V	1.2V	1.2V	1.2V	1.2V	20μA											1Q			0.05		0.05			0.05							V								
		43	4.2V	1.2V	1.2V	2/	4.2V	20μA											1Q			0.05		0.05			0.05							V								
		44	4.2V	4.2V	4.2V	2/	4.2V	20μA											1Q			0.05		0.05			0.05							V								

See footnotes at end of table.

TABLE III. Group A inspection for device type 04 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases E,F Test no.	Terminal conditions 1/																Measured terminal	Test limits						Unit		
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C				
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max			
V <sub>OL5</sub>	3007	47	1.2V	4.2V	4.2V	1.2V	4.2V	5.2mA											6.0V	1Q		0.26		0.4		0.26	V	
		48	4.2V	1.2V	1.2V	1.2V	1.2V		5.2mA	GND										"	1Q							"
		49								"	5.2mA									"	2Q							"
		50								"		5.2mA								"	2Q							"
		51	4.2V	1.2V	1.2V	2/	4.2V	5.2mA			"									"	1Q							"
		52	4.2V	4.2V	4.2V	2/	4.2V				"	5.2mA								"	1Q							"
		53									"		5.2mA							"	2Q							"
54									"			5.2mA						"	2Q							"		
I <sub>OS4</sub>	3011	55	4.0 V	GND	GND	GND	GND	GND											4.0V	1Q	-10	-120	-10	-120	-10	-120	mA	
		56	GND	GND	GND	GND	4.0V		GND	"									"	1Q	"	"	"	"	"	"	"	
		57								"	GND			4.0V	GND	GND	GND	GND	"	2Q	"	"	"	"	"	"	"	
		58								"		GND			GND	GND	GND	4.0V	"	2Q	"	"	"	"	"	"	"	
I <sub>IH</sub>	3010	59	6.0V															6.0V	1CLR		50		100			nA		
		60		6.0V															"	1J							"	
		61			6.0V														"	1K							"	
		62				6.0V													"	1CLK							"	
		63					6.0V												"	1PRE							"	
		64						6.0V						6.0V					"	2PRE							"	
		65													6.0V				"	2CLK							"	
		66														6.0V				"	2K						"	
67															6.0V			"	2J						"			
68																6.0V	"	2CLR							"			
I <sub>IL</sub>	3009	69	GND															"	1CLR		-50		-100			"		
		70		GND															"	1J							"	
		71			GND														"	1K							"	
		72				GND													"	1CLK							"	
		73					GND												"	1PRE							"	
		74						GND							GND				"	2PRE							"	
		75														GND			"	2CLK							"	
		76															GND			"	2K						"	
		77																GND		"	2J						"	
		78																	GND	"	2CLR						"	
																			Subgroup 4 T <sub>C</sub> = +25°C									
																			Min	Max								
C <sub>i</sub>	3012	79	4/							GND								GND	1CLR							pF		
		80		4/						"								"	1J							"		
		81			4/					"								"	1K							"		
		82				4/				"								"	1CLK							"		
		83					4/			"								"	1PRE							"		
		84						4/		"				4/				"	2PRE							"		
		85								"					4/			"	2CLK							"		
		86								"						4/		"	2K							"		
		87								"							4/		"	2J						"		
		88								"								4/	"	2CLR						"		

See footnotes at end of table.

TABLE III. Group A inspection for device type 04 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit														
			2		3		4		5		7		8		10		12			13		14		15			17		18		19		20		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		17	18	19	20	Min	Max		Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max	Min	Max
Truth table tests 6/ 7/	3014	Test no.	1CLR	1J	1K	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2K	2J	2CLR	V <sub>CC</sub>	All outputs	5/	5/	5/	5/	5/	5/															
		89	B	A	A	B	A	L	H	GND	H	L	A	B	A	A	B	4.5V		"	"	"	"	"	"															
		90	B	A	A	A	A	L	H	"	H	L	A	A	A	A	B	"		"	"	"	"	"																
		91	B	A	A	A	B	A	A	"	H	L	A	B	A	A	B	"		"	"	"	"	"																
		92	A	A	A	A	B	A	L	H	"	H	L	A	B	A	A	A		"	"	"	"	"	"															
		93	A	A	A	A	B	B	H	L	"	L	H	B	B	A	A	A		"	"	"	"	"	"															
		94	A	B	A	A	B	B	H	L	"	L	H	B	B	A	B	A		"	"	"	"	"	"															
		95	A	B	B	B	B	B	H	L	"	L	H	B	B	B	B	A		"	"	"	"	"	"															
		96	A	B	B	A	B	B	H	L	"	L	H	B	A	B	B	A		"	"	"	"	"	"															
		97	A	B	B	B	B	B	H	L	"	L	H	B	B	B	B	A		"	"	"	"	"	"															
		98	A	B	B	B	A	A	H	L	"	L	H	A	B	B	B	A		"	"	"	"	"	"															
		99	A	B	B	A	A	L	H	H	"	H	L	A	A	B	B	A		"	"	"	"	"	"															
		100	A	B	B	B	A	L	L	H	"	H	L	A	B	B	B	A		"	"	"	"	"	"															
		101	A	B	A	B	A	L	L	H	"	H	L	A	B	A	B	A		"	"	"	"	"	"															
		102	A	B	A	A	A	L	L	H	"	H	L	A	A	A	B	A		"	"	"	"	"	"															
		103	A	B	A	A	B	A	L	L	H	"	H	L	A	B	A	B		A	"	"	"	"	"															
		104	A	A	A	A	B	A	L	L	H	"	H	L	A	B	A	A		A	"	"	"	"	"															
		105	A	A	A	A	A	A	H	L	"	L	H	A	A	A	A	A		A	"	"	"	"	"															
		106	A	A	A	A	B	A	H	L	"	L	H	A	B	A	A	A		A	"	"	"	"	"															
		107	A	A	A	B	B	A	H	L	"	L	H	A	B	B	A	A		A	"	"	"	"	"															
		108	A	A	A	B	A	A	L	H	"	H	L	A	A	B	B	A		A	"	"	"	"	"															
109	A	A	A	B	B	A	L	L	H	"	H	L	A	B	B	A	A	"	"	"	"	"																		
110	A	A	A	B	A	A	H	L	"	L	H	A	A	B	B	A	A	"	"	"	"	"																		
111	A	A	A	B	B	A	H	L	"	L	H	A	A	B	B	A	A	"	"	"	"	"																		
112	B	A	B	B	A	L	L	H	"	H	L	A	B	B	A	B	"	"	"	"	"	"																		
																			Test limits 8/																					
																			Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C																	
																			Min	Max	Min	Max	Min	Max																
f <sub>MAX</sub>	(Fig. 3)	113	4.5V	4.5V	GND	IN	4.5V	OUT	OUT	GND	OUT	OUT	4.5V	IN	GND	4.5V	4.5V	4.5V	1Q	31		23		31		MHz														
Z/ g/		114	4.5V	4.5V	GND	IN	4.5V		OUT	"	OUT	OUT	4.5V	IN	GND	4.5V	4.5V	"	1Q	"	"	"	"	"	"	"														
		115								"								"	2Q	"	"	"	"	"	"	"														
		116								"								"	2Q	"	"	"	"	"	"	"														
t <sub>PHL1</sub>	3003 (Fig. 3)	117	4.5V	IN	GND	IN	4.5V	OUT	OUT	"	OUT	OUT	4.5V	IN	4.5V	IN	4.5V	"	1CLK to 1Q	5	31	5	41	5	31	ns														
Z/		118	4.5V	4.5V	IN	IN	4.5V		OUT	"	OUT	OUT	4.5V	IN	4.5V	IN	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"														
		119								"								"	2CLK to 2Q	"	"	"	"	"	"	"														
		120								"								"	2CLK to 2Q	"	"	"	"	"	"	"														
t <sub>PLH1</sub>	3003 (Fig. 3)	121	4.5V	IN	4.5V	IN	4.5V	OUT	OUT	"	OUT	OUT	4.5V	IN	GND	4.5V	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"														
Z/		122	4.5V	GND	IN	IN	4.5V		OUT	"	OUT	OUT	4.5V	IN	GND	4.5V	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"														
		123								"								"	2CLK to 2Q	"	"	"	"	"	"	"														
		124								"								"	2CLK to 2Q	"	"	"	"	"	"	"														
t <sub>PHL2</sub>	3003 (Fig. 3)	125	IN	4.5V	GND	GND	4.5V	OUT	OUT	"	OUT	OUT	IN	GND	GND	4.5V	4.5V	"	1CLR to 1Q	6	41	6	54	6	41	"														
Z/		126	4.5V	4.5V	GND	GND	IN		OUT	"	OUT	OUT	4.5V	GND	GND	4.5V	IN	"	1PRE to 1Q	"	"	"	"	"	"	"														
		127								"								"	2PRE to 2Q	"	"	"	"	"	"	"														
		128								"								"	2CLR to 2Q	"	"	"	"	"	"	"														

See footnotes at end of table.

TABLE III. Group A inspection for device type 04 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits 8/						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max	
t <sub>PLH2</sub> Z/	3003 (Fig. 3)	129	4.5V	4.5V	GND	GND	IN	OUT	GND									4.5V	1PRE to 1Q	6	41	6	54	6	41	ns
		130	IN	4.5V	GND	GND	4.5V		OUT	"								"	1CLR to 1Q	"	"	"	"	"	"	"
		131							"	OUT			4.5V	GND	GND	4.5V	IN	"	2CLR to 2Q	"	"	"	"	"	"	"
		132							"		OUT							"	2PRE to 2Q	"	"	"	"	"	"	"
t <sub>THL</sub> Z/	3004 (Fig. 3)	133	4.5V	IN	GND	IN	4.5V	OUT	"									"	1Q	3	15	3	20	3	15	"
		134	4.5V	4.5V	IN	IN	4.5V		OUT	"								"	1Q	"	"	"	"	"	"	"
		135							"	OUT			4.5V	IN	4.5V	IN	4.5V	"	2Q	"	"	"	"	"	"	"
		136							"		OUT							"	2Q	"	"	"	"	"	"	"
t <sub>TLH</sub> Z/	3004 (Fig. 3)	137	4.5V	IN	4.5V	IN	4.5V	OUT	"									"	1Q	"	"	"	"	"	"	"
		138	4.5V	GND	IN	IN	4.5V		OUT	"								"	1Q	"	"	"	"	"	"	"
		139							"	OUT			4.5V	IN	GND	IN	4.5V	"	2Q	"	"	"	"	"	"	"
		140							"		OUT							"	2Q	"	"	"	"	"	"	"

See footnotes at end of table.

TABLE III. Group A inspection for device type 05.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit		
			Cases E,F		2	3	4	5	7	8	9	10	12	13	14	15	17	18		19	20	Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C			Subgroup 3 T <sub>C</sub> = -55°C	
			Test no.	1CLK	1K	1J	1PRE	1Q	1Q	2Q	GND	2Q	2PRE	2J	2K	2CLK	2CLR	1CLR		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max	
V <sub>IC</sub> (pos) 1/		1	1mA															GND	1CLK	1/	1.5					V		
		2		1mA															"	1K	"	"				"		
		3			1mA														"	1J	"	"				"		
		4				1mA													"	1PRE	"	"				"		
		5													1mA				"	2PRE	"	"				"		
		6														1mA			"	2J	"	"				"		
		7															1mA		"	2K	"	"				"		
		8																1mA	"	2CLK	"	"				"		
		9																	"	2CLR	"	"				"		
		10																	"	1CLR	"	"				"		
V <sub>IC</sub> (neg) 1/		11	-1mA															GND	1CLK		-1.5					"		
		12		-1mA															"	1K	"	"				"		
		13			-1mA														"	1J	"	"				"		
		14				-1mA													"	1PRE	"	"				"		
		15													-1mA				"	2PRE	"	"				"		
		16														-1mA			"	2J	"	"				"		
		17															-1mA		"	2K	"	"				"		
		18																-1mA	"	2CLK	"	"				"		
		19																	"	2CLR	"	"				"		
		20																	"	1CLR	"	"				"		
I <sub>CC</sub>	3005	21	6.0V	6.0V	6.0V	GND												"								μA		
		22	6.0V	6.0V	6.0V	6.0V													"	V <sub>CC</sub>		0.15		15			μA	
V <sub>OH3</sub>	3006	23	1.2V	1.2V	4.2V	1.2V	-20μA												"	1Q	5.95		5.95		5.95		V	
		24	1.2V	1.2V	4.2V	4.2V													"	1Q	"	"		"		"		
		25																	"	2Q	"	"		"		"		
		26																	"	2Q	"	"		"		"		
		27	2/	1.2V	4.2V	4.2V	-20μA												"	2Q	"	"		"		"		
		28	2/	4.2V	1.2V	4.2V													"	1Q	"	"		"		"		
		29																	"	1Q	"	"		"		"		
		30																	"	2Q	"	"		"		"		
																				"	2Q	"	"		"		"	
																				"	2Q	"	"		"		"	
V <sub>OH5</sub>	3006	31	1.2V	1.2V	4.2V	1.2V	-5.2mA												"	1Q	5.48		5.2		5.48		V	
		32	1.2V	1.2V	4.2V	4.2V													"	1Q	"	"		"		"		
		33																	"	2Q	"	"		"		"		
		34																	"	2Q	"	"		"		"		
		35	2/	1.2V	4.2V	4.2V	-5.2mA												"	1Q	"	"		"		"		
		36	2/	4.2V	1.2V	4.2V													"	1Q	"	"		"		"		
		37																	"	1Q	"	"		"		"		
		38																	"	2Q	"	"		"		"		
																				"	2Q	"	"		"		"	
																				"	2Q	"	"		"		"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 05 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C		
			Cases E,F	1CLK	1K	1J	1PRE	1Q	1Q	2Q	2PRE	2J	2K	2CLK	2CLR	1CLR	V <sub>CC</sub>	Min		Max	Min	Max	Min	Max		
V <sub>OL3</sub>	3007	39	1.2V	4.2V	1.2V	4.2V	20μA		GND								1.2V	6.0V	1Q		0.05		0.05		0.05	V
		40	1.2V	4.2V	1.2V	1.2V		20μA		"							4.2V	"	1Q		"		"		"	"
		41								"							2Q	"	2Q		"		"		"	"
		42								"	20μA						1.2V	"	2Q		"		"		"	"
		43	2/	4.2V	1.2V	4.2V	20μA			"							1.2V	"	1Q		"		"		"	"
		44	2/	1.2V	4.2V	4.2V		20μA		"							4.2V	"	1Q		"		"		"	"
		45								"							4.2V	"	1Q		"		"		"	"
46								20μA							2/	4.2V	"	2Q		"		"		"	"	
V <sub>OL5</sub>	3007	47	1.2V	4.2V	1.2V	4.2V	5.2mA										1.2V	"	1Q		0.26		0.4		0.26	"
		48	1.2V	4.2V	1.2V	1.2V		5.2mA		"							4.2V	"	1Q		"		"		"	"
		49								"							2Q	"	2Q		"		"		"	"
		50								"	5.2mA						1.2V	"	2Q		"		"		"	"
		51	2/	4.2V	1.2V	4.2V	5.2mA			"							4.2V	"	1Q		"		"		"	"
		52	2/	1.2V	4.2V	4.2V		5.2mA		"							4.2V	"	1Q		"		"		"	"
		53								"							4.2V	"	2Q		"		"		"	"
54								5.2mA							2/	4.2V	"	2Q		"		"		"	"	
I <sub>OS4</sub>	3011	55	GND	GND	GND	GND	GND										4.0V	4.0V	1Q	-10	-120	-10	-120	-10	-120	mA
		56	GND	GND	GND	4.0V		GND		"							"	"	1Q	"	"	"	"	"	"	"
		57								"							"	"	2Q	"	"	"	"	"	"	"
		58							GND	"	GND	4.0V	GND	GND	GND	GND	4.0V	"	2Q	"	"	"	"	"	"	"
I <sub>IH</sub>	3010	59	6.0V														6.0V	1CLK		50		100			nA	
		60		6.0V													"	1K		"		"			"	
		61			6.0V												"	1J		"		"			"	
		62				6.0V											"	1PRE		"		"			"	
		63															"	2PRE		"		"			"	
		64															"	2J		"		"			"	
		65															"	2K		"		"			"	
		66															"	2CLK		"		"			"	
		67															"	2CLR		"		"			"	
68															"	1CLR		"		"			"			
I <sub>IL</sub>	3009	69	GND														"	1CLK		-50		-100			nA	
		70		GND													"	1K		"		"			"	
		71			GND												"	1J		"		"			"	
		72				GND											"	1PRE		"		"			"	
		73															"	2PRE		"		"			"	
		74															"	2J		"		"			"	
		75															"	2K		"		"			"	
		76															"	2CLK		"		"			"	
		77															"	2CLR		"		"			"	
		78															"	1CLR		"		"			"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 05 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 4 T <sub>C</sub> = +25°C						
			Cases E,F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15		16	Min	Max				
Test no.	1CLK	1K	1J	1PRE	1Q	1Q	2Q	GND	2Q	2PRE	2J	2K	2CLK	2CLR	1CLR	V <sub>CC</sub>			Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C			
																		Min	Max	Min	Max	Min	Max			
C <sub>i</sub>	3012	79	4/						GND								GND	1CLK		10					pF	
		80		4/					"									1K		"				"		
		81			4/				"									1J		"				"		
		82				4/			"									1PRE		"				"		
		83							"			4/						2PRE		"				"		
		84							"				4/					2J		"				"		
		85							"					4/				2K		"				"		
		86							"						4/			2CLK		"				"		
		87							"							4/		2CLR		"				"		
		88							"								4/	1CLR		"				"		
Truth table tests 6/ 7/	3014	89	A	B	A	A	L	H	H	GND	L	A	A	A	B	B	B	6.0V	All outputs	5/	5/	5/	5/	5/	5/	
		90	B	B	A	A	L	H	H	"	L	A	A	A	B	B	B	"	"	"	"	"	"	"	"	
		91	A	B	A	A	L	H	H	"	L	A	A	A	A	B	B	"	"	"	"	"	"	"	"	
		92	A	A	A	A	L	L	H	H	"	L	A	A	A	A	A	"	"	"	"	"	"	"	"	
		93	A	A	A	A	L	L	H	H	"	L	A	A	A	A	A	"	"	"	"	"	"	"	"	
		94	A	A	A	B	L	H	H	"	L	A	B	A	A	A	A	"	"	"	"	"	"	"	"	
		95	A	A	B	B	L	H	L	"	H	B	B	A	A	A	A	"	"	"	"	"	"	"	"	
		96	B	A	B	B	L	H	L	"	H	B	B	A	A	A	A	"	"	"	"	"	"	"	"	
		97	A	A	B	B	L	H	L	"	H	B	B	A	A	A	A	"	"	"	"	"	"	"	"	
		98	A	A	B	A	L	H	L	"	H	A	A	A	A	A	A	"	"	"	"	"	"	"	"	
		99	A	B	B	A	L	H	L	"	H	B	B	A	A	A	A	"	"	"	"	"	"	"	"	
		100	B	B	B	A	L	H	L	"	H	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		101	A	B	B	A	L	H	L	"	H	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		102	A	B	B	A	L	H	L	"	H	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		103	A	B	B	A	L	H	H	"	L	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		104	B	B	B	A	L	H	H	"	L	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		105	A	B	B	A	L	H	H	"	L	A	B	B	B	A	A	"	"	"	"	"	"	"	"	
		106	A	B	A	A	L	H	H	"	L	A	A	B	B	A	A	"	"	"	"	"	"	"	"	
		107	B	B	A	A	L	L	L	"	H	A	A	B	B	A	A	"	"	"	"	"	"	"	"	
		108	A	B	A	A	L	L	L	"	H	A	A	A	A	A	A	"	"	"	"	"	"	"	"	
109	A	A	A	A	L	L	L	"	H	A	A	A	A	A	A	"	"	"	"	"	"	"	"			
110	A	A	B	A	L	L	L	"	H	A	A	A	A	A	A	"	"	"	"	"	"	"	"			
111	B	A	B	A	L	H	H	"	L	A	B	A	A	B	A	"	"	"	"	"	"	"	"			
112	A	A	A	A	L	H	H	"	L	A	B	A	A	A	A	"	"	"	"	"	"	"	"			
113	A	A	A	A	L	H	H	"	L	A	A	A	A	A	A	"	"	"	"	"	"	"	"			
114	B	A	A	A	L	H	L	"	H	A	A	A	A	B	A	"	"	"	"	"	"	"	"			
115	A	A	A	A	L	L	L	"	H	A	A	A	A	A	A	"	"	"	"	"	"	"	"			
116	B	A	A	A	L	L	H	"	L	A	A	A	A	B	A	"	"	"	"	"	"	"	"			
117	A	A	A	A	L	H	H	"	L	A	A	A	A	A	A	"	"	"	"	"	"	"	"			
118	A	A	A	A	L	H	H	"	L	A	A	A	A	A	A	"	"	"	"	"	"	"	"			

See footnotes at end of table.

TABLE III. Group A inspection for device type 05 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases E,F Test no.	Terminal conditions 1/																Measured terminal	Test limits 8/						Unit			
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C					
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max				
			1CLK	1K	1J	1PRE	1Q	1Q	2Q	GND	2Q	2PRE	2J	2K	2CLK	2CLR	1CLR	V <sub>CC</sub>											
f <sub>MAX</sub> Z/ g/	(Fig. 3)	119 120 121 122	IN IN	4.5V 4.5V	4.5V 4.5V	4.5V 4.5V	OUT	OUT		GND		OUT	4.5V	4.5V	4.5V	IN	4.5V	4.5V	4.5V	4.5V	1Q 1Q 2Q 2Q	28		21		28		MHz	
t <sub>PHL1</sub> Z/	3003 (Fig. 3)	123 124 125 126	IN IN	4.5V IN	IN 4.5V	4.5V 4.5V	OUT	OUT				OUT	4.5V	IN	4.5V	IN	4.5V	4.5V			1CLK to 1Q 1CLK to 1Q 2CLK to 2Q 2CLK to 2Q	5	31	5	41	5	31	ns	
t <sub>PLH1</sub> Z/	3003 (Fig. 3)	127 128 129 130	IN IN	GND IN	IN GND	4.5V 4.5V	OUT	OUT				OUT	4.5V	IN	GND	IN	4.5V	4.5V			1CLK to 1Q 1CLK to 1Q 2CLK to 2Q 2CLK to 2Q								
t <sub>PHL2</sub> Z/	3003 (Fig. 3)	131 132 133 134	GND GND	4.5V 4.5V	4.5V 4.5V	IN	OUT	OUT				OUT	4.5V	4.5V	4.5V	GND	IN	4.5V	IN			1CLR to 1Q 1PRE to 1Q 2CLR to 2Q 2PRE to 2Q	6	32	6	43	6	32	
t <sub>PLH2</sub> Z/	3003 (Fig. 3)	135 136 137 138	GND GND	4.5V 4.5V	4.5V 4.5V	IN	OUT	OUT				OUT	IN	4.5V	4.5V	GND	4.5V	IN				1PRE to 1Q 1CLR to 1Q 2PRE to 2Q 2CLR to 2Q							
t <sub>THL</sub> Z/	3004 (Fig. 3)	139 140 141 142	IN IN	4.5V IN	IN 4.5V	4.5V 4.5V	OUT	OUT				OUT	4.5V	IN	4.5V	IN	4.5V	4.5V				1Q 1Q 2Q 2Q	3	15	3	20	3	15	
t <sub>TLH</sub> Z/	3004 (Fig. 3)	143 144 145 146	IN IN	GND IN	IN GND	4.5V 4.5V	OUT	OUT				OUT	4.5V	IN	GND	IN	4.5V	4.5V				1Q 1Q 2Q 2Q							

See footnotes at end of table.

TABLE III. Group A inspection for device type 06.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit		
			Cases E,F		2	3	4	5	7	8	9	10	12	13	14	15	17	18		19	20	Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C			Subgroup 3 T <sub>C</sub> = -55°C	
			Test no.	OE1	OE2	1Q	2Q	3Q	4Q	CLK	GND	E1	E2	4D	3D	2D	1D	CLR		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max	
V <sub>IC</sub> (pos) 1/		1	1mA	1mA						1mA	1/							GND	OE1	1/	1.5					V		
		2								"								OE2	"	"					"			
		3								"								CLK	"	"					"			
		4								"	1mA							E1	"	"					"			
		5								"		1mA						E2	"	"					"			
		6								"			1mA					4D	"	"					"			
		7								"				1mA				3D	"	"					"			
		8								"					1mA			2D	"	"					"			
		9								"						1mA		1D	"	"					"			
		10								"							1mA	CLR	"	"					"			
V <sub>IC</sub> (neg) 1/		11	-1mA	-1mA						GND								1/	OE1		-1.5					"		
		12								"								OE2	"	"					"			
		13								"								CLK	"	"					"			
		14								"	-1mA							E1	"	"					"			
		15								"		-1mA						E2	"	"					"			
		16								"			-1mA					4D	"	"					"			
		17								"				-1mA				3D	"	"					"			
		18								"					-1mA			2D	"	"					"			
		19								"						-1mA		1D	"	"					"			
		20								"							-1mA	CLR	"	"					"			
I <sub>CC</sub>	3005	21	GND	GND						2/	"	GND	GND	6.0V	6.0V	6.0V	6.0V									μA		
		22	GND	GND						GND	"	"	"	"	"	"	"	GND				0.2	20					
I <sub>CCZ</sub>		23	6.0V	6.0V						GND	"	"	"	"	"	"	6.0V	6.0V				0.2	20					
V <sub>OH3</sub>	3006	24	1.2V	1.2V	-20μA					2/	"	1.2V	1.2V	1.2V	1.2V	1.2V	4.2V	1.2V			1Q	5.95		5.95		5.95	V	
		25	"	"		-20μA				"	"	"	"	1.2V	4.2V	1.2V	"	"			2Q	"		"		"		
		26	"	"						"	"	"	"	4.2V	1.2V	"	"	"			3Q	"		"		"		
		27	"	"						"	"	"	"	1.2V	1.2V	"	"	"			4Q	"		"		"		
V <sub>OH5</sub>	3006	28	"	"	-7.8mA					"	"	"	"	1.2V	1.2V	4.2V	"	"			1Q	5.48		5.2		5.48	"	
		29	"	"		-7.8mA				"	"	"	"	1.2V	4.2V	1.2V	"	"			2Q	"		"		"		
		30	"	"						"	"	"	"	4.2V	1.2V	1.2V	"	"			3Q	"		"		"		
		31	"	"						"	"	"	"	1.2V	1.2V	1.2V	"	"			4Q	"		"		"		
V <sub>OL3</sub>	3007	32	"	"	20μA					1.2V	"	"	"	"	4.2V	4.2V	4.2V	4.2V	"		1Q		0.05		0.05		0.05	
		33	"	"		20μA				"	"	"	"	"	"	"	"	"			2Q	"		"		"		
		34	"	"						"	"	"	"	"	"	"	"	"			3Q	"		"		"		
		35	"	"						"	"	"	"	"	"	"	"	"			4Q	"		"		"		
		36	"	"	20μA					"	"	"	"	"	"	"	"	"			1Q	"		"		"		
		37	"	"		20μA				2/	"	"	"	"	"	"	1.2V	1.2V			2Q	"		"		"		
		38	"	"						"	"	"	"	"	1.2V	4.2V	"	"			3Q	"		"		"		
		39	"	"						"	"	"	"	1.2V	4.2V	4.2V	"	"			4Q	"		"		"		

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit																
			2		3		4		5		7		8		9		10			12		13		14			15		17		18		19		20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C	
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		17	18	19	20	Min	Max		Min	Max	Min	Max	Min	Max	Min	Max								
V <sub>OL5</sub>	3007	40	1.2V	1.2V	7.8mA	7.8mA	7.8mA	7.8mA	1.2V	GND	1.2V	1.2V	4.2V	4.2V	4.2V	4.2V	4.2V	6.0V	1Q		0.26		0.4		0.26	V																
		41	"	"	"	7.8mA	7.8mA	7.8mA	"	"	"	"	"	"	"	"	"	"	2Q		"		"		"	"																
		42	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	3Q		"		"		"	"																
		43	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	4Q		"		"		"	"																
		44	"	"	7.8mA	7.8mA	7.8mA	7.8mA	2/	"	"	"	"	"	"	1.2V	1.2V	1.2V	1Q		"		"		"	"																
		45	"	"	"	7.8mA	7.8mA	7.8mA	"	"	"	"	"	"	1.2V	4.2V	"	"	2Q		"		"		"	"																
		46	"	"	"	"	7.8mA	7.8mA	"	"	"	"	"	1.2V	4.2V	"	"	3Q		"		"		"	"	"																
47	"	"	"	"	"	7.8mA	"	"	"	"	1.2V	4.2V	4.2V	"	"	4Q		"		"		"	"	"																		
I <sub>OS4</sub>	3011	48	GND	GND	GND	GND	GND	GND	"	"	GND	GND	4.0V	4.0V	4.0V	4.0V	GND	4.0V	1Q	-10	-135	-10	-135	-10	-135	mA																
		49	"	"	"	GND	GND	"	"	"	"	"	"	"	"	"	"	"	2Q	"	"	"	"	"	"	"																
		50	"	"	"	"	GND	"	"	"	"	"	"	"	"	"	"	"	"	3Q	"	"	"	"	"	"	"	"														
		51	"	"	"	"	"	GND	"	"	"	"	"	"	"	"	"	"	"	4Q	"	"	"	"	"	"	"	"														
I <sub>OZH</sub>		52	1.2V	1.2V	6.0V	6.0V	6.0V	6.0V	"	"	4.2V	4.2V	"	"	"	"	"	1.2V	6.0V	1Q		0.2		2.0		μA																
		53	"	"	"	6.0V	6.0V	6.0V	"	"	"	"	"	"	"	"	"	"	"	2Q		"		"		"																
		54	"	"	"	"	6.0V	6.0V	6.0V	"	"	"	"	"	"	"	"	"	"	3Q		"		"		"																
		55	"	"	"	"	6.0V	6.0V	6.0V	"	"	"	"	"	"	"	"	"	"	4Q		"		"		"																
I <sub>OZL</sub>		56	1.2V	1.2V	GND	GND	GND	GND	"	"	"	"	"	"	"	"	"	"	"	1Q		-0.2		-2.0		"																
		57	"	"	"	GND	GND	"	"	"	"	"	"	"	"	"	"	"	"	2Q		"		"		"																
		58	"	"	"	"	GND	"	"	"	"	"	"	"	"	"	"	"	"	3Q		"		"		"																
		59	"	"	"	"	"	GND	"	"	"	"	"	"	"	"	"	"	"	4Q		"		"		"																
I <sub>IH</sub>	3010	60	6.0V	6.0V					6.0V	"	"	"	"	"	"	"	"	"	OE1		50		100		nA																	
		61	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OE2		"		"		"																	
		62	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	CLK		"		"		"																	
		63	"	"	"	"	"	"	"	"	6.0V	E1		"		"		"																								
		64	"	"	"	"	"	"	"	"	"	6.0V	E2		"		"		"																							
		65	"	"	"	"	"	"	"	"	"	"	6.0V	6.0V	6.0V	6.0V	6.0V	6.0V	4D		"		"		"																	
		66	"	"	"	"	"	"	"	"	"	"	"	6.0V	6.0V	6.0V	6.0V	6.0V	3D		"		"		"																	
		67	"	"	"	"	"	"	"	"	"	"	"	"	6.0V	6.0V	6.0V	6.0V	2D		"		"		"																	
		68	"	"	"	"	"	"	"	"	"	"	"	"	"	6.0V	6.0V	6.0V	1D		"		"		"																	
69	"	"	"	"	"	"	"	"	"	"	"	"	"	"	6.0V	6.0V	6.0V	CLR		"		"		"																		
I <sub>IL</sub>	3009	70	GND	GND					GND	"	"	"	"	"	"	"	"	"	OE1		-50		-100		"																	
		71	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	OE2		"		"		"																	
		72	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"	CLK		"		"		"																	
		73	"	"	"	"	"	"	"	"	"	GND	E1		"		"		"																							
		74	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	GND	GND	GND	E2		"		"		"																	
		75	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	GND	GND	GND	4D		"		"		"																	
		76	"	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	GND	GND	3D		"		"		"																	
		77	"	"	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	GND	2D		"		"		"																	
		78	"	"	"	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	1D		"		"		"																	
		79	"	"	"	"	"	"	"	"	"	"	"	"	"	"	GND	GND	GND	CLR		"		"		"																

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 4 T <sub>C</sub> = +25°C						
			Cases E,F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15		16	Min	Max				
Test no.	OE1	OE2	1Q	2Q	3Q	4Q	CLK	GND	E1	E2	4D	3D	2D	1D	CLR	V <sub>CC</sub>										
C <sub>i</sub>	3012	80	4/						GND								GND	OE1		10					pF	
		81	4/	4/						"								"	OE2		"				"	
		82							4/	"	4/							"	CLK		"				"	
		83								"		4/						"	E1		"				"	
		84								"			4/					"	E2		"				"	
		85								"			4/	4/				"	4D		"				"	
		86								"				4/	4/			"	3D		"				"	
		87								"					4/	4/		"	2D		"				"	
		88								"						4/	4/	"	1D		"				"	
		89								"							4/	"	CLR		"				"	
C <sub>o</sub>	3012	90	GND	6.0V	4/				"	6.0V	6.0V					GND	6.0V	1Q		20				"		
		91	GND	6.0V		4/			"	"	"					"	"	2Q		"				"		
		92	6.0V	GND			4/			"	"	"				"	"	3Q		"				"		
		93	6.0V	GND				4/		"	"	"				"	"	4Q		"				"		
																		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C				
																		Min	Max	Min	Max	Min	Max			
Truth table tests 6/ 7/	3014	94	B	B	L	L	L	L	B	GND	B	B	A	A	A	A	4.5V	All outputs	5/	5/	5/	5/	5/	5/		
		95	B	B	L	L	L	L	B	"	B	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		96	B	B	H	H	H	H	A	"	B	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		97	B	B	H	H	H	H	B	"	B	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		98	B	B	H	H	H	H	B	"	B	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		99	B	B	H	H	H	H	B	"	A	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		100	B	B	H	H	H	H	A	"	A	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		101	B	B	H	H	H	H	B	"	A	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		102	B	B	H	H	H	H	B	"	A	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		103	B	B	H	H	H	H	A	"	A	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		104	B	B	H	H	H	H	B	"	A	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		105	B	B	H	H	H	H	B	"	B	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		106	B	B	H	H	H	H	A	"	B	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		107	B	B	H	H	H	H	B	"	B	A	B	B	B	B	"	"	"	"	"	"	"	"	"	
		108	B	B	H	H	H	H	B	"	B	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		109	B	B	L	L	L	L	A	"	B	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		110	B	B	L	L	L	L	B	"	B	B	B	B	B	B	"	"	"	"	"	"	"	"	"	
		111	B	B	L	L	L	L	B	"	B	B	A	A	B	B	"	"	"	"	"	"	"	"	"	
		112	B	B	L	L	L	L	A	"	A	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		113	B	B	L	L	L	L	B	"	A	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		114	B	B	L	L	L	L	A	"	A	B	A	A	A	A	"	"	"	"	"	"	"	"	"	
		115	B	B	L	L	L	L	B	"	A	A	A	A	A	A	"	"	"	"	"	"	"	"	"	
116	B	B	L	L	L	L	A	"	A	A	A	A	A	A	"	"	"	"	"	"	"	"	"			
117	B	B	L	L	L	L	B	"	A	A	A	A	A	A	"	"	"	"	"	"	"	"	"			
118	B	B	L	L	L	L	A	"	B	A	A	A	A	A	"	"	"	"	"	"	"	"	"			
119	B	B	L	L	L	L	A	"	B	A	A	A	A	A	"	"	"	"	"	"	"	"	"			
120	B	B	L	L	L	L	B	"	B	A	A	A	A	A	"	"	"	"	"	"	"	"	"			
121	B	B	L	L	L	L	B	"	B	B	A	A	A	A	"	"	"	"	"	"	"	"	"			
122	B	B	L	L	L	L	B	"	B	B	A	A	A	A	"	"	"	"	"	"	"	"	"			

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits 8/						Unit													
			2		3		4		5		7		8		9		10			12		13		14			15		17		18		19		20		Subgroup 9 T <sub>C</sub> = +25°C	Subgroup 10 T <sub>C</sub> = +125°C	Subgroup 11 T <sub>C</sub> = -55°C
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		17	18	19	20																
			Test no.	OE1	OE2	1Q	2Q	3Q	4Q	CLK	GND	E1	E2	4D	3D	2D	1D	CLR		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max												
f <sub>MAX</sub> 6/ 9/	(Fig. 3)	123 124 125 126	GND	GND	OUT	OUT	OUT	OUT	IN	GND	GND	GND	IN	IN	IN	GND	4.5V	1Q 2Q 3Q 4Q	31		23		31										MHz						
t <sub>PHL1</sub> Z/	3003 (Fig. 3)	127 128 129 130	"	"	OUT	OUT	OUT	OUT	"	"	"	"	IN	IN	IN	"	"	CLK to 1Q CLK to 2Q CLK to 3Q CLK to 4Q	6	35	6	47	6	35								ns							
t <sub>PLH1</sub> Z/	3003 (Fig. 3)	131 132 133 134	"	"	OUT	OUT	OUT	OUT	"	"	"	"	IN	IN	IN	"	"	CLK to 1Q CLK to 2Q CLK to 3Q CLK to 4Q	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"						
t <sub>PHL2</sub> Z/	3003 (Fig. 3)	135 136 137 138	"	"	OUT	OUT	OUT	OUT	10/	"	"	"	4.5V	4.5V	4.5V	IN	"	CLR to 1Q CLR to 2Q CLR to 3Q CLR to 4Q	5	31	5	41	5	31								"							
t <sub>PHZ</sub> Z/	3003 (Fig. 3)	139 140 141 142 143 144 145 146	IN	GND	OUT	OUT	OUT	OUT	10/	GND	GND	GND	4.5V	4.5V	4.5V	GND	4.5V	OE1 to 1Q OE1 to 2Q OE1 to 3Q OE1 to 4Q OE2 to 1Q OE2 to 2Q OE2 to 3Q OE2 to 4Q	5	26	5	35	5	26									ns						
t <sub>PLZ</sub> Z/	3003 (Fig. 3)	147 148 149 150 151 152 153 154	IN	GND	OUT	OUT	OUT	OUT	GND	"	"	"	4.5V	4.5V	4.5V	10/	"	OE1 to 1Q OE1 to 2Q OE1 to 3Q OE1 to 4Q OE2 to 1Q OE2 to 2Q OE2 to 3Q OE2 to 4Q	"	26	"	35	"	26								"							
t <sub>PZH</sub> Z/	3003 (Fig. 3)	155 156 157 158 159 160 161 162	IN	GND	OUT	OUT	OUT	OUT	10/	"	"	"	4.5V	4.5V	4.5V	GND	"	OE1 to 1Q OE1 to 2Q OE1 to 3Q OE1 to 4Q OE2 to 1Q OE2 to 2Q OE2 to 3Q OE2 to 4Q	"	"	"	"	"	"	"	"	"	"	"	"	"	"	"						

See footnotes at end of table.

TABLE III. Group A inspection for device type 06 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits 2/						Unit	
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C			
			Cases E,F	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15		16	Min	Max	Min	Max	Min		Max
Test no.	OE1	OE2	1Q	2Q	3Q	4Q	CLK	GND	GND	GND	GND	4D	3D	2D	1D	CLR	V <sub>CC</sub>	OE1 to 1Q	OE1 to 2Q	OE1 to 3Q	OE1 to 4Q	OE2 to 1Q	OE2 to 2Q	OE2 to 3Q	OE2 to 4Q		
t <sub>PZL</sub> Z/	3003 (Fig. 3)	163	IN	GND	OUT	OUT	OUT	OUT	GND	GND	GND	GND			4.5V	4.5V	4.5V	10/	4.5V	OE1 to 1Q	5	26	5	35	5	26	ns
		164	"	"	"	OUT	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE1 to 2Q	"	"	"	"	"	"	"
		165	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE1 to 3Q	"	"	"	"	"	"	"
		166	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE1 to 4Q	"	"	"	"	"	"	"
		167	GND	IN	OUT	OUT	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE2 to 1Q	"	"	"	"	"	"	"
		168	"	"	"	OUT	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE2 to 2Q	"	"	"	"	"	"	"
		169	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE2 to 3Q	"	"	"	"	"	"	"
170	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	OE2 to 4Q	"	"	"	"	"	"	"		
t <sub>THL</sub> Z/	3004 (Fig. 3)	171	"	GND	OUT	OUT	OUT	OUT	10/	"	"	"			4.5V	4.5V	4.5V	IN	"	1Q	2	12	2	16	2	12	"
		172	"	"	"	OUT	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	2Q	"	"	"	"	"	"	"
		173	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	3Q	"	"	"	"	"	"	"
		174	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	4Q	"	"	"	"	"	"	"
t <sub>TLH</sub> Z/	3004 (Fig. 3)	175	"	"	OUT	OUT	OUT	OUT	IN	"	"	"			4.5V	4.5V	4.5V	10/	"	1Q	"	"	"	"	"	"	"
		176	"	"	"	OUT	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	2Q	"	"	"	"	"	"	"
		177	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	3Q	"	"	"	"	"	"	"
		178	"	"	"	"	OUT	OUT	"	"	"	"			4.5V	4.5V		"	"	4Q	"	"	"	"	"	"	"

See footnotes at end of table.

TABLE III. Group A inspection for device type 07.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit		
			Cases E,F		2	3	4	5	7	8	9	10	12	13	14	15	17	18		19	20	Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C			Subgroup 3 T <sub>C</sub> = -55°C	
			Test no.	CLR	1Q	1D	2D	2Q	3D	3Q	GND	CLK	4Q	4D	5Q	5D	6D	6Q		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max	
V <sub>IC</sub> (pos) 1/		1	1mA		1mA	1mA				1/								GND	CLR	1/	1.5					V		
		2								"								"	1D	"	"					"		
		3								"								"	2D	"	"					"		
		4								"								"	3D	"	"					"		
		5								"	1mA							"	CLK	"	"					"		
		6								"								"	4D	"	"					"		
		7								"								"	5D	"	"					"		
		8								"							1mA	"	6D	"	"					"		
V <sub>IC</sub> (neg) 1/		9	-1mA		-1mA	-1mA				GND								1/	CLR		-1.5					"		
		10								"								"	1D		"					"		
		11								"								"	2D		"					"		
		12								"								"	3D		"					"		
		13								"	-1mA							"	CLK		"					"		
		14								"								"	4D		"					"		
		15								"								"	5D		"					"		
		16								"							-1mA	"	6D		"					"		
I <sub>CC</sub>	3005	17	GND		6.0V	6.0V		6.0V		"	6.0V		6.0V	6.0V	6.0V		6.0V	V <sub>CC</sub>			0.2		20			μA		
		18	6.0V		6.0V	6.0V		6.0V		"	2/		6.0V	6.0V	6.0V		6.0V	V <sub>CC</sub>			0.2		20			μA		
V <sub>OH3</sub>	3006	19	4.2V	-20μA	4.2V					"								"	1Q	5.95		5.95		5.95		V		
		20	"			4.2V	-20μA			"								"	2Q	"		"		"		"		
		21	"					4.2V	-20μA		"								"	3Q	"		"		"		"	
		22	"								"								"	4Q	"		"		"		"	
		23	"								"								"	5Q	"		"		"		"	
		24	"								"								"	6Q	"		"		"		"	
V <sub>OH5</sub>	3006	25	"	-5.2mA	4.2V					"								"	1Q	5.48		5.2		5.48		"		
		26	"			4.2V				"								"	2Q	"		"		"		"		
		27	"				4.2V	-5.2mA			"							"	3Q	"		"		"		"		
		28	"						4.2V	-5.2mA	"							"	4Q	"		"		"		"		
		29	"								"							"	5Q	"		"		"		"		
		30	"								"							"	6Q	"		"		"		"		
V <sub>OL3</sub>	3007	31	1.2V	20μA						"								"	1Q		0.05		0.05		0.05	"		
		32	"					20μA			"							"	2Q		"		"		"	"		
		33	"								"							"	3Q		"		"		"	"		
		34	"								"		20μA					"	4Q		"		"		"	"		
		35	"								"							"	5Q		"		"		"	"		
		36	"								"							"	6Q		"		"		"	"		
		37	4.2V	20μA	1.2V						"	2/						"	1Q		"		"		"	"		
		38	"		1.2V						"	"						"	2Q		"		"		"	"		
		39	"			1.2V	20μA				"							"	3Q		"		"		"	"		
		40	"							1.2V	20μA	"						"	4Q		"		"		"	"		
		41	"									"						"	5Q		"		"		"	"		
		42	"									"						"	6Q		"		"		"	"		

See footnotes at end of table.

TABLE III. Group A inspection for device type 07 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit		
			Cases E,F		2	3	4	5	7	8	9	10	12	13	14	15	17	18		19	20	Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C			Subgroup 3 T <sub>C</sub> = -55°C	
			Test no.	CLR	1Q	1D	2D	2Q	3D	3Q	GND	CLK	4Q	4D	5Q	5D	6D	6Q		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max	
V <sub>OL5</sub>	3007	43	1.2V	5.2mA				5.2mA	1.2V		GND							6.0V	1Q		0.26		0.4		0.26	V		
		44	"	"				5.2mA	"		"								"	2Q		"		"		"	"	
		45	"	"				5.2mA	"		"								"	3Q		"		"		"	"	
		46	"	"				5.2mA	"		"								"	4Q		"		"		"	"	
		47	"	"				5.2mA	"		"								"	5Q		"		"		"	"	
		48	"	"				5.2mA	"		"								"	6Q		"		"		"	"	
		49	4.2V	5.2mA	1.2V	1.2V	5.2mA	4.2V		"		2/							"	1Q		"		"		"	"	
		50	"	"				4.2V		"		"							"	2Q		"		"		"	"	
		51	"	"				1.2V		"		"							"	3Q		"		"		"	"	
		52	"	"				4.2V		"		"							"	4Q		"		"		"	"	
		53	"	"				"		"		"							"	5Q		"		"		"	"	
		54	"	"				"		"		"							"	6Q		"		"		"	"	
I <sub>OS4</sub>	3011	55	4.0V	GND	4.0V	4.0V	GND	4.0V		"			4.0V		4.0V	4.0V		4.0V	1Q	-10	-120	-10	-120	-10	-120	mA		
		56	"	"	"	"	GND	"		"			"		"	"		"	2Q	"	"	"	"	"	"	"		
		57	"	"	"	"	GND	"		GND			"		"	"		"	3Q	"	"	"	"	"	"	"		
		58	"	"	"	"	GND	"		"		GND		"		"	"		"	4Q	"	"	"	"	"	"	"	
		59	"	"	"	"	GND	"		"		"		GND		"	"		"	5Q	"	"	"	"	"	"	"	
		60	"	"	"	"	GND	"		"		"		"		GND	"		"	6Q	"	"	"	"	"	"	"	
I <sub>IH</sub>	3010	61	6.0V		6.0V					"								6.0V	CLR		50		100			nA		
		62	"		"	"				"								"	1D		"		"		"	"		
		63	"		"	6.0V				"								"	2D		"		"		"	"		
		64	"		"	6.0V			6.0V	"								"	3D		"		"		"	"		
		65	"		"				6.0V	"								"	CLK		"		"		"	"		
		66	"		"					"		6.0V						"	4D		"		"		"	"		
		67	"		"					"				6.0V				"	5D		"		"		"	"		
		68	"		"					"					6.0V			"	6D		"		"		"	"		
I <sub>IL</sub>	3009	69	GND		GND					"								"	CLR		-50		-100			"		
		70	"		"	GND				"								"	1D		"		"		"	"		
		71	"		"	GND				"								"	2D		"		"		"	"		
		72	"		"	GND			GND	"								"	3D		"		"		"	"		
		73	"		"				GND	"								"	CLK		"		"		"	"		
		74	"		"					"								"	4D		"		"		"	"		
		75	"		"					"				GND				"	5D		"		"		"	"		
		76	"		"					"					GND			"	6D		"		"		"	"		
																			Subgroup 4 T <sub>C</sub> = +25°C									
																			Min	Max								
C <sub>i</sub>	3012	77	4/						GND									GND	CLR		10					pF		
		78	"			4/			"									"	1D		"		"		"	"		
		79	"			4/	4/		"									"	2D		"		"		"	"		
		80	"						"									"	3D		"		"		"	"		
		81	"					4/	"									"	CLK		"		"		"	"		
		82	"						"		4/							"	4D		"		"		"	"		
		83	"						"					4/				"	5D		"		"		"	"		
		84	"						"						4/			"	6D		"		"		"	"		

See footnotes at end of table.

TABLE III. Group A inspection for device type 07 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/																Measured terminal	Test limits						Unit																		
			Cases E,F		2		3		4		5		7		8		9			10		12		13			14		15		17		18		19		20		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C	
			Test no.	CLR	1Q	1D	2D	2Q	3D	3Q	GND	CLK	4Q	4D	5Q	5D	6D	6Q		V <sub>CC</sub>	Min	Max	Min	Max	Min		Max																	
Truth table tests 6/ 7/	3014	85	B	L	A	A	L	A	L	GND	B	L	A	L	A	A	L	4.5V	All outputs	5/	5/	5/	5/	5/	5/																			
		86	A	L	A	A	L	A	L	"	B	L	A	L	A	A	L	"		"	"	"	"	"	"																			
		87	A	H	A	A	H	A	H	"	A	H	A	H	A	A	H	"		"	"	"	"	"	"																			
		88	A	H	A	A	H	A	H	"	B	H	A	H	A	A	H	"		"	"	"	"	"	"																			
		89	A	H	B	B	H	B	H	"	B	H	B	H	B	B	H	"		"	"	"	"	"	"																			
90	A	L	B	B	L	B	L	"	A	L	B	L	B	B	L	"	"	"	"	"	"	"																						
																			Test limits 8/																									
																			Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C																					
																			Min	Max	Min	Max	Min	Max																				
f <sub>MAX</sub>	(Fig. 3)	91	4.5V	OUT	IN	IN	OUT	IN	OUT	GND	IN							4.5V	1Q	31		23		31		MHz																		
9/		92	"							"	"							"	2Q	"		"		"		"																		
		93	"							"	"	OUT	IN	OUT	IN	IN	OUT	"	3Q	"		"		"		"																		
		94	"							"	"							"	4Q	"		"		"		"																		
		95	"							"	"							"	5Q	"		"		"		"																		
		96	"							"	"							"	6Q	"		"		"		"																		
t <sub>PHL1</sub>	3003 (Fig. 3)	97	"	OUT	IN	IN	OUT	IN	OUT	"	"						"	CLK to 1Q	5	31	5	42	5	31	ns																			
Z/		98	"							"	"						"	CLK to 2Q	"	"	"	"	"	"	"																			
		99	"							"	"						"	CLK to 3Q	"	"	"	"	"	"	"																			
		100	"							"	"	OUT	IN	OUT	IN	IN	OUT	"	CLK to 4Q	"	"	"	"	"	"																			
		101	"							"	"						"	CLK to 5Q	"	"	"	"	"	"	"																			
		102	"							"	"						"	CLK to 6Q	"	"	"	"	"	"	"																			
t <sub>PLH1</sub>	3003 (Fig. 3)	103	"	OUT	IN	IN	OUT	IN	OUT	"	"						"	CLK to 1Q	"	"	"	"	"	"	"																			
Z/		104	"							"	"						"	CLK to 2Q	"	"	"	"	"	"	"																			
		105	"							"	"						"	CLK to 3Q	"	"	"	"	"	"	"																			
		106	"							"	"	OUT	IN	OUT	IN	IN	OUT	"	CLK to 4Q	"	"	"	"	"	"																			
		107	"							"	"						"	CLK to 5Q	"	"	"	"	"	"	"																			
		108	"							"	"						"	CLK to 6Q	"	"	"	"	"	"	"																			
t <sub>PHL2</sub>	3003 (Fig. 3)	109	IN	OUT	4.5V	4.5V	OUT	4.5V	OUT	"	10/						"	CLR to 1Q	"	"	"	"	"	"	"																			
Z/		110	"							"	"						"	CLR to 2Q	"	"	"	"	"	"	"																			
		111	"							"	"						"	CLR to 3Q	"	"	"	"	"	"	"																			
		112	"							"	"	OUT	4.5V	OUT	4.5V	4.5V	OUT	"	CLR to 4Q	"	"	"	"	"	"																			
		113	"							"	"						"	CLR to 5Q	"	"	"	"	"	"	"																			
		114	"							"	"						"	CLR to 6Q	"	"	"	"	"	"	"																			
t <sub>THL</sub>	3004 (Fig. 3)	115	4.5V	OUT	IN	IN	OUT	IN	OUT	"	IN						"	1Q	3	15	3	20	3	15	"																			
Z/		116	"							"	"						"	2Q	"	"	"	"	"	"	"																			
		117	"							"	"						"	3Q	"	"	"	"	"	"	"																			
		118	"							"	"	OUT	IN	OUT	IN	IN	OUT	"	4Q	"	"	"	"	"	"																			
		119	"							"	"						"	5Q	"	"	"	"	"	"	"																			
		120	"							"	"						"	6Q	"	"	"	"	"	"	"																			
t <sub>FLH</sub>	3004 (Fig. 3)	121	"	OUT	IN	IN	OUT	IN	OUT	"	"						"	1Q	"	"	"	"	"	"	"																			
Z/		122	"							"	"						"	2Q	"	"	"	"	"	"	"																			
		123	"							"	"						"	3Q	"	"	"	"	"	"	"																			
		124	"							"	"	OUT	IN	OUT	IN	IN	OUT	"	4Q	"	"	"	"	"	"																			
		125	"							"	"						"	5Q	"	"	"	"	"	"	"																			
		126	"							"	"						"	6Q	"	"	"	"	"	"	"																			

See footnotes at end of table.

TABLE III. Group A inspection for device type 08.

Symbol	MIL-STD-883 method	Case 2 Cases E,F Test no.	Terminal conditions 1/																Measured terminal	Test limits						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max	
V <sub>IC</sub> (pos) 1/		1	1mA			1mA				1/							GND	CLR	1/	1.5					V	
		2								"							"	1D	"	"					"	
		3					1mA			"							"	2D	"	"					"	
		4						1mA		"	1mA						"	CLK	"	"					"	
		5								"							"	3D	"	"					"	
		6								"						1mA	"	4D	"	"					"	
V <sub>IC</sub> (neg) 1/		7	-1mA							GND							1/	CLR		-1.5					"	
		8								"							"	1D	"	"					"	
		9					-1mA			"							"	2D	"	"					"	
		10						-1mA		"	-1mA						"	CLK	"	"					"	
		11								"						-1mA	"	3D	"	"					"	
		12								"							-1mA	4D	"	"					"	
I <sub>CC</sub>	3005	13	GND			6.0V	6.0V			"	GND				6.0V	6.0V		6.0V	V <sub>CC</sub>		0.2		20		μA	
		14	6.0V			6.0V	6.0V			"	2/				6.0V	6.0V		V <sub>CC</sub>		0.2		20		μA		
V <sub>OH3</sub>	3006	15	1.2V		-20μA					"							"	1Q	5.95		5.95		5.95		V	
		16	"							"							"	2Q	"	"	"	"	"	"	"	
		17	"							"						-20μA	"	3Q	"	"	"	"	"	"	"	
		18	"							"							"	4Q	"	"	"	"	"	"	"	
		19	4.2V	-20μA			4.2V				"	2/					-20μA	"	1Q	"	"	"	"	"	"	
		20	"				4.2V				"	"						"	2Q	"	"	"	"	"	"	
		21	"					4.2V			"	"					-20μA	"	3Q	"	"	"	"	"	"	
		22	"								"	"						4.2V	4Q	"	"	"	"	"	"	
		23	"								"	"						4.2V	2Q	"	"	"	"	"	"	
		24	"				-20μA	1.2V			"	"						-20μA	4Q	"	"	"	"	"	"	
		25	"					1.2V			"	"							1Q	"	"	"	"	"	"	
		26	"								"	"					-20μA	1.2V	2Q	"	"	"	"	"	"	
		V <sub>OH5</sub>	3006	27	1.2V		-5.2mA					"							"	1Q	5.48		5.2		5.48	
28	"									"								"	2Q	"	"	"	"	"	"	
29	"									"								"	3Q	"	"	"	"	"	"	
30	"									"								"	4Q	"	"	"	"	"	"	
31	4.2V			-5.2mA			4.2V				"	2/						-5.2mA	1Q	"	"	"	"	"	"	
32	"						4.2V				"	"							2Q	"	"	"	"	"	"	
33	"							4.2V			"	"							3Q	"	"	"	"	"	"	
34	"										"	"							4Q	"	"	"	"	"	"	
35	"						-5.2mA	1.2V			"	"							1Q	"	"	"	"	"	"	
36	"							1.2V			"	"							2Q	"	"	"	"	"	"	
37	"										"	"							3Q	"	"	"	"	"	"	
38	"										"	"							4Q	"	"	"	"	"	"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 08 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases E,F Test no.	Terminal conditions 1/																Measured terminal	Test limits						Unit	
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C			
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max		
V <sub>OL3</sub>	3007	39	1.2V	20μA														6.0V	1Q		0.05		0.05		0.05	V	
		40	"	"						20μA	GND							"	2Q		"		"		"	"	
		41	"	"							"			20μA				"	3Q		"		"		"	"	
		42	"	"							"							"	4Q		"		"		"	"	
		43	4.2V		20μA	4.2V					"	2/						"	1Q		"		"		"	"	
		44	"				4.2V			20μA	"	"						"	2Q		"		"		"	"	
		45	"								"	"			20μA	4.2V		"	3Q		"		"		"	"	
		46	"								"	"				4.2V	20μA	"	4Q		"		"		"	"	
		47	"	20μA			1.2V				"	"						"	1Q		"		"		"	"	
		48	"					1.2V			"	"						"	2Q		"		"		"	"	
49	"								"	"			20μA		1.2V		"	3Q		"		"		"	"		
50	"								"	"					1.2V		"	4Q		"		"		"	"		
V <sub>OL5</sub>	3007	51	1.2V	5.2mA													"	1Q		0.26		0.4		0.26	"		
		52	"	"													"	2Q		"		"		"	"		
		53	"	"													"	3Q		"		"		"	"		
		54	"	"													"	4Q		"		"		"	"		
		55	4.2V		5.2mA	4.2V					"	2/					"	1Q		"		"		"	"		
		56	"				4.2V			5.2mA	"	"					"	2Q		"		"		"	"		
		57	"								"	"			5.2mA	4.2V		"	3Q		"		"		"	"	
		58	"								"	"				4.2V	5.2mA	"	4Q		"		"		"	"	
		59	"	5.2mA			1.2V				"	"						"	1Q		"		"		"	"	
		60	"					1.2V			"	"						"	2Q		"		"		"	"	
61	"								"	"			5.2mA		1.2V		"	3Q		"		"		"	"		
62	"								"	"					1.2V		"	4Q		"		"		"	"		
I <sub>OS4</sub>	3011	63	4.0V	GND	GND	4.0V	GND	GND	GND	"	3/						4.0V	1Q	-10	-120	-10	-120	-10	-120	mA		
		64	"	"						"	"						"	1Q		"		"		"	"		
		65	"	"							"	"					"	2Q		"		"		"	"		
		66	"	"			4.0V	GND	GND		"	"					"	2Q		"		"		"	"		
		67	"	"					GND		"	"					"	3Q		"		"		"	"		
		68	"	"							"	"			GND	GND	4.0V	"	3Q		"		"		"	"	
		69	"	"							"	"					4.0V	"	4Q		"		"		"	"	
		70	"	"							"	"					GND	"	4Q		"		"		"	"	
		I <sub>IH</sub>	3010	71	6.0V							"	"						6.0V	CLR		50		100			nA
				72	"				6.0V			"	"						"	1D		"		"			"
73	"							6.0V			"	"					"	2D		"		"			"		
74	"										"	"					"	CLK		"		"			"		
75	"										"	"					"	3D		"		"			"		
76	"										"	"					"	4D		"		"			"		
I <sub>IL</sub>	3009	77	GND							"	"						"	CLR		-50		-100			"		
		78	"							"	"						"	1D		"		"			"		
		79	"				GND			"	"						"	2D		"		"			"		
		80	"					GND			"	"					"	CLK		"		"			"		
		81	"								"	"			GND			"	3D		"		"			"	
		82	"								"	"						"	4D		"		"			"	

See footnotes at end of table.



TABLE III. Group A inspection for device type 08 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases E,F Test no.	Terminal conditions 1/																Measured terminal	Test limits 8/						Unit
			2	3	4	5	7	8	9	10	12	13	14	15	17	18	19	20		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C		
			1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16		Min	Max	Min	Max	Min	Max	
t <sub>PLH1</sub> Z/	3003 (Fig. 3)	117	4.5V	OUT		IN	IN		OUT	GND	IN							4.5V	CLK to 1Q	4	31	4	41	4	31	ns
		118	"				IN			"	"	OUT						"	CLK to 2Q	"	"	"	"	"	"	"
		119	"							"	"		IN					"	CLK to 3Q	"	"	"	"	"	"	"
		120	"							"	"	OUT						"	CLK to 4Q	"	"	"	"	"	"	"
		121	"			OUT	IN			"	"							"	CLK to 1Q	"	"	"	"	"	"	"
		122	"				IN	IN	OUT	"	"							"	CLK to 2Q	"	"	"	"	"	"	"
		123 124	"							"	"		OUT	IN	IN	OUT		"	CLK to 3Q CLK to 4Q	"	"	"	"	"	"	"
t <sub>PHL2</sub> Z/	3003 (Fig. 3)	125	IN	OUT		4.5V	4.5V		OUT	"	10/						"	CLR to 1Q	"	32	"	43	"	32	"	
		126	"						"	"	"			4.5V			"	CLR to 2Q	"	"	"	"	"	"	"	
		127	"						"	"	OUT						"	CLR to 3Q	"	"	"	"	"	"	"	
		128	"						"	"				4.5V	4.5V		OUT	CLR to 4Q	"	"	"	"	"	"	"	
t <sub>PLH2</sub> Z/	3003 (Fig. 3)	129	"		OUT	4.5V	4.5V	OUT		"	"						"	CLR to 1Q	"	"	"	"	"	"	"	
		130	"						"	"		OUT	4.5V				"	CLR to 2Q	"	"	"	"	"	"	"	
		131	"						"	"							"	CLR to 3Q	"	"	"	"	"	"	"	
		132	"						"	"				4.5V	OUT		"	CLR to 4Q	"	"	"	"	"	"	"	
t <sub>THL</sub> Z/	3004 (Fig. 3)	133	4.5V	OUT		IN	IN		OUT	GND	IN						4.5V	1Q	3	15	3	20	3	15	ns	
		134	"							"	"	OUT					"	2Q	"	"	"	"	"	"	"	
		135	"							"	"		IN				"	3Q	"	"	"	"	"	"	"	
		136	"							"	"	OUT					"	4Q	"	"	"	"	"	"	"	
		137	"			OUT	IN			"	"			IN			"	1Q	"	"	"	"	"	"	"	
		138	"				IN	IN	OUT	"	"						"	2Q	"	"	"	"	"	"	"	
		139 140	"							"	"		OUT	IN	IN	OUT		"	3Q 4Q	"	"	"	"	"	"	"
t <sub>TLH</sub> Z/	3004 (Fig. 3)	141	"	OUT		IN	IN		OUT	"	"						"	1Q	"	"	"	"	"	"	"	
		142	"							"	"	OUT					"	2Q	"	"	"	"	"	"	"	
		143	"							"	"		IN				"	3Q	"	"	"	"	"	"	"	
		144	"							"	"			IN			"	4Q	"	"	"	"	"	"	"	
		145	"			OUT	IN			"	"						"	1Q	"	"	"	"	"	"	"	
		146	"							"	"						"	2Q	"	"	"	"	"	"	"	
		147	"					IN	OUT	"	"			OUT	IN		"	3Q	"	"	"	"	"	"	"	
		148	"							"	"				IN	OUT		"	4Q	"	"	"	"	"	"	

See footnotes at end of table.

TABLE III. Group A inspection for device type 52.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit					
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C							
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max						
V <sub>IC</sub> (pos) 1/		Test no.	1CLR	1D	1CLK	1PRE	1Q	1Q	GND	2Q	2PRE	2CLK	2D	2CLR	V <sub>CC</sub>	1CLR	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR						
		1	1mA						1/						GND	1CLR	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR	1/	1.5				
		2		1mA					"						"	"	"	"	"	"	"	"	"	"	"				
		3			1mA				"						"	"	"	"	"	"	"	"	"	"	"				
		4				1mA			"						"	"	"	"	"	"	"	"	"	"	"				
		5					1mA		"			1mA			"	"	"	"	"	"	"	"	"	"	"				
		6							"				1mA		"	"	"	"	"	"	"	"	"	"	"				
		7							"					1mA	"	"	"	"	"	"	"	"	"	"	"				
	8							"						"	"	"	"	"	"	"	"	"	"	"					
V <sub>IC</sub> (neg) 1/		9	-1mA						GND						1/	1CLR	1D	1CLK	1PRE	2PRE	2CLK	2D	2CLR		-1.5				
		10		-1mA					"					"	"	"	"	"	"	"	"	"	"	"					
		11			-1mA				"					"	"	"	"	"	"	"	"	"	"	"					
		12				-1mA			"					"	"	"	"	"	"	"	"	"	"	"					
		13							"			-1mA			"	"	"	"	"	"	"	"	"	"	"				
		14							"				-1mA		"	"	"	"	"	"	"	"	"	"	"				
		15							"					-1mA	"	"	"	"	"	"	"	"	"	"	"				
		16							"						"	"	"	"	"	"	"	"	"	"	"				
I <sub>CC</sub>	3005	17	5.5V	GND	GND	GND									5.5V	V <sub>CC</sub>								0.15		15			
		18	GND	GND	GND	5.5V				"						GND	"								0.15		15		
I <sub>CCΔ</sub>		219	2.4V	0.4V	0.4V	0.4V						0.4V	0.4V	0.4V	0.4V	"	"							3.0		3.0		3.0	mA
		220	0.4V	2.4V	0.4V	0.4V						"	"	"	"	"	"							"		"		"	"
		221	"	0.4V	2.4V	"						"	"	"	"	"	"							"		"		"	"
		222	"	"	0.4V	2.4V						"	"	"	"	"	"							"		"		"	"
		223	"	"	"	0.4V	2.4V					"	"	"	"	"	"							"		"		"	"
		224	"	"	"	"	"					2.4V	"	"	"	"	"							"		"		"	"
		225	"	"	"	"	"					0.4V	2.4V	"	"	"	"							"		"		"	"
		226	"	"	"	"	"					"	0.4V	2.4V	2.4V	"	"							"		"		"	"
V <sub>OH6</sub>	3006	23	2.0V	0.8V	0.8V	0.8V	-20μA								4.5V	1Q							4.40		4.40		4.40	V	
		24	0.8V	0.8V	0.8V	2.0V		-20μA								"	1Q							"		"		"	"
		25														"	2Q							"		"		"	"
		26														"	2Q							"		"		"	"
		27	2.0V	2.0V	2/	2.0V	-20μA									"	1Q							"		"		"	"
		28	2.0V	0.8V	2/	2.0V		-20μA								"	1Q							"		"		"	"
		29														"	2Q							"		"		"	"
		30														"	2Q							"		"		"	"
V <sub>OH7</sub>	3006	31-38	Same terminal conditions as specified above for V <sub>OH6</sub> except I <sub>OH</sub> = -4.0 mA, V <sub>CC</sub> = 5.5 V.															3.98		3.70		3.98							
V <sub>OL6</sub>	3007	39	2.0V	0.8V	0.8V	0.8V	20μA	20μA	GND						4.5V	1Q								0.05		0.05		0.05	
		40	0.8V	0.8V	0.8V	2.0V	20μA		"						"	1Q							"	"		"		"	
		41													"	2Q							"	"		"		"	
		42													"	2Q							"	"		"		"	
		43	2.0V	2.0V	2/	2.0V	20μA	20μA		"	20μA					"	1Q							"	"		"		"
		44	2.0V	0.8V	2/	2.0V	20μA		"							"	1Q							"	"		"		"
		45														"	2Q							"	"		"		"
		46														"	2Q							"	"		"		"

See footnotes at end of table.

TABLE III. Group A inspection for device type 52 – Continued.

Symbol	MIL-STD-883 method	Case 2	Terminal conditions 1/														Measured terminal	Test limits						Unit
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 1 T <sub>C</sub> = +25°C		Subgroup 2 T <sub>C</sub> = +125°C		Subgroup 3 T <sub>C</sub> = -55°C		
			Cases C,D	1	2	3	4	5	6	7	8	9	10	11	12	13		14	Min	Max	Min	Max	Min	
Test no.	1CLR	1D	1CLK	1PRE	1Q	1Q	GND	2Q	2Q	2PRE	2CLK	2D	2CLR	V <sub>CC</sub>										
V <sub>OL7</sub>	3007	47-54	Same terminal conditions as specified above for V <sub>OL6</sub> except I <sub>OL</sub> = 4.0 mA, V <sub>CC</sub> = 5.5 V.															0.26		0.4		0.26	V	
I <sub>OS4</sub>	3011	55	4.0V	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	4.0V	1Q	-10	-120	-10	-120	-10	-120	mA
		56	GND	GND	GND	4.0V	GND	GND	GND	GND	GND	GND	GND	GND	GND	4.0V	1Q	"	"	"	"	"	"	"
		57															2Q	"	"	"	"	"	"	"
		58															2Q	"	"	"	"	"	"	"
I <sub>IH</sub>	3010	59	6.0V												5.5V	1CLR		.05		0.1			μA	
		60		6.0V												1D		"		"			"	
		61			6.0V											1CLK		"		"			"	
		62				6.0V										1PRE		"		"			"	
		63										6.0V				2PRE		"		"			"	
		64											6.0V			2CLK		"		"			"	
		65												6.0V		2D		"		"			"	
66													6.0V	2CLR		"		"			"			
I <sub>IL</sub>	3009	67	GND													1CLR		-.05		-0.1			"	
		68		GND												1D		"		"			"	
		69			GND											1CLK		"		"			"	
		70				GND										1PRE		"		"			"	
		71										GND				2PRE		"		"			"	
		72											GND			2CLK		"		"			"	
		73												GND		2D		"		"			"	
		74													GND	2CLR		"		"			"	
																Subgroup 4 T <sub>C</sub> = +25°C								
C <sub>i</sub>	3012	75	4/							GND					GND	1CLR		10					pF	
		76		4/												1D		"		"			"	
		77			4/											1CLK		"		"			"	
		78				4/										1PRE		"		"			"	
		79					4/									2PRE		"		"			"	
		80										4/				2CLK		"		"			"	
		81											4/			2D		"		"			"	
82												4/		2CLR		"		"			"			
																Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C				
Truth table tests 6/ 7/	3014	83	B	A	B	A	L	H	GND	H	L	A	B	A	B	4.5V	All outputs	5/	5/	5/	5/	5/	5/	
		84	B	A	A	A	L	H	"	H	L	A	A	A	B	"	"	"	"	"	"	"	"	
		85	B	A	B	A	L	H	"	H	L	A	B	A	B	"	"	"	"	"	"	"	"	
		86	A	A	B	A	L	H	"	H	L	A	B	A	A	"	"	"	"	"	"	"	"	

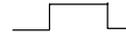
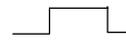
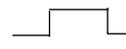
See footnotes at end of table.

TABLE III. Group A inspection for device type 52 – Continued.

Symbol	MIL-STD-883 method	Case 2 Cases C,D Test no.	Terminal conditions 1/														Measured terminal	Test limits						Unit					
			2	3	4	6	8	9	10	12	13	14	16	18	19	20		Subgroup 7 T <sub>C</sub> = +25°C		Subgroup 8 T <sub>C</sub> = +125°C		Subgroup 8 T <sub>C</sub> = -55°C							
			1	2	3	4	5	6	7	8	9	10	11	12	13	14		Min	Max	Min	Max	Min	Max						
			1CLR	1D	1CLK	1PRE	1Q	1Q	GND	2Q	2PRE	2CLK	2D	2CLR	V <sub>CC</sub>														
Truth table tests 6/ 7/	3014	87	A	A	B	B	H	L	GND	L	H	B	B	A	A	4.5V	All outputs	5/	5/	5/	5/	5/	5/						
		88	A	B	B	B	H	L	"	L	H	B	B	B	A	"		"	"	"	"	"	"						
		89	A	B	A	B	H	L	"	L	H	B	A	B	A	"		"	"	"	"	"	"						
		90	A	B	B	B	H	L	"	L	H	B	B	B	A	"		"	"	"	"	"	"						
		91	A	B	B	A	H	L	"	L	H	A	B	B	A	"		"	"	"	"	"	"						
		92	A	B	A	A	L	H	"	H	L	A	A	B	A	"		"	"	"	"	"	"						
		93	A	B	B	A	L	H	"	H	L	A	B	B	A	"		"	"	"	"	"	"						
		94	A	A	B	A	L	H	"	H	L	A	B	A	A	"		"	"	"	"	"	"						
		95	A	A	A	A	H	L	"	L	H	A	A	A	A	"		"	"	"	"	"	"						
																		Test limits 8/											
																		Subgroup 9 T <sub>C</sub> = +25°C		Subgroup 10 T <sub>C</sub> = +125°C		Subgroup 11 T <sub>C</sub> = -55°C							
																		Min	Max	Min	Max	Min	Max						
f <sub>MAX</sub>	(Fig. 3)	96	4.5V	IN	IN	4.5V	OUT	OUT	GND	OUT	OUT	4.5V	IN	IN	4.5V	4.5V	1Q	28		21		28		MHz					
7/ 9/		97	4.5V	IN	IN	4.5V			"	OUT		4.5V	IN	IN	4.5V	"	1Q	"		"		"		"					
		98							"		OUT	4.5V	IN	IN	4.5V	"	2Q	"		"		"		"					
		99							"		OUT	4.5V	IN	IN	4.5V	"	2Q	"		"		"		"					
t <sub>PHL1</sub>	3003 (Fig. 3)	100	4.5V	IN	IN	4.5V	OUT	OUT	"		OUT	4.5V	IN	IN	4.5V	"	1CLK to 1Q	5	31	5	41	5	31	ns					
7/		101							"		OUT	4.5V	IN	IN	4.5V	"	2CLK to 2Q	"	"	"	"	"	"	"					
		102	4.5V	IN	IN	4.5V		OUT	"	OUT		4.5V	IN	IN	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"					
		103							"	OUT		4.5V	IN	IN	4.5V	"	2CLK to 2Q	"	"	"	"	"	"	"					
t <sub>PLH1</sub>	3003 (Fig. 3)	104	4.5V	IN	IN	4.5V	OUT	OUT	"		OUT	4.5V	IN	IN	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"					
7/		105							"		OUT	4.5V	IN	IN	4.5V	"	2CLK to 2Q	"	"	"	"	"	"	"					
		106	4.5V	IN	IN	4.5V		OUT	"	OUT		4.5V	IN	IN	4.5V	"	1CLK to 1Q	"	"	"	"	"	"	"					
		107							"	OUT		4.5V	IN	IN	4.5V	"	2CLK to 2Q	"	"	"	"	"	"	"					
t <sub>PHL2</sub>	3003 (Fig. 3)	108	IN	GND	GND	4.5V	OUT	OUT	"		OUT	4.5V	GND	GND	IN	"	1CLR to 1Q	"	35	"	47	"	35	"					
7/		109	4.5V	GND	GND	IN		OUT	"		OUT	4.5V	GND	GND	4.5V	"	1PRE to 1Q	"	"	"	"	"	"	"					
		110							"		OUT	4.5V	GND	GND	4.5V	"	2CLR to 2Q	"	"	"	"	"	"	"					
		111							"	OUT		4.5V	GND	GND	4.5V	"	2PRE to 2Q	"	"	"	"	"	"	"					
t <sub>PLH2</sub>	3003 (Fig. 3)	112	IN	GND	GND	4.5V	OUT	OUT	"		OUT	4.5V	GND	GND	IN	"	1CLR to 1Q	"	"	"	"	"	"	"					
7/		113	4.5V	GND	GND	IN		OUT	"		OUT	4.5V	GND	GND	4.5V	"	1PRE to 1Q	"	"	"	"	"	"	"					
		114							"		OUT	4.5V	GND	GND	4.5V	"	2CLR to 2Q	"	"	"	"	"	"	"					
		115							"		OUT	4.5V	GND	GND	4.5V	"	2PRE to 2Q	"	"	"	"	"	"	"					
t <sub>THL</sub>	3004 (Fig. 3)	116	IN	GND	GND	4.5V	OUT	OUT	"		OUT	4.5V	GND	GND	IN	"	1Q	3	15	3	20	3	15	"					
7/		117	4.5V	GND	GND	IN		OUT	"		OUT	4.5V	GND	GND	4.5V	"	1Q	"	"	"	"	"	"	"					
		118							"		OUT	4.5V	GND	GND	4.5V	"	2Q	"	"	"	"	"	"	"					
		119							"		OUT	4.5V	GND	GND	4.5V	"	2Q	"	"	"	"	"	"	"					
t <sub>TLH</sub>	3004 (Fig. 3)	120	4.5V	GND	GND	IN	OUT	OUT	"		OUT	4.5V	GND	GND	IN	"	1Q	"	"	"	"	"	"	"					
7/		121	IN	GND	GND	4.5V		OUT	"		OUT	4.5V	GND	GND	4.5V	"	1Q	"	"	"	"	"	"	"					
		122							"		OUT	4.5V	GND	GND	4.5V	"	2Q	"	"	"	"	"	"	"					
		123							"		OUT	4.5V	GND	GND	4.5V	"	2Q	"	"	"	"	"	"	"					

See footnotes on next page.

TABLE III. Group A inspection – Continued.

- 1/ Pins not designated may be high level logic, low level logic, or open. Exceptions are as follows:
- $V_{IC}(\text{pos})$  tests, the GND terminal shall be open. For test equipment that does not allow GND pin to be open during test, a minimum limit of 0.4 V applies.
  - $V_{IC}(\text{neg})$  tests, the  $V_{CC}$  terminal shall be open.
  - $I_C$  tests, the output terminals shall be open.
- 2/ Apply one clock pulse prior to test as follows:  $\begin{matrix} 6.0 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   or  $\begin{matrix} 6.0 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   as appropriate.
- 3/ Apply one clock pulse prior to test as follows:  $\begin{matrix} 4.0 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   or  $\begin{matrix} 4.0 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   as appropriate.
- 4/ See 4.4.1c.
- 5/  $A = 3.7 \text{ V}$ ,  $B = 0.4 \text{ V}$  for all device types (except 52 where  $A = 2.4 \text{ V}$ );  $H > 2.5 \text{ V}$ ,  $L < 2.5 \text{ V}$ .
- 6/ Only a summary of attributes data is required.
- 7/ Apply input test parameters such that  $t_{su}$ ,  $t_{hold}$ ,  $t_{rem}$ , and  $t_w$  values are not greater than the recommended operating minimums (see 1.4).  
Preset outputs to required state if necessary prior to test.
- 8/ See 4.4.1d.
- 9/ The  $f_{MAX}$ , minimum limit specified, is the frequency of the clock input. The data input is  $f_{MAX}/2$
- 10/ Apply one clock pulse prior to test as follows:  $\begin{matrix} 4.5 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   or  $\begin{matrix} 4.5 \text{ V} \\ 0.0 \text{ V} \end{matrix}$   as appropriate.
- 11/ Three-state output conditions are required.

4.3 Qualification inspection. Qualification inspection shall be in accordance with MIL-PRF-38535.

4.4 Technology Conformance inspection (TCI). Technology conformance inspection shall be in accordance with MIL-PRF-38535 and herein for groups A, B, C, and D inspections (see 4.4.1 through 4.4.4).

4.4.1 Group A inspection. Group A inspection shall be in accordance with table III of MIL-PRF-38535 and as follows:

- a. Tests shall be performed in accordance with table II herein.
- b. Subgroups 5 and 6 shall be omitted.
- c. Subgroup 4 ( $C_{IN}$ ,  $C_O$ , and  $C_C$  measurements) shall be measured only for initial qualification and after process or design changes that may affect input capacitance. Capacitance shall be measured between the designated terminal and GND at a frequency of 1 MHz.
- d. Subgroups 9 and 11 shall be measured only for initial qualification and after process or design changes which may affect dynamic performance.

4.4.2 Group B inspection. Group B inspection shall be in accordance with table II of MIL-PRF-38535.

4.4.3 Group C inspection. Group C inspection shall be in accordance with table IV of MIL-PRF-38535 and as follows:

- a. End-point electrical parameters shall be as specified in table II herein. Delta limits shall apply only to subgroup 1 of group C inspection and shall consist of tests specified in table IV herein.
- b. The steady-state life test duration, test condition, and test temperature, or approved alternatives shall be as specified in the device manufacturer's QM plan in accordance with MIL-PRF-38535. The burn-in test circuit shall be maintained under document control by the device manufacturer's Technology Review Board (TRB) in accordance with MIL-PRF-38535 and shall be made available to the acquiring or preparing activity upon request. The test circuit shall specify the inputs, outputs, biases, and power dissipation, as applicable, in accordance with the intent specified in method 1005 of MIL-STD-883.

4.4.4 Group D inspection. Group D inspection shall be in accordance with table V of MIL-PRF-38535. End-point electrical parameters shall be as specified in table II herein.

4.5 Methods of inspection. Methods of inspection shall be specified and as follows:

4.5.1 Voltage and current. Unless otherwise specified, all voltages given are referenced to the microcircuit GND terminal. Currents given are conventional current and positive when flowing into the referenced terminal.

4.5.2 Burn-in and life test cool down procedures. When the burn-in and life tests are completed and prior to removal of bias voltages, the devices under test (DUT) shall be cooled to within 10°C of their power stable condition at room temperature; then, electrical parameter end-point measurements shall be performed.

TABLE IV. Delta limits at 25°C.

Parameter <sup>1/</sup>	Device types	
	All	
$I_{CC}$		±30 nA

<sup>1/</sup> The above parameters shall be recorded before and after the required burn-in and life tests to determine deltas ( $\Delta$ ).

4.5.3 Quiescent supply current ( $I_{CC}$  test). When performing quiescent supply current measurements ( $I_{CC}$ ), the meter shall be placed so that all currents flow through the meter.

## 5. PACKAGING

5.1 Packaging requirements. For acquisition purposes, the packaging requirements shall be as specified in the contract or order (see 6.2). When packaging of materiel is to be performed by DoD or in-house contractor personnel, these personnel need to contact the responsible packaging activity to ascertain packaging requirements. Packaging requirements are maintained by the Inventory Control Point's packaging activity within the Military Service or Defense Agency, or within the military service's system commands. Packaging data retrieval is available from the managing Military Department's or Defense Agency's automated packaging files, CD-ROM products, or by contacting the responsible packaging activity.

## 6. NOTES

(This section contains information of a general or explanatory nature that may be helpful, but is not mandatory.)

6.1 Intended use. Microcircuits conforming to this specification are intended for original equipment design applications and logistic support of existing equipment.

6.2 Acquisition requirements. Acquisition documents should specify the following:

- a. Title, number, and date of the specification.
- b. PIN and compliance identifier, if applicable (see 1.2).
- c. Requirements for delivery of one copy of the quality conformance inspection data pertinent to the device inspection lot to be supplied with each shipment by the device manufacturer, if applicable.
- d. Requirements for certificate of compliance, if applicable.
- e. Requirements for notification of change of product or process to contracting activity in addition to notification to the qualifying activity, if applicable.
- f. Requirements for failure analysis (including required test condition of method 5003 of MIL-STD-883), corrective action, and reporting of results, if applicable.
- g. Requirements for product assurance options.
- h. Requirements for special carriers, lead lengths, or lead forming, if applicable. These requirements should not affect the part number. Unless otherwise specified, these requirements will not apply to direct purchase by or direct shipment to the Government.
- i. Requirements for "JAN" marking.
- j. Packaging requirements (see 5.1).

6.3 Superseding information. The requirements of MIL-M-38510 have been superseded to take advantage of the available Qualified Manufacturer Listing (QML) system provided by MIL-PRF-38535. Previous references to MIL-M-38510 in this document have been replaced by appropriate references to MIL-PRF-38535. All technical requirements now consist of this specification and MIL-PRF-38535. The MIL-M-38510 specification sheet number and PIN have been retained to avoid adversely impacting existing government logistics systems and contractors parts lists.

6.4 Qualification. With respect to products requiring qualification, awards will be made only for products which are, at the time of award of contract, qualified for inclusion in Qualified Manufacturers List QML-38535 whether or not such products have actually been so listed by that date. The attention of the contractors is called to these requirements, and manufacturers are urged to arrange to have the products that they propose to offer to the Federal Government tested for qualification in order that they may be eligible to be awarded contracts or purchase orders for the products covered by this specification. Information pertaining to qualification of products may be obtained from DSCC-VQ, P.O. Box 3990, Columbus, Ohio 43218-3990.

6.5 Abbreviations, symbols, and definitions. The abbreviations, symbols, and definitions used herein are defined in MIL-PRF-38535, MIL-HDBK-1331, and as follows:

- T<sub>C</sub> ..... Case temperature.
- C<sub>IN</sub>..... Input terminal-to-GND capacitance.
- GND ..... Ground zero voltage potential.
- I<sub>CC</sub> ..... Quiescent supply current.
- T<sub>A</sub> ..... Free air temperature.
- V<sub>CC</sub> ..... Positive supply voltage.
- C<sub>PD</sub>..... Power dissipation capacitance.

6.6 Logistic support. Lead materials and finishes (see 3.4) are interchangeable. Unless otherwise specified, microcircuits acquired for Government logistic support will be acquired to device class S for National Aeronautics and Space Administration or class B for Department of Defense (see 1.2.2), lead material and finish A (see 3.4). Longer length leads and lead forming should not affect the part number.

6.7 Data reporting. When specified in the purchase order or contract, a copy of the following data, as applicable, will be supplied.

- a. Attributes data for all screening tests (see 4.2) and variables data for all static burn-in, dynamic burn-in, and steady-state life tests (see 3.6).
- b. A copy of each radiograph.
- c. The technology conformance inspection (TCI) data (see 4.4).
- d. Parameter distribution data on parameters evaluated during burn-in (see 3.6).
- e. Final electrical parameters data (see 4.2d).

6.8 Substitutability. The cross-reference information below is presented for the convenience of users. Microcircuits covered by this specification will functionally replace the listed generic-industry type. Generic-industry microcircuit types may not have equivalent operational performance characteristics across military temperature ranges or reliability factors equivalent to MIL-M-35810 device types and may have slight physical variations in relation to case size. The presence of this information should not be deemed as permitting substitution of generic-industry types for MIL-M-38510 types or as a waiver of any of the provisions of MIL-PRF-38535.

Military device type	Generic-industry type
01	54HC73
02	54HC74
03	54HC107
04	54HC109
05	54HC112
06	54HC173
07	54HC174
08	54HC175
52	54HCT74

6.9 Changes from previous. Marginal notations are not used in this revision to identify changes with respect to the previous issue due to the extent of the changes.

Custodians:  
Army - CR  
Navy - EC  
Air Force - 11  
DLA - CC

Preparing activity:  
DLA - CC  
  
(Project 5962-2005-020)

Review activities:  
Army - MI, SM  
Navy - AS, CG, MC, SH, TD  
Air Force - 03, 19, 99

NOTE: The activities listed above were interested in this document as of the date of this document. Since organizations and responsibilities can change, you should verify the currency of the information above using ASSIST Online database at <http://assist.daps.dla.mil>.